## GENERAL DESCRIPTION

The 71M6543F/71M6543G are 4th-generation polyphase metering systems-on-chips (SoCs) with a 5 MHz 8051 -compatible MPU core, low-power real-time clock (RTC) with digital temperature compensation, flash memory, and LCD driver. Our Single Converter Technology® with a 22-bit delta-sigma ADC, seven analog inputs, digital metrology temperature compensation, precision voltage reference, and a 32-bit computation engine (CE) supports a wide range of metering applications with very few external components.
The 71M6543F/71M6543G support optional interfaces to the 71M6xx3 series of isolated sensors that offer BOM cost reduction, immunity to magnetic tamper, and enhanced reliability. The ICs feature ultra-low-power operation in active and battery modes, 5KB shared RAM, and 64KB (71M6543F) or 128KB (71M6543G) of flash memory, which can be programmed with code and/or data during meter operation.

A complete array of code development tools, demonstration code, and reference designs enable rapid development and certification of meters that meet all ANSI and IEC electricity metering standards worldwide.


Single Converter Technology is a registered trademark of Maxim Integrated Products, Inc.
MICROWIRE is a registered trademark of National Semiconductor Corp.

## 71M6543F/71M6543G Energy Meter ICs

## FEATURES

- 0.1\% Typical Accuracy Over 2000:1 Current Range
- Exceeds IEC 62053/ANSI C12.20 Standards
- Seven Sensor Inputs with Neutral Current Measurement, Differential Mode Selectable for Current Inputs
- Selectable Gain of 1 or 8 for One Current Input to Support Shunts
- High-Speed Wh/VARh Pulse Outputs with Programmable Width
- 64KB Flash, 5KB RAM (71M6543F)
- 128KB Flash, 5KB RAM (71M6543G)
- Up to Four Pulse Outputs with Pulse Count
- Four-Quadrant Metering, Phase Sequencing
- Digital Temperature Compensation:

Metrology Compensation
Accurate RTC for TOU Functions with Automatic Temperature Compensation for Crystal in All Power Modes

- Independent 32-Bit Compute Engine
- $46-64 \mathrm{~Hz}$ Line Frequency Range with the Same Calibration
- Phase Compensation $\left( \pm 7^{\circ}\right)$
- Three Battery-Backup Modes:


## Brownout Mode

LCD Mode
Sleep Mode

- Wake-Up on Pin Events and Wake-on-Timer
- $1 \mu \mathrm{~A}$ in Sleep Mode
- Flash Security
- In-System Program Update
- 8-Bit MPU (80515), Up to 5MIPS
- Full-Speed MPU Clock in Brownout Mode
- LCD Driver:

6 Common Segment Drivers
Up to 56 Selectable Pins

- Up to 51 Multifunction DIO Pins
- Hardware Watchdog Timer (WDT)
- $I^{2} \mathrm{C} / \mathrm{MICROWIRE}{ }^{\circledR}$ EEPROM Interface
- SPI Interface with Flash Program Capability
- Two UARTs for IR and AMR
- IR LED Driver with Modulation
- Industrial Temperature Range
- 100-Pin Lead-Free LQFP Package


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Figure 1: IC Functional Block Diagram

## 1 Introduction

This data sheet covers the 71M6543F (64KB) and 71M6543G (128KB) 4th-generation polyphase energy measurement system-on-chips (SoCs). The term "71M6543" is used when discussing a device feature or behavior that is applicable to all four part numbers. The specific part numbers are used when discussing those features that apply only to specific part numbers. This data sheet also covers details about the companion 71M6xx3 isolated current sensor device.
This document covers the use of the 71 M 6543 in conjunction with the $71 \mathrm{M} 6 \times x 3$ isolated current sensor. The 71M6543 and 71M6xx3 ICs make it possible to use one non-isolated and three additional isolated shunt current sensors to create polyphase energy meters using inexpensive shunt resistors, while achieving unprecedented performance with this type of sensor technology. The 71M6543 SoCs also support Current Transformers (CT).
To facilitate document navigation, hyperlinks are often used to reference figures, tables and section headings that are located in other parts of the document. All hyperlinks in this document are highlighted in blue. Hyperlinks are used extensively to increase the level of detail and clarity provided within each section by referencing other relevant parts of the document. To further facilitate document navigation, this document is published as a PDF document with bookmarks enabled.

The reader is also encouraged to obtain and review the documents listed in 8 Related Information on page 152 of this document.

## 2 Hardware Description

### 2.1 Hardware Overview

The 71M6543 single-chip energy meter integrates all primary functional blocks required to implement a solid-state electricity meter. Included on the chip are:

- An analog front-end (AFE) featuring a 22-bit second-order sigma-delta ADC
- An independent 32-bit digital computation engine (CE) to implement DSP functions
- An 8051-compatible microprocessor (MPU) which executes one instruction per clock cycle (80515)
- A precision voltage reference (VREF)
- A temperature sensor for digital temperature compensation of:
- Metrology (MPU)
- Automatic RTC in all power states
- MPU assisted RTC compensation
- LCD Driver
- RAM and Flash memory
- A real time clock (RTC)
- A variety of I/O pins
- A power failure interrupt
- A zero-crossing interrupt
- Selectable current sensor interfaces for locally-connected sensors as well as isolated sensors (i.e., using the 71M6xx3 companion IC with a shunt resistor sensor)
- Resistive Shunt and Current Transformers are supported

In order to implement a polyphase meter with or without neutral current sensing, one resistive shunt current sensor may be connected directly (non-isolated) to the 71 M 6543 device, while up to three additional current shunts are isolated using a companion 71M6xx3 isolated sensor IC. An inexpensive, small size pulse transformer is used to electrically isolate the 71M6xx3 remote sensor from the 71M6543. The 71M6543 performs digital communications bi-directionally with the 71M6xx3 and also provides power to the 71M6xx3 through the isolating pulse transformer. Isolated (remote) shunt current sensors are connected to the differential input of the 71M6xx3. The 71M6543 may also be used with Current Transformers; in this case the 71M6xx3 isolated sensors are not required. Included on the 71M6xx3 companion isolator chip are:

- Digital isolation communications interface
- An analog front-end (AFE) featuring a 22-bit second-order sigma-delta ADC
- A precision voltage reference (VREF)
- A temperature sensor (for current-sensing digital temperature compensation)
- A fully differential shunt resistor sensor input
- A pre-amplifier to optimize shunt current sensor performance
- Isolated power circuitry obtains dc power from pulses sent by the 71M6543

In a typical application, the 32-bit compute engine (CE) of the 71 M 6543 sequentially processes the samples from the voltage inputs on analog input pins and performs calculations to measure active energy (Wh) and reactive energy (VARh), as well as $A^{2} h$, and $V^{2} h$ for four-quadrant metering. These measurements are then accessed by the MPU, processed further and output using the peripheral devices available to the MPU.

In addition to advanced measurement functions, the real time clock (RTC) function allows the 71M6543 to record time of use (TOU) metering information for multi-rate applications and to time-stamp tamper or other events. An automatic RTC temperature compensation circuit operates in all power states including when the MPU is halted, and continues to compensate using back-up battery power during power outages.

Measurements can be displayed on 3.3 V LCDs commonly used in low-temperature environments. The integrated charge pump and temperature sensor can be used by the MPU to enhance 3.3 V LCD performance at cold temperatures. The on-chip charge pump may also drive 5 V LCDs. Flexible mapping of LCD display segments facilitates the integration of existing custom LCDs. Design trade-off between the
number of LCD segments and DIO pins can be implemented in software to accommodate various requirements.
In addition to the temperature-trimmed ultra-precision voltage reference, the on-chip digital temperature compensation mechanism includes a temperature sensor and associated controls for correction of unwanted temperature effects on metrology and RTC accuracy (i.e., to meet the requirements of ANSI and IEC standards). Temperature-dependent external components such as the crystal oscillator, current transformers (CTs), Current Shunts and their corresponding signal conditioning circuits can be characterized and their correction factors can be programmed to produce electricity meters with exceptional accuracy over the industrial temperature range.
One of the two internal UARTs is adapted to support an Infrared LED with internal drive and sense configuration and can also function as a standard UART. The optical output can be modulated at 38 kHz . This flexibility makes it possible to implement AMR meters with an IR interface. A block diagram of the IC is shown in Figure 1.

### 2.2 Analog Front-End (AFE)

The AFE functions as a data acquisition system, controlled by the MPU. The 71M6543 AFE may also be augmented by isolated 71M6xx3 sensors in order to support low-cost current shunt sensors. Figure 2, and Figure 3 show the two most common configurations; other configurations are possible. Sensors that are connected directly to the 71M6543 (i.e., IADC0-IADC1, VADC8, VADC9 and VADC10) are multiplexed into the single second-order sigma-delta ADC input for sampling in the 71M6543. The 71M6543 ADC output is decimated by the FIR filter and stored in CE RAM where it can be accessed and processed by the CE.

Shunt current sensors that are isolated by using a 71M6xx3 device, are sampled by a second-order sigma delta ADC in the 71M6xx3 and the signal samples are transferred over the digital isolation interface through the low-cost isolation pulse transformer.

Figure 2 shows the 71 M 6543 using shunt current sensors and the 71 M 6 xx 3 isolated sensor devices. Figure 2 supports neutral current measurement with a local shunt connected to the IADC0-IADC1 input plus three remote (isolated) shunt sensors. As seen in Figure 2, when a remote isolated shunt sensor is connected via the 71 M 6 xx 3 , the samples associated with this current channel are not routed to the multiplexer, and are instead transferred digitally to the 71 M 6543 via the isolation interface and are directly stored in CE RAM. The MUX_SELn[3:0] I/O RAM control fields allow the MPU to configure the AFE for the desired multiplexer sampling sequence. Refer to Table 1 and Table 2 for the appropriate CE code and the corresponding AFE settings.

See Figure 31 for the meter wiring configuration corresponding to Figure 2.


Figure 2: AFE Block Diagram (Shunts: One-Local, Three-Remotes)

The 71M6543 AFE can also be directly interfaced to Current Transformers (CTs), as seen in Figure 3. In this case, all voltage and current channels are multiplexed into a single second-order sigma-delta ADC in the 71M6543 and the 71M6xx3 remote isolated sensors are not used. The fourth CT and the measurement of Neutral current via the IADC0-IADC1 current channel are optional.

See Figure 32 for the meter wiring configuration corresponding to Figure 3.


Figure 3. AFE Block Diagram (Four CTs)

### 2.2.1 Signal Input Pins

The 71M6543 features eleven ADC input pins.
IADC0 through IADC7 are intended for use as current sensor inputs. These eight current sensor inputs can be configured as four single-ended inputs, or can be paired to form four differential inputs. For best performance, it is recommended to configure the current sensor inputs as differential inputs (i.e., IADCOIADC1, IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7). The first differential input (IADC0-IADC1) features a pre-amplifier with a selectable gain of 1 or 8 , and is intended for direct connection to a shunt resistor sensor, and can also be used with a Current Transformer (CT). The three remaining differential pairs (i.e., IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7) may be used with CTs, or may be enabled to interface to a remote 71M6xx3 isolated current sensor providing isolation for a shunt resistor sensor using a low cost pulse transformer.

The remaining three inputs VADC8 (VA), VADC9 (VB) and VADC10 (VC) are single-ended, and are intended for sensing each of the phase voltages in a polyphase meter application. These three single-ended inputs are referenced to the V3P3A pin.

All ADC input pins measure voltage. In the case of shunt current sensors, currents are sensed as a voltage drop in the shunt resistor sensor. In the case of Current Transformers (CT), the current is measured as a voltage across a burden resistor that is connected to the secondary of the CT. Meanwhile, line voltages are sensed through resistive voltage dividers. The VADC8 (VA), VADC9 (VB) and VADC10 (VC) pins are single-ended and their common return is the V3P3A pin. See Figure 27, Figure 28, Figure 29 and Figure 30 for detailed connections for each type of sensor. Also refer to the 71M6543 Demonstration Board schematic and bill of materials for typical component values used in these and other circuits.

Pins IADC0-IADC1 can be programmed individually to be differential or single-ended as determined by the DIFF0_E (I/O RAM 0x210C[4]) control bit. However, for most applications, IADC0-IADC1 are configured as a differential input to work with a resistive shunt or CT directly interfaced to the IADC0IADC1 differential input with the appropriate external signal conditioning components.

The performance of the IADC0-IADC1 pins can be enhanced by enabling a pre-amplifier with a fixed gain of 8, using the I/O RAM control bit PRE_E (I/O RAM 0x2704[5]). When PRE_E = 1, IADC0-IADC1 become the inputs to the $8 x$ pre-amplifier, and the output of this amplifier is supplied to the multiplexer. The $8 x$ amplification is useful when current sensors with low sensitivity, such as shunt resistors, are used. With $P R E \_E$ set, the IADC0-IADC1 input signal amplitude is restricted to 31.25 mV peak. When $P R E \_E=0$ (Gain = 1), the IADC0-IADC1 input signal is restricted to 250 mV peak.
For the 71 M 6543 application utilizing shunt resistor sensors (Figure 2), the IADC0-IADC1 pins are configured for differential mode to interface to a local shunt by setting the DIFF0_E control bit. Meanwhile, the IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7 pins are re-configured as digital remote sensor interface designed to communicate with a 71M6xx3 isolated sensor by setting the RMTx_E control bits (I/O RAM 0x2709[5:3]). The 71M6xx3 communicates with the 71M6543 using a bi-directional digital data stream through an isolating pulse transformer. The 71 M 6543 also supplies power to the 71 M 6 xx 3 through the isolating transformer. This type of interface is further described at the end of this chapter. See 2.2.8 71M6xx3 Isolated Sensor Interface.

For use with Current Transformers (CTs), as shown in Figure 3, the RMTx_E control bits are reset, so that IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7 are configured as local analog inputs. The IADC0-IADC1 pins cannot be configured as a remote sensor interface.

### 2.2.2 Input Multiplexer

When operating with locally connected sensors, the input multiplexer sequentially applies the input signals from the analog input pins to the input of the ADC (see Figure 3), according to the sampling sequence determined by the eleven $M U X n_{-} S E L[3: 0]$ control fields. One complete sampling sequence is called a multiplexer frame. The multiplexer of the 71 M 6543 can select up to eleven input signals when the current sensor inputs are configured for single-ended mode. When the current sensor inputs are configured in differential mode (recommended for best performance), the number of input signals is seven (i.e., IADC0IADC1, IADC2-IADC3, IADC4-IADC5, IADC6-IADC7, VADC8, VADC9 and VADC10) per multiplexer frame. The number of slots in the multiplexer frame is controlled by the I/O RAM control field MUX_DIV [3:0] (I/O RAM 0x2100[7:4]) (see Figure 4). The multiplexer always starts at state 0 and proceeds until the number of sensor channels determined by the $M U X_{-} D I V[3: 0]$ field setting have been converted.
The 71 M 6543 requires a unique CE code that is written for the specific meter configuration. Moreover, each CE code requires specific AFE and MUX settings in order to function properly. Table 1 provides the CE code and settings corresponding to the 1-Local / 3-Remote sensor configuration shown in Figure 2. Table 2 provides the CE code and settings corresponding to the CT configuration shown in Figure 3.

Table 1. Required CE Code and Settings for 1-Local / 3-Remotes

| I/O RAM <br> Mnemonic | I/O RAM <br> Location | I/O RAM Setting | Comments |
| :---: | :---: | :---: | :---: |
| FIR_LEN[1:0] | $210 \mathrm{C}[2: 1]$ | 1 | 288 cycles |

Table 2. Required CE Code and Settings for CT Sensors

| I/O RAM <br> Mnemonic | I/O RAM <br> Location | I/O RAM Setting <br> (Hex) | Comments |
| :---: | :---: | :---: | :---: |
| FIR_LEN[1:0] | $210 \mathrm{C}[2: 1]$ | 1 | 288 cycles |
| $A D C \_D I V$ | $2200[5]$ | 0 | Fast |
| PLL_FAST | $2200[4]$ | 1 | 19.66 MHz |
| $M U X \_D I V[3: 0]$ | $2100[7: 4]$ | 7 | See note 1 |
| $M U X 0 \_S E L[3: 0]$ | $2105[3: 0]$ | 2 | Slot 0 is IADC2-IADC3 <br> (IA) |
| MUXI_SEL[3:0] | $2105[7: 4]$ | 8 | Slot 1 is VADC8 |
| (VA) |  |  |  |

Using settings for the I/O RAM Mnemonics listed in Table 1 and Table 2 that do not match those required by the corresponding CE code being used may result in undesirable side effects and must not be selected by the MPU. Consult your local Maxim representative to obtain the correct CE code and AFE / MUX settings corresponding to the application.

For a polyphase configuration with neutral current sensing using shunt resistor current sensors and the 71M6xx3 isolated sensors, as shown in Figure 2, the IADC0-IADC1 input must be configured as a differential input, to be connected to a local shunt (see Figure 30 for the shunt connection details). The local shunt connected to the IADC0-IADC1 input is used to sense the Neutral current. The voltage sensors (VADC8, VADC9 and VADC10) are also directly connected to the 71 M 6543 (see Figure 27 for the connection details) and are also routed though the multiplexer, as seen in Figure 2. Meanwhile, the IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7 current inputs are configured as remote sensor digital interfaces and the corresponding samples are not routed through the multiplexer. For this configuration, the multiplexer sequence is as shown in Figure 4.

For a polyphase configuration with optional neutral current sensing using Current Transformer (CTs) sensors, as shown in Figure 3, all four current sensor inputs must be configured as a differential inputs, to be connected to their corresponding CTs (see Figure 29 for the differential CT connection details). The IADC0-IADC1 current sensor input is optionally used to sense the Neutral current for anti-tampering purposes. The voltage sensors (VADC8, VADC9 and VADC10) are directly connected to the 71 M 6543 (see Figure 27 for the voltage sensor connection details). No 71M6xx3 isolated sensors are used in this configuration and all sensors are routed though the multiplexer, as seen in Figure 3. For this configuration, the multiplexer sequence is as shown in Figure 5.

The multiplexer sequence shown in Figure 4 corresponds to the configuration shown in Figure 2. The frame duration is 13 CK 32 cycles (where CK32 $=32,768 \mathrm{~Hz}$ ), therefore, the resulting sample rate is $32,768 \mathrm{~Hz} / 13=2,520.6 \mathrm{~Hz}$. Note that Figure 4 only shows the currents that pass through the 71 M 6543 multiplexer, and does not show the currents that are copied directly into CE RAM from the remote sensors (see Figure 2), which are sampled during the second half of the multiplexer frame. The two unused conversion slots shown are necessary to produce the desired $2,520.6 \mathrm{~Hz}$ sample rate.


Figure 4: States in a Multiplexer Frame (MUX_DIV[3:0] = 6)

The multiplexer sequence shown in Figure 5 corresponds to the CT configuration shown in Figure 3. Since in this case all current sensors are locally connected to the 71 M 6543 , all currents are routed through the multiplexer, as seen in Figure 3. For this multiplexer sequence, the frame duration is 15 CK32 cycles (where CK32 $=32,768 \mathrm{~Hz}$ ), therefore, the resulting sample rate is $32,768 \mathrm{~Hz} / 15=2,184.5 \mathrm{~Hz}$.


Figure 5: States in a Multiplexer Frame (MUX_DIV[3:0] = 7)

Multiplexer advance, FIR initiation and chopping of the ADC reference voltage (using the internal CROSS signal, see 2.2.7 Voltage References) are controlled by the internal MUX_CTRL circuit. Additionally, MUX_CTRL launches each pass of the CE through its code. MUX_CTRL is clocked by CK32, the 32768 Hz clock from the PLL block. The behavior of the MUX_CTRL circuit is governed by:

- CHOP_E[1:0] (I/O RAM 0x2106[3:2])
- MUX_DIV[3:0] (I/O RAM 0x2100[7:4])
- FIR_LEN[1:0] (I/O RAM 0x210C[2:1])
- ADC_DIV (I/O RAM 0x2200[5])

The duration of each multiplexer state depends on the number of ADC samples processed by the FIR as determined by the FIR_LEN[1:0] (I/O RAM 0x210C[2:1] control field. Each multiplexer state starts on the rising edge of CK32, the 32-kHz clock.


It is required that MUX DIV[3:0] (I/O RAM 0x2100[7:4]) be set to zero while changing the ADC configuration to minimize system transients. After all configuration bits are set, MUX_DIV[3:0] should be set to the required value.

The duration of each time slot in CK32 cycles depends on $F I R_{-} L E N[1: 0], A D C_{-} D I V$ and $P L L \_F A S T$ :

Time_Slot_Duration $=\left(3-2^{*} P L L \_F A S T\right)^{*}\left(F I R_{\_} L E N[1: 0]+1\right) *\left(A D C \_D I V+1\right)$

The duration of a multiplexer frame in CK32 cycles is:

$$
\text { MUX_Frame_Duration }=3-2^{*} P L L \_F A S T+\text { Time_Slot_Duration * MUX_DIV[3:0] }
$$

The duration of a multiplexer frame in CK_FIR cycles is:
MUX frame duration (CK_FIR cycles) =

$$
\left[3-2^{*} P L L \_F A S T+\text { Time_Slot_Duration * } M U X_{-} D I V\right]^{*}\left(48+P L L \_F A S T^{*} 102\right)
$$

The ADC conversion sequence is programmable through the MUXn_SEL control fields (I/O RAM 0x2100 to $0 \times 2105$ ). As stated above, there are up to eleven ADC time slots in the 71 M 6543 , as set by MUX_DIV[3:0] (I/O RAM 0x2100[7:4]). In the expression MUXn_SEL[3:0] = x, ' n ' refers to the multiplexer frame time slot number and ' $x$ ' refers to the desired ADC input number or ADC handle (i.e., IADC0 to VADC10, or simply 0 to 10 decimal). Thus, there are a total of 11 valid ADC handles in the 71 M 6543 devices. For example, if $M U X 0 \_S E L[3: 0]=0$, then IADC0, corresponding to the sample from the IADC0-IADC1 input (configured as a differential input), is positioned in the multiplexer frame during time slot 0 . See Table 1 and Table 2 for the appropriate $M U X n \_S E L[3: 0]$ settings and other settings applicable to a particular meter configuration and CE code.

Note that when the remote sensor interface is enabled, the samples corresponding to the remote sensor currents do not pass through the 71 M 6543 multiplexer. The sampling of the remote current sensors occurs in the second half of the multiplexer frame. The VA, VB and VC voltages are assigned the last three slots in the frame. With this slot assignment for VA, VB and VC, the sampling of the corresponding remote sensor currents bears a precise timing relationship to their corresponding phase voltages, and delay compensation is accurately performed (see 2.2.3 Delay Compensation on page 19).

Also when using remote sensors, it is necessary to introduce unused slots to realize the number of slots specified by the MUX_DIV[3:0] (I/O RAM 0x2100[7:4]) field setting (see Figure 4 and Figure 5). The MUXn_SEL[3:0] control fields for these unused ("dummy") slots must be written with a valid ADC handle (i.e., 0 to 10 decimal) that is not otherwise being used. In this manner, the unused ADC handle, is used as a "dummy" place holder in the multiplexer frame, and the correct duration multiplexer frame sequence is generated and also the desired sample rate. The resulting sample data stored in the CE RAM location corresponding to the "dummy" ADC handle is ignored by the CE code. Meanwhile, the digital isolation interface takes care of automatically storing the samples for the remote current sensors in the appropriate CE RAM locations.

Delay compensation and other functions in the CE code require the settings for MUX_DIV[3:0], MUXn_SEL[3:0], RMT_E,FIR_LEN[1:0], ADC_DIV and PLL_FAST to be fixed for a given CE code. Refer to Table 1 and $\overline{\text { Table }} 2 \overline{\text { for }}$ fortings $\overline{\text { the }}$ applicable to the 71 M 6543 .

Table 3 summarizes the I/O RAM registers used for configuring the multiplexer, signals pins, and ADC. All listed registers are 0 after reset and wake from battery modes, and are readable and writable.

Table 3: Multiplexer and ADC Configuration Bits

| Name | Location | Description |
| :---: | :---: | :---: |
| MUX0_SEL[3:0] | 2105[3:0] | Selects the ADC input converted during time slot 0 . |
| MUX1_SEL[3:0] | 2105[7:4] | Selects the ADC input converted during time slot 1. |
| MUX2_SEL[3:0] | 2104[3:0] | Selects the ADC input converted during time slot 2. |
| MUX3_SEL[3:0] | 2104[7:4] | Selects the ADC input converted during time slot 3 . |
| MUX4_SEL[3:0] | 2103[3:0] | Selects the ADC input converted during time slot 4. |
| MUX5_SEL[3:0] | 2103[7:4] | Selects the ADC input converted during time slot 5 . |
| MUX6_SEL[3:0] | 2102[3:0] | Selects the ADC input converted during time slot 6. |
| MUX7_SEL[3:0] | 2102[7:0] | Selects the ADC input converted during time slot 7 . |
| MUX8_SEL[3:0] | 2101[3:0] | Selects the ADC input converted during time slot 8. |
| MUX9_SEL[3:0] | 2101[7:0] | Selects the ADC input converted during time slot 9 . |
| MUX10_SEL[3:0] | 2100[3:0] | Selects the ADC input converted during time slot 10. |
| ADC_DIV | 2200[5] | Controls the rate of the ADC and FIR clocks. |
| MUX_DIV[3:0] | 2100[7:4] | The number of ADC time slots in each multiplexer frame (maximum = 11). |
| PLL_FAST | 2200[4] | Controls the speed of the PLL and MCK. |
| FIR_LEN[1:0] | 210C[2:1] | Determines the number of ADC cycles in the ADC decimation FIR filter. |
| DIFF0_E | 210C[4] | Enables the differential configuration for analog input pins IADC0-IADC1 |
| DIFF2_E | 210C[5] | Enables the differential configuration for analog input pins IADC2-IADC3 |
| DIFF4_E | 210C[6] | Enables the differential configuration for analog input pins IADC4-IADC5 |
| DIFF6_E | 210C[7] | Enables the differential configuration for analog input pins IADC6-IADC7 |
| RMT2_E | 2709[3] | Enables the remote sensor interface transforming pins IADC2-IADC3 into a digital interface for communications with a 71M6xx3 sensor. |
| RMT4_E | 2709[4] | Enables the remote sensor interface transforming pins IADC4-IADC5 into a digital interface for communications with a 71M6xx3 sensor. |
| RMT6_E | 2709[5] | Enables the remote sensor interface transforming pins IADC6-IADC7 into a digital interface for communications with a 71 M 6 xx 3 sensor. |
| PRE_E | 2704[5] | Enables the 8x pre-amplifier. |

### 2.2.3 Delay Compensation

When measuring the energy of a phase (i.e., Wh and VARh) in a service, the voltage and current for that phase must be sampled at the same instant. Otherwise, the phase difference, $\Phi$, introduces errors.

$$
\phi=\frac{t_{\text {delay }}}{T} \cdot 360^{\circ}=t_{\text {delay }} \cdot f \cdot 360^{\circ}
$$

Where $f$ is the frequency of the input signal, $T=1 / f$ and $t_{\text {delay }}$ is the sampling delay between current and voltage.

Traditionally, sampling is accomplished by using two A/D converters per phase (one for voltage and the other one for current) controlled to sample simultaneously. Maxim's Single Converter Technology, however, exploits the 32-bit signal processing capability of its CE to implement "constant delay" all-pass filters. The all-pass filter corrects for the conversion time difference between the voltage and the corresponding current samples that are obtained with a single multiplexed A/D converter.

The "constant delay" all-pass filter provides a broad-band delay $360^{\circ}-\theta$, which is precisely matched to the difference in sample time between the voltage and the current of a given phase. This digital filter does not affect the amplitude of the signal, but provides a precisely controlled phase response.

The recommended ADC multiplexer sequence samples the current first, immediately followed by sampling of the corresponding phase voltage, thus the voltage is delayed by a phase angle $\Phi$ relative to the current. The delay compensation implemented in the CE aligns the voltage samples with their corresponding current samples by first delaying the current samples by one full sample interval (i.e., $360^{\circ}$ ), then routing the voltage samples through the all-pass filter, thus delaying the voltage samples by $360^{\circ}-\theta$, resulting in the residual phase error between the current and its corresponding voltage of $\theta-\Phi$. The residual phase error is negligible, and is typically less than $\pm 1.5$ milli-degrees at 100 Hz , thus it does not contribute to errors in the energy measurements.

When using remote sensors, the CE performs the same delay compensation described above to align each voltage sample with its corresponding current sample. Even though the remote current samples do not pass through the 71M6543 multiplexer, their timing relationship to their corresponding voltages is fixed and precisely known, provided that the MUXn_SEL[3:0] slot assignment fields are programmed as shown in Table 1. Note that these slot assignments result in VA, VB and VC occupying multiplexer slots 3, 4 and 5, respectively (see Figure 4).

### 2.2.4 ADC Pre-Amplifier

The ADC pre-amplifier is a low-noise differential amplifier with a fixed gain of 8 available only on the IADC0-IADC1 sensor input pins. A gain of 8 is enabled by setting PRE_E=1 (I/O RAM 0x2704[5]). When disabled, the supply current of the pre-amplifier is $<10 \mathrm{nA}$ and the gain is unity. With proper settings of the PRE_E and DIFF0_E (I/O RAM 0x210C[4]) bits, the pre-amplifier can be used whether differential mode is selected or not. $\overline{\text { For }}$ best performance, the differential mode is recommended. In order to save power, the bias current of the pre-amplifier and ADC is adjusted according to the ADC_DIV control bit (I/O RAM 0x2200[5]).

### 2.2.5 A/D Converter (ADC)

A single $2^{\text {nd }}$ order sigma-delta $A / D$ converter digitizes the voltage and current inputs to the device. The resolution of the ADC, including the sign bit, is 21 bits (FIR_LEN[1:0] = 01, I/O RAM 0x210C[2:1]), or 22 bits (FIR_LEN[1:0] = 10). The ADC is clocked by CKADC.

Initiation of each ADC conversion is controlled by the internal MUX_CTRL circuit as described earlier. At the end of each ADC conversion, the FIR filter output data is stored into the CE RAM location determined by the multiplexer selection.

### 2.2.6 FIR Filter

The finite impulse response filter is an integral part of the ADC and it is optimized for use with the multiplexer. The purpose of the FIR filter is to decimate the ADC output to the desired resolution. At the end of each ADC conversion, the output data is stored into the fixed CE RAM location determined by the multiplexer selection stored in the MUXn_SEL[3:0] fields. FIR data is stored after being shifted left by 9 bits.

### 2.2.7 Voltage References

A bandgap circuit provides the reference voltage to the ADC. The amplifier within the reference is chopper stabilized, i.e., the chopper circuit can be enabled or disabled by the MPU using the I/O RAM control field CHOP_E[1:0] (I/O RAM 0x2106[3:2]). The two bits in the CHOP_E[1:0] field enable the MPU to operate the chopper circuit in regular or inverted operation, or in toggling modes (recommended). When the chopper circuit is toggled in between multiplexer cycles, dc offsets on VREF are automatically be averaged out, therefore the chopper circuit should always be configured for one of the toggling modes.

Since the VREF band-gap amplifier is chopper-stabilized, the dc offset voltage, which is the most significant long-term drift mechanism in the voltage references (VREF), is automatically removed by the chopper circuit. Both the 71M6543 and the 71M6xx3 feature chopper circuits for their respective VREF voltage reference.

The general topology of a chopped amplifier is shown in Figure 6. The CROSS signal is an internal onchip signal and is not accessible on any pin or register.


Figure 6: General Topology of a Chopped Amplifier

It is assumed that an offset voltage Voff appears at the positive amplifier input. With all switches, as controlled by CROSS (an internal signal), in the A position, the output voltage is:

$$
\text { Voutp }- \text { Voutn }=G(\text { Vinp }+ \text { Voff }- \text { Vinn })=G(\text { Vinp }- \text { Vinn })+G \text { Voff }
$$

With all switches set to the B position by applying the inverted CROSS signal, the output voltage is:

$$
\begin{aligned}
& \text { Voutn }- \text { Voutp }=G(\text { Vinn }- \text { Vinp }+ \text { Voff })=G(\text { Vinn }- \text { Vinp })+G \text { Voff, or } \\
& \text { Voutp }- \text { Voutn }=G(\text { Vinp }- \text { Vinn })-G \text { Voff }
\end{aligned}
$$

Thus, when CROSS is toggled, e.g., after each multiplexer cycle, the offset alternately appears on the output as positive and negative, which results in the offset effectively being eliminated, regardless of its polarity or magnitude.
When CROSS is high, the connection of the amplifier input devices is reversed. This preserves the overall polarity of that amplifier gain; it inverts its input offset. By alternately reversing the connection, the amplifier's offset is averaged to zero. This removes the most significant long-term drift mechanism in the voltage reference. The CHOP_E[1:0] (I/O RAM 0x2106[3:2]) control field controls the behavior of CROSS. On the first CK32 rising edge after the last multiplexer state of its sequence, the multiplexer waits one additional CK32 cycle before beginning a new frame. At the beginning of this cycle, the value of CROSS is updated according to the CHOP_E[1:0] field. The extra CK32 cycle allows time for the chopped VREF to settle. During this cycle, MUXSYNC is held high. The leading edge of MUXSYNC initiates a pass through the CE program sequence.
CHOP_E[1:0] has four states: positive, reverse, and two toggle states. In the positive state, CHOP $_{-}$[1:0] $=01, \bar{C} R O S S$ is held low. In the reverse state, $C H O P_{-} E[1: 0]=10$, CROSS is held high. The two automatic toggling states are selected by setting CHOP_E=11 or CHOP_E=00.


Figure 7: CROSS Signal with CHOP_E $^{\boldsymbol{E}} \mathbf{= 0 0}$
Figure 7 shows CROSS over two accumulation intervals when $C H O P_{-} E[1: 0]=00$ : At the end of the first interval, CROSS is high, at the end of the second interval, CROSS is low. Operation with CHOP_E[1:0] = 00 does not require control of the chopping mechanism by the MPU.
In the second toggle state, CHOP_ $_{-} E[1: 0]=11$, CROSS does not toggle at the end of the last multiplexer cycle in an accumulation interval.

### 2.2.8 71M6xx3 Isolated Sensor Interface

### 2.2.8.1 General Description

Non-isolating sensors, such as shunt resistors, can be connected to the inputs of the 71 M 6543 via a combination of a pulse transformer and a 71M6xx3 IC (a top-level block diagram of this sensor interface is shown in Figure 31). The 71M6xx3 receives power directly from the 71 M 6543 via a pulse transformer and does not require a dedicated power supply circuit. The 71M6xx3 establishes 2-way communication with the 71 M 6543 , supplying current samples and auxiliary information such as sensor temperature via a serial data stream.

Up to three 71M6xx3 Isolated Sensors can be supported by the 71M6543. When a remote sensor interface is enabled, the two analog current inputs become re-configured as a digital remote sensor interface. For example, when control bit $R M T 2_{2} E=1$, the IADC2-IADC3 analog pins are re-configured as the digital interface pins to the remote sensor.

Each 71M6xx3 Isolated Sensor consists of the following building blocks:

- Power supply that derives power from pulses received from the 71M6543
- Bi-directional digital communications interface
- Shunt signal pre-amplifier
- 22-bit 2nd Order Sigma-Delta ADC Converter with precision bandgap reference (chopping amplifier)
- Temperature sensor (for digitally compensating VREF)
- Fuse system containing part-specific information

During an ordinary multiplexer cycle, the 71M6543 internally determines which other channels are enabled with MUX_DIV[3:0] (I/O RAM 0x2100[7:4]). At the same time, it decimates the modulator output from the 71M6xx3 Isolated Sensors. Each result is written to CE RAM during one of its CE access time slots.

### 2.2.8.2 Communication between 71M6543 and 71M6xx3 Isolated Sensor

The ADC of the 71M6xx3 derives its timing from the power pulses generated by the 71M6543 and as a result, operates its ADC slaved to the frequency of the power pulses. The generation of power pulses, as well as the communication protocol between the 71M6543 and 71M6xx3 Isolated Sensor, is automatic and transparent to the user. Details are not covered in this data sheet.

### 2.2.8.3 Control of the 71M6xx3 Isolated Sensor

The 71M6543 can read or write certain types of information from each 71M6xx3 remote sensor.
The data to be read is selected by a combination of the RCMD[4:0] and TMUXRn[2:0]. To perform a read transaction from one of the 71M6xx3 devices, the MPU first writes the TMUXRn[2:0] field (where $\mathrm{n}=2,4,6$, located at I/O RAM 0x270A[2:0], 0x270A[6:4] and 0x2709[2:0], respectively). Next, the MPU writes RCMD[4:0] (SFR 0xFC[4:0]) with the desired command and phase selection. When the RCMD[4:2] bits have cleared to zero, the transaction has been completed and the requested data is available in $R M T_{-} R D[15: 0]$ (I/O RAM 0x2602[7:0] is the MSB and $0 x 2603[7: 0]$ is the LSB). The read parity error bit, $P E R R_{-} R D$ (SFR $0 x F C[6]$ ) is also updated during the transaction. If the MPU writes to $R C M D[4: 0]$ before a previously initiated read transaction is completed, the command is ignored. Therefore, the MPU must wait for $R C M D[4: 2]=0$ before proceeding to issue the next remote sensor read command.

If the CE is running ( $C E \_E=1$ ), the MPU must write $R C M D[4: 0]$ immediately after a CE_BUSY rising edge. RCMD[4:0] must be written before the next rising edge of MUX_SYNC. Failure to do this can cause incorrect data to be read.

The $R C M D[4: 0]$ field is divided into two sub-fields, $C O M M A N D=R C M D[4: 2]$ and $P H A S E=R C M D[1: 0]$, as shown in Table 4.

Table 4. RCMD[4:0] Bits

| Command RCMD[4:2] |  | Phase Selector RCMD [1:0] |  | Associated TMUXRn Control Field |
| :---: | :---: | :---: | :---: | :---: |
| 000 | Invalid | 00 | Invalid | --- |
| 001 | Command 1 | 01 | IADC2-IADC3 | TMUXR2[2:0] |
| 010 | Command 2 | 10 | IADC4-IADC5 | TMUXR4[2:0] |
| 011 | Reserved | 11 | IADC6-IADC7 | TMUXR6[2:0] |
| 100 | Reserved |  |  |  |
| 101 | Invalid |  |  |  |
| 110 | Reserved |  |  |  |
| 111 | Reserved |  |  |  |

Notes:

1. Only two codes of RCMD[4:2] (SFR $0 x F C[4: 2]$ ) are relevant for normal operation. These are RCMD[4:2] $=001$ and 010. Codes 000 and 101 are invalid and will be ignored if used. The remaining codes are reserved and must not be used.
2. For the $R C M D[1: 0]$ control field, codes 01,10 and 11 are valid and 00 is invalid and must not be used.
3. The specific phase ( $\mathrm{A}, \mathrm{B}$ or C ) associated with each TMUXRn[2:0] field, is determined by how the IADCn input pins are connected in the meter design.

Table 5 shows the allowable combinations of values in RCMD[4:2] and TMUXRn[2:0], and the corresponding data type and format sent back by the 71M6xx3 remote sensor and how the data is stored in $R M T_{-} R D[15: 8]$ and $R M T_{-} R D[7: 0]$. The MPU selects which of the three phases is read by asserting the proper code in the $R C M D[\overline{1}: 0]$ field, as shown in Table 4.

Table 5: Remote Interface Read Commands

| RCMD[4:2] | TMUXRn[2:0] | Read Operation | RMT_RD [15:8] | RMT_RD [7:0] |
| :---: | :---: | :---: | :---: | :---: |
| 001 | 00X | $\begin{aligned} & \text { TRIMT[7:0] } \\ & \text { (trim fuse for all } 71 \mathrm{M} 6 \times 3 \times 3 \text { ) } \end{aligned}$ | TRIMT[7] $=$ RMT_RD[8] | TRIMT[6:0]=RMT_RD[7:1] |
| 001 | 11X | TRIMBGB[7:0] and TRIMBGD[7:0] <br> (additional trim fuses for <br> 71M6113 and 71M6203 only) | TRIMBGB[7:0] | TRIMBGD[7:0] |
| 010 | 00X | $\begin{aligned} & \text { STEMP[10:0] } \\ & \text { (sensed 71M6xx3 temperature) } \end{aligned}$ | $\begin{gathered} \text { STEMP[10: } 8]=R M T_{\text {(RMT_RD[15:11] are sign extended) }} R D[10: 8] \\ \hline \end{gathered}$ | STEMP[7:0] |
| 010 | 01X | VSENSE[7:0] (sensed 71 M $1 \times \times \times 3$ supply voltage) | All zeros | VSENSE[7:0] |
| 010 | 10X | $\begin{aligned} & \hline \begin{array}{l} \text { VERSION[7:0] } \\ \text { (chip version) } \end{array} \end{aligned}$ | VERSION[7:0] | All zeros |

## Notes:

1. TRIMT[7:0] is the VREF trim value for all 71M6xx3 devices. Note that the TRIMT[7:0] 8-bit value is formed by $R M T_{-} R D[8]$ and $R M T_{-} R D[7: 1]$. See the 71M6xxx Data Sheet for the equations related to TRIMT[7:0] and the corresponding temperature coefficient.
2. TRIMBGB[7:0] and TRIMBGD[7:0] are trim values used for characterizing the $71 \mathrm{M} 6113(0.5 \%)$ and 71 M 6203 ( $0.1 \%$ ) over temperature. See the 71M6xxx Data sheet for the equations related to TRIMBGB[7:0] and TRIMBGD[7:0] and the corresponding temperature coefficients.
3. See 2.5.6 71M6xx3 Temperature Sensor on page 56.
4. See 2.5.8 71M6xx3 VCC Monitor on page 56.

With hardware and trim-related information on each connected 71M6xx3 Isolated Sensor available to the 71M6543, the MPU can implement temperature compensation of the energy measurement based on the individual temperature characteristics of the 71M6xx3 Isolated Sensors. See 4.5 Metrology Temperature Compensation for details.

Table 6 shows all I/O RAM registers used for control of the external 71M6xx3 Isolated Sensors. See the 71M6xx3 Data Sheet for additional details.

Table 6: I/O RAM Control Bits for Isolated Sensor

| Name | Address | RST Default | WAKE <br> Default | R/W | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| RCMD [4:0] | $\begin{gathered} \text { SFR } \\ \text { FC[4:0] } \end{gathered}$ | 0 | 0 | R/W | When the MPU writes a non-zero value to RCMD, the 71 M 6543 issues a command to the corresponding isolated sensor selected with RCMD [1:0]. When the command is complete, the 71M6543 clears RCMD[4:2]. The command code itself is in RCMD[4:2]. |
| $\begin{aligned} & \text { PERR_RD } \\ & \text { PERR_WR } \end{aligned}$ | SFR FC[6] SFR FC[5] | 0 | 0 | R/W | The 71M6543 sets these bits to indicate that a parity error on the isolated sensor has been detected. Once set, the bits are remembered until they are cleared by the MPU. |
| CHOPR[1:0] | 2709[7:6] | 00 | 00 | R/W | The CHOP settings for the isolated sensors. 00 - Auto chop. Change every multiplexer frame. 01 - Positive <br> 10 - Negative <br> 11 - Same as 00 |
| TMUXR2[2:0] | 270A[2:0] | 000 | 000 | R/W | The TMUX bits for control of the isolated sensor. |
| TMUXR4[2:0] | 270A[6:4] | 000 | 000 | R/W | The TMUX bits for control of the isolated sensor. |
| TMUXR6[2:0] | 2709[2:0] | 000 | 000 | R/W | The TMUX bits for control of the isolated sensor. |
| $\begin{gathered} R M T_{-} R D[15: 8] \\ R M \overline{T_{-}} R D[7: 0] \end{gathered}$ | $\begin{aligned} & 2602[7: 0] \\ & 2603[7: 0] \end{aligned}$ | 0 | 0 | R | The read buffer for 71 M 6 xx 3 read operations. |
| RFLY_DIS | 210C[3] | 0 | 0 | R/W | Controls how the 71M6543 drives the 71M6xx3 power pulse. When set, the power pulse is driven high and low. When cleared, it is driven high followed by an open circuit fly-back interval. |
| RMT2_E | 2709[3] | 0 | 0 | R/W | Enables the isolated remote sensor interface and re-configures pins IADC2-IADC3 as a balanced pair digital remote interface. |
| RMT4_E | 2709[4] | 0 | 0 | R/W | Enables the isolated remote sensor interface and re-configures pins IADC4-IADC5 as a balanced pair digital remote interface. |
| RMT6_E | 2709[5] | 0 | 0 | R/W | Enables the isolated remote sensor interface and re-configures pins IADC6-IADC7 as a balanced pair digital remote interface. |

Refer to Table 70 starting on page 102 for more complete details about these I/O RAM locations.

### 2.3 Digital Computation Engine (CE)

The CE, a dedicated 32-bit signal processor, performs the precision computations necessary to accurately measure energy. The CE calculations and processes include:

- Multiplication of each current sample with its associated voltage sample to obtain the energy per sample (when multiplied by the constant sample time).
- Frequency-insensitive delay cancellation on all channels (to compensate for the delay between samples caused by the multiplexing scheme).
- $90^{\circ}$ phase shifter (for VAR calculations).
- Pulse generation.
- Monitoring of the input signal frequency (for frequency and phase information).
- Monitoring of the input signal amplitude (for sag detection).
- Scaling of the processed samples based on calibration coefficients.
- Scaling of samples based on temperature compensation information.


### 2.3.1 CE Program Memory

The CE program resides in flash memory. Common access to flash memory by the CE and MPU is controlled by a memory share circuit. Each CE instruction word is two bytes long. Allocated flash space for the CE program cannot exceed 4096 16-bit words ( 8 KB ). The CE program counter begins a pass through the CE code each time multiplexer state 0 begins. The code pass ends when a HALT instruction is executed. For proper operation, the code pass must be completed before the multiplexer cycle ends.

The CE program must begin on a 1 KB boundary of the flash address. The I/O RAM control field CE_LCTN[6/5:0] (I/O RAM 0x2109[6/5:0]) on the 71M6543F and CE_LCTN[6:0] (I/O RAM 0x2109[6:0]) on the 71 M 6543 G defines which 1 KB boundary contains the CE code. Thus, the first CE instruction is located at 1024*CE_LCTN[5:0] on the 71M6543F and 1024*CE_LCTN[6:0] on the 71M6543G.

### 2.3.2 CE Data Memory

The CE and MPU share data memory (RAM). Common access to XRAM by the CE and MPU is controlled by a memory share circuit. The CE can access up to 3 KB of the 5 KB data RAM (XRAM), i.e. from RAM address $0 \times 0000$ to $0 \times 0 \mathrm{C} 00$.

The XRAM can be accessed by the FIR filter block, the RTM circuit, the CE, and the MPU. Assigned time slots are reserved for FIR and MPU, respectively, to prevent bus contention for XRAM data access by the CE.
The MPU reads and writes the XRAM shared between the CE and MPU as the primary means of data communication between the two processors.

The CE is aided by support hardware to facilitate implementation of equations, pulse counters, and accumulators. This hardware is controlled through I/O RAM field $E Q U[2: 0]$ (equation assist, I/O RAM 0x2106[7:5]), bit DIO_PV (I/O RAM 0x2457[6]), bit DIO_PW (pulse count assist, I/O RAM 0x2457[7]), and SUM_SAMPS[12:0] (accumulation assist, I/O RAM 0x2107[4:0] and 0x2108[7:0]).

The integration time for each energy output, when using standard CE code, is SUM_SAMPS[12:0] /2184.53 (with MUX_DIV[3:0] = 7, I/O RAM 0x2100[7:4] ). CE hardware issues the XFER_BUSY interrupt when the accumulation is complete.

### 2.3.3 CE Communication with the MPU

The CE outputs six signals to the MPU: CE_BUSY, XFER_BUSY, XPULSE, YPULSE, WPULSE and VPULSE. These are connected to the MPU interrupt service. CE_BUSY indicates that the CE is actively processing data. This signal occurs once every multiplexer frame. XFER_BUSY indicates that the CE is updating to the output region of the CE RAM, which occurs whenever an accumulation cycle has been completed. Both, CE_BUSY and XFER_BUSY are cleared when the CE executes a HALT instruction.

XPULSE and YPULSE can be configured to interrupt the MPU and indicate zero crossings of the mains voltage, sag failures, or other significant events. Additionally, these signals can be connected directly to DIO pins to provide direct outputs from the CE. Interrupts associated with these signals always occur on the leading edge.

### 2.3.4 Meter Equations

The 71M6543 provides hardware assistance to the CE in order to support various meter equations. This assistance is controlled through I/O RAM field EQU[2:0] (equation assist, I/O RAM 0x2106[7:5]). The Compute Engine (CE) firmware configurations can implement the equations listed in Table 7. EQU[2:0] specifies the equation to be used based on the meter configuration and on the number of phases used for metering.

Table 7: Inputs Selected in Multiplexer Cycles

| EQU[2:0]* | Description | Wh and VARh formula |  |  | Recommended Multiplexer Sequence |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Element 0 | Element 1 | Element 2 |  |
| 2 | 2-element, 3-W, 3¢ Delta | VA - IA | VB • IB | N/A | IA VA IB VB |
| 3 | 2-element, 4-W, 3¢ Delta | $\mathrm{VA}(\mathrm{IA}-\mathrm{IB}) / 2$ | $\mathrm{VC} \cdot \mathrm{IC}$ | N/A | IA VA IB VB IC VC |
| 4 | 2-element, 4-W, 3¢ Wye | $\mathrm{VA}(\mathrm{IA}-\mathrm{IB}) / 2$ | $\mathrm{VB}(\mathrm{IC-IB}) / 2$ | N/A | $1 A$ VA IB VB IC VC |
| 5 | 3-element, 4-W, $3 \phi$ Wye | VA $\cdot 1 \mathrm{~A}$ | VB • IB | VC • IC | IA VA IB VB IC VC (ID) |

Note:

* Only EQU[2:0] = 5 is supported by the currently available CE code versions for the 71M6543. Contact your local Maxim representative for CE codes that support equations 2, 3, and 4.


### 2.3.5 Real-Time Monitor (RTM)

The CE contains a Real-Time Monitor (RTM), which can be programmed to monitor four selectable XRAM locations at full sample rate. The data from the four monitored locations are serially output to the TMUXOUT pin via the digital output multiplexer at the beginning of each CE code pass. The RTM can be enabled and disabled with RTM_E (I/O RAM 0x2106[1]). The RTM output clock is available on the TMUX2OUT pin. Each RTM word is clocked out in 35 cycles and contains a leading flag bit. See Figure 8 for the RTM output format. RTM is low when not in use.


Figure 8: RTM Timing

### 2.3.6 Pulse Generators

The 71M6543 provides four pulse generators, VPULSE, WPULSE, XPULSE and YPULSE. The XPULSE and YPULSE generators are used by standard CE code to output CE status indicators, for example the status of the sag detection, to DIO pins. All pulses can be configured to generate interrupts to the MPU.
The polarity of the pulses may be inverted with PLS_INV (I/O RAM 0x210C[0]). When this bit is set, the pulses are active high, rather than the more usual active low. $P L S_{-} I N V$ inverts all the pulse outputs.

The function of each pulse generator is determined by the CE code and the MPU code must configure the corresponding pulse outputs in agreement with the CE code. For example, standard CE code produces a mains zero-crossing pulse on XPULSE and a SAG pulse on YPULSE.

A common use of the zero-crossing pulses is to generate interrupts in order to drive real-time clock software in places where the mains frequency is sufficiently accurate to do so and also to adjust for crystal aging. A common use for the SAG pulse is to generate an interrupt that alerts the MPU when mains power is about to fail, so that the MPU code can store accumulated energy and other data to EEPROM before the V3P3SYS supply voltage actually drops.

### 2.3.6.1 XPULSE and YPULSE

Pulses generated by the CE may be exported to the XPULSE and YPULSE pulse output pins. Pins SEGDIO6 and SEGDIO7 are used for these pulses, respectively. Generally, the XPULSE and YPULSE outputs can be updated once on each pass of the CE code.

See 5.3 CE Interface Description on page 116 for details.

### 2.3.6.2 VPULSE and WPULSE

Referring to Figure 9, during each CE code pass the hardware stores exported WPULSE and VPULSE sign bits in an 8-bit FIFO and outputs them at a specified interval. This permits the CE code to calculate the VPULSE and WPULSE outputs at the beginning of its code pass and to rely on hardware to spread them over the multiplexer frame. As seen in Figure 9, the FIFO is reset at the beginning of each multiplexer frame. As also seen in Figure 9, the I/O RAM register PLS_INTERVAL[7:0] (I/O RAM 0x210B[7:0]) controls the delay to the first pulse update and the interval between subsequent updates. The LSB of the PLS_INTERVAL[7:0] register is equivalent to 4 CK_FIR cycles (CK_FIR is typically 4.9152 MHz if $P L L \_F A S T=1$ and $A D C \_D I V=0$, but other CK_FIR frequencies are possible; see the ADC_DIV definition in Table 70.) If PLS_INTERVAL[7:0]=0, the FIFO is deactivated and the pulse outputs are updated immediately.
The MUX frame duration in units of CK_FIR clock cycles is given by:
If $P L L_{-} F A S T=1$ :
MUX frame duration in CK_FIR cycles $=\left[1+\left(F I R_{-} L E N+1\right) *\left(A D C_{-} D I V+1\right) *\left(M U X \_D I V\right)\right]$ * $\left.150 /\left(A D C \_D I V+1\right)\right]$
If $P L L_{-} F A S T=0$ :
MUX frame duration in CK_FIR cycles $=\left[3+3^{*}\left(F I R_{-} L E N+1\right) *\left(A D C_{-} D I V+1\right) *\left(M U X \_D I V\right)\right]$ * $\left.48 /\left(A D C \_D I V+1\right)\right]$
PLS_INTERVAL[7:0] in units of CK_FIR clock cycles is calculated by:
PLS_INTERVAL[7:0] = floor ( Mux frame duration in CK_FIR cycles / CE pulse updates per Mux frame / 4 )
Since the FIFO resets at the beginning of each multiplexer frame, the user must specify
PLS_INTERVAL[7:0] so that all of the possible pulse updates occurring in one CE execution are output before the multiplexer frame completes. For instance, the 71 M 6543 CE code outputs six updates per multiplexer interval, and if the multiplexer interval is 1950 CK_FIR clock cycles long, the ideal value for the interval is $1950 / 6 / 4=81.25$. However, if $P L S \_I N T E R V A L[7: 0]=82$, the sixth output occurs too late and would be lost. In this case, the proper value for PLS_INTERVAL[7:0] is 81 (i.e., round down the result).

Since one LSB of PLS_INTERVAL[7:0] is equal to 4 CK_FIR clock cycles, the pulse time interval $T_{1}$ in units of CK_FIR clock cycles is:

$$
\mathrm{T}_{1}=4^{*} P L S \_I N T E R V A L[7: 0]
$$

If the FIFO is enabled (i.e., $P L S \_I N T E R V A L[7: 0] \neq 0$ ), hardware also provides a maximum pulse width feature in control register PLS_MAXWIDTH[7:0] (I/O RAM 0x210A). By default, WPULSE and VPULSE are negative pulses (i.e., low level pulses, designed to sink current through an LED). PLS_MAXWIDTH[7:0] determines the maximum negative pulse width $\mathrm{T}_{\text {MAx }}$ in units of CK_FIR clock cycles based on the pulse interval $\mathrm{T}_{\text {I }}$ according to the formula:

$$
\mathrm{T}_{\mathrm{MAX}}=\left(2 * P L S \_M A X W I D T H[7: 0]+1\right) * \mathrm{~T}_{\mathrm{I}}
$$

If $P L S \_M A X W I D T H=255$ or $P L S_{-} I N T E R V A L=0$, no pulse width checking is performed, and the pulses default to $50 \%$ duty cycle.
The polarity of the pulses may be inverted with the control bit PLS_INV (I/O RAM 0x210C[0]). When $P L S_{-} I N V$ is set, the pulses are active high. The default value for $P \bar{L} S_{-} I N V$ is zero, which selects active low pulses.

The WPULSE and VPULSE pulse generator outputs are available on pins SEGDIOO/WPULSE and SEGDIO1/VPULSE, respectively (pins 45 and 44). The pulses can also be output on OPT_TX pin 53 (see $O P T_{-} T X E[1: 0]$, I/O RAM 0x2456[3:2] for details).


Figure 9. Pulse Generator FIFO Timing

### 2.3.7 CE Functional Overview

The ADC processes one sample per channel per multiplexer cycle. Figure 10 shows the timing of the samples taken during one multiplexer cycle with MUX_DIV[3:0] = 7 (I/O RAM 0x2100[7:4]).
The number of samples processed during one accumulation cycle is controlled by the I/O RAM register SUM_SAMPS[12:0] (0x2107[4:0] and 0x2108[7:07). The integration time for each energy output is:

SUM_SAMPS[12:0] / 2184.53, where 2184.53 is the sample rate in Hz
For example, $S U M_{-} S A M P S[12: 0]=2184$ establishes 2184 multiplexer cycles per accumulation cycle or $2184 / 2184.53=0.9998$ seconds. After an accumulation cycle is completed, the XFER_BUSY interrupt signals to the MPU that accumulated data are available. The slight difference between the nominal length of the accumulation interval ( 1000 ms ) and the actual length of $999.8 \mathrm{~ms}(0.025 \%)$ is accounted for in the CE code and is of no practical consequence.


Figure 10: Samples from Multiplexer Cycle (Frame)
The end of each multiplexer cycle is signaled to the MPU by the CE_BUSY interrupt. At the end of each multiplexer cycle, status information, such as sag data and the digitized input signal, is available to the MPU.

## 833ms



Figure 11: Accumulation Interval
Figure 11 shows the accumulation interval resulting from SUM_SAMPS[12:0] = 1819 (I/O RAM 0x2107[4:0] and $0 x 2108[7: 07$ ), consisting of 1819 samples of $457.8 \mu \mathrm{~s}$ each, followed by the XFER_BUSY interrupt. The sampling in this example is applied to a 50 Hz signal. There is no correlation between the line signal frequency and the choice of SUM_SAMPS[12:0]. Furthermore, sampling does not have to start when the line voltage crosses the zero line, and the length of the accumulation interval need not be an integer multiple of the signal cycles.

### 2.4 80515 MPU Core

The 71 M6543 include an 80515 MPU (8-bit, 8051-compatible) that processes most instructions in one clock cycle. Using a 4.9 MHz clock results in a processing throughput of 4.9 MIPS . The 80515 architecture eliminates redundant bus states and implements parallel execution of fetch and execution phases. Normally, a machine cycle is aligned with a memory fetch, therefore, most of the 1-byte instructions are performed in a single machine cycle (MPU clock cycle). This leads to an $8 x$ average performance improvement (in terms of MIPS) over the Intel ${ }^{\circledR} 8051$ device running at the same clock frequency.
Table 8 shows the CKMPU frequency as a function of the MCK clock (19.6608 MHz) divided by the MPU clock divider MPU_DIV[2:0] (I/O RAM Ox2200[2:0]). Actual processor clocking speed can be adjusted to the total processing demand of the application (metering calculations, AMR management, memory management, LCD driver management and I/O management) using MPU_DIV[2:0], as shown in Table 8.

Table 8: CKMPU Clock Frequencies

| MPU_DIV [2:0] | CKMPU Frequency |
| :---: | :---: |
| 000 | 4.9152 MHz |
| 001 | 2.4576 MHz |
| 010 | 1.2288 MHz |
| 011 | 614.4 kHz |
| 100 |  |
| $y n$ | 307.2 kHz |
| 101 |  |
| 110 |  |
| 111 |  |

Typical measurement and metering functions based on the results provided by the internal 32-bit compute engine (CE) are available for the MPU as part of the Maxim demonstration code, which is provided to help reduce the product design cycle.

### 2.4.1 Memory Organization and Addressing

The 80515 MPU core incorporates the Harvard architecture with separate code and data spaces. Memory organization in the 80515 is similar to that of the industry standard 8051. There are three memory areas: Program memory (Flash, shared by MPU and CE), external RAM (Data RAM, shared by the CE and MPU, Configuration or I/O RAM), and internal data memory (Internal RAM). Table 9 shows the memory map.

## Program Memory

The 80515 can address up to 64 KB of program memory space ( $0 \times 0000$ to $0 x F F F F$ ). Program memory is read when the MPU fetches instructions or performs a MOVC operation.
After reset, the MPU starts program execution from program memory location $0 \times 0000$. The lower part of the program memory includes reset and interrupt vectors. The interrupt vectors are spaced at 8-byte intervals, starting from 0x0003.

## MPU External Data Memory (XRAM)

Both internal and external memory is physically located on the 71 M 6543 device. The external memory referred to in this documentation is only external to the 80515 MPU core.

5 KB of RAM starting at address $0 x 0000$ is shared by the CE and MPU. The CE normally uses the first 1 KB , leaving 4 KB for the MPU. Different versions of the CE code use varying amounts. Consult the documentation for the specific code version being used for the exact limit.

To change the slot assignments established by MUXn_SEL[3:0], first set MUX_DIV[3:0] to zero, then change the $M U X n_{-} S E L[3: 0]$ slot assignments, and finally set $M U X_{-} D I V[3: 0]$ to the number of active MUX frame slots.

The 80515 writes into external data memory when the MPU executes a MOVX @Ri,A or MOVX @DPTR,A instruction. The MPU reads external data memory by executing a MOVX A,@Ri or MOVX A,@DPTR instruction (PDATA, SFR 0xBF, provides the upper 8 bytes for the MOVX A,@Ri instruction).

## Internal and External Memory Map

Table 9 shows the address, type, use and size of the various memory components.
Table 9: Memory Map

| Address <br> (hex) | Memory <br> Technology | Memory <br> Type | Name | Typical Usage | Memory Size <br> (bytes) |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 0000-FFFF | Flash Memory | Non-volatile | Program memory | MPU Program and <br> non-volatile data | 64 KB |
|  | CE program <br> (on 1 KB boundary) | 3 KB max. |  |  |  |
| 0000-13FF | Static RAM | Volatile | External RAM <br> (XRAM) | Shared by CE and <br> MPU | 5 KB |
| 2000-27FF | Static RAM | Volatile | Configuration <br> RAM (I/O RAM) | Hardware control | 2 KB |
| $2800-287 \mathrm{~F}$ | Static RAM | Non-volatile <br> (battery) | Configuration <br> RAM (I/O RAM) | Battery-buffered <br> memory | 128 |
| 0000-00FF | Static RAM | Volatile | Internal RAM | Part of 80515 Core | 256 |

## MOVX Addressing

There are two types of instructions differing in whether they provide an 8-bit or 16-bit indirect address to the external data RAM.

In the first type, MOVX A,@Ri, the contents of R0 or R1 in the current register bank provide the eight lower-ordered bits of address. The eight high-ordered bits of the address are specified with the PDATA SFR. This method allows the user paged access ( 256 pages of 256 bytes each) to all ranges of the external data RAM.

In the second type of MOVX instruction, MOVX A,@DPTR, the data pointer generates a 16-bit address. This form is faster and more efficient when accessing very large data arrays (up to 64 KB ), since no additional instructions are needed to set up the eight high ordered bits of the address.

It is possible to mix the two MOVX types. This provides the user with four separate data pointers, two with direct access and two with paged access, to the entire 64 KB of external memory range.

## Dual Data Pointer

The Dual Data Pointer accelerates the block moves of data. The standard DPTR is a 16-bit register that is used to address external memory or peripherals. In the 80515 core, the standard data pointer is called $D P T R$, the second data pointer is called DPTR1. The data pointer select bit, located in the LSB of the DPS register (DPS[0], SFR 0x92), chooses the active pointer. $D P T R$ is selected when $D P S[0]=0$ and $D P T R 1$ is selected when $D P S[0]=1$.

The user switches between pointers by toggling the LSB of the DPS register. The values in the data pointers are not affected by the LSB of the DPS register. All DPTR related instructions use the currently selected DPTR for any activity.


The second data pointer may not be supported by certain compilers.
DPTR1 is useful for copy routines, where it can make the inner loop of the routine two instructions faster compared to the reloading of $D P T R$ from registers. Any interrupt routine using DPTR1 must save and restore $D P S, D P T R$ and DPTR1, which increases stack usage and slows down interrupt latency.

By selecting the Evatronics R80515 core in the Keil compiler project settings and by using the compiler directive "MODC2", dual data pointers are enabled in certain library routines.

An alternative data pointer is available in the form of the PDATA register ( $S F R 0 x B F$ ), sometimes referred to as USR2). It defines the high byte of a 16-bit address when reading or writing XDATA with the instruction MOVX A,@Ri or MOVX @Ri,A.

## Internal Data Memory Map and Access

The Internal data memory provides 256 bytes ( $0 x 00$ to $0 x F F$ ) of data memory. The internal data memory address is always 1 byte wide. Table 10 shows the internal data memory map.

The Special Function Registers (SFR) occupy the upper 128 bytes. The SFR area of internal data memory is available only by direct addressing. Indirect addressing of this area accesses the upper 128 bytes of Internal RAM. The lower 128 bytes contain working registers and bit addressable memory. The lower 32 bytes form four banks of eight registers (R0-R7). Two bits on the program memory status word (PSW, SFR $0 x D 0$ ) select which bank is in use. The next 16 bytes form a block of bit addressable memory space at addresses $0 \times 00-0 \times 7 \mathrm{~F}$. All of the bytes in the lower 128 bytes are accessible through direct or indirect addressing.

Table 10: Internal Data Memory Map

| Address Range |  | Direct Addressing | Indirect Addressing |
| :---: | :---: | :---: | :---: |
| $0 \times 80$ | $0 \times F F$ | Special Function Registers (SFRs) | RAM |
| $0 \times 30$ | $0 \times 7 \mathrm{~F}$ | Byte addressable area |  |
| $0 \times 20$ | $0 \times 2 \mathrm{~F}$ | Bit addressable area |  |
| $0 \times 00$ | $0 \times 1 \mathrm{~F}$ | Register banks R0...R7 |  |

### 2.4.2 Special Function Registers (SFRs)

A map of the Special Function Registers is shown in Table 11.
Only a few addresses in the SFR memory space are occupied, the others are not implemented. A read access to unimplemented addresses returns undefined data, while a write access has no effect. SFRs specific to the 71 M 6543 are shown in bold print on a gray field. The registers at $0 \times 80,0 \times 88,0 \times 90$, etc., are bit addressable, all others are byte addressable.

Table 11: Special Function Register Map

| Hex/ Bin | Bit Addressable | Byte Addressable |  |  |  |  |  |  | Bin/ <br> Hex |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | X000 | X001 | X010 | X011 | X100 | X101 | X110 | X111 |  |
| F8 | FLAG1 | VSTAT |  |  | REMOTE0 | SPII |  |  | FF |
| F0 | $B$ |  |  |  |  |  |  |  | F7 |
| E8 | IFLAGS |  |  |  |  |  |  |  | EF |
| E0 | $A$ |  |  |  |  |  |  |  | E7 |
| D8 | WDCON |  |  |  |  |  |  |  | DF |
| D0 | PSW |  |  |  |  |  |  |  | D7 |
| C8 | T2CON |  |  |  |  |  |  |  | CF |
| C0 | IRCON |  |  |  |  |  |  |  | C7 |
| B8 | IEN1 | IP1 | SORELH | S1RELH |  |  |  | PDATA | BF |
| B0 | P3 |  | FLSHCTL |  |  |  | FL_BANK | PGADR | B7 |
| A8 | IEN0 | IP0 | SORELL |  |  |  |  |  | AF |
| A0 | P2 | DIR2 | DIR0 |  |  |  |  |  | A7 |
| 98 | SOCON | SOBUF | IEN2 | SlCON | SlBUF | S1RELL | EEDATA | EECTRL | 9F |
| 90 | P1 | DIR1 | DPS |  | ERASE |  |  |  | 97 |
| 88 | TCON | TMOD | TLO | TL1 | TH0 | TH1 | CKCON |  | 8F |
| 80 | P0 | SP | DPL | DPH | DPL1 | DPH1 |  | PCON | 87 |

### 2.4.3 Generic 80515 Special Function Registers

Table 12 shows the location, description and reset or power-up value of the generic 80515 SFRs. Additional descriptions of the registers can be found at the page numbers listed in the table.

Table 12: Generic 80515 SFRs - Location and Reset Values

| Name | Address (Hex) | Reset value (Hex) | Description | Page(s) |
| :---: | :---: | :---: | :---: | :---: |
| P0 | 0x80 | 0xFF | Port 0 | 35 |
| SP | $0 \times 81$ | $0 \times 07$ | Stack Pointer | 34 |
| DPL | $0 \times 82$ | 0x00 | Data Pointer Low 0 | 34 |
| DPH | 0x83 | $0 \times 00$ | Data Pointer High 0 | 34 |
| DPL1 | $0 \times 84$ | $0 \times 00$ | Data Pointer Low 1 | 34 |
| DPH1 | $0 \times 85$ | $0 \times 00$ | Data Pointer High 1 | 34 |
| PCON | $0 \times 87$ | $0 \times 00$ | Power Reduction Modes, UART Speed Control | 38 |
| TCON | $0 \times 88$ | $0 \times 00$ | Timer/Counter Control | 41 |
| TMOD | 0x89 | 0x00 | Timer Mode Control | 39 |
| TLO | $0 \times 8 \mathrm{~A}$ | $0 \times 00$ | Timer 0, low byte | 38 |
| TL1 | $0 \times 8 \mathrm{~B}$ | $0 \times 00$ | Timer 1, high byte | 38 |
| TH0 | 0x8C | $0 \times 00$ | Timer 0, low byte | 38 |
| TH1 | $0 \times 8 \mathrm{D}$ | $0 \times 00$ | Timer 1, high byte | 38 |
| CKCON | $0 \times 8 \mathrm{E}$ | $0 \times 01$ | Clock Control (Stretch=1) | 35 |
| P1 | 0x90 | 0xFF | Port 1 | 35 |
| DPS | 0x92 | $0 \times 00$ | Data Pointer select Register | 31 |
| SOCON | 0x98 | $0 \times 00$ | Serial Port 0, Control Register | 37 |
| SOBUF | $0 \times 99$ | 0x00 | Serial Port 0, Data Buffer | 35 |
| IEN2 | 0x9A | $0 \times 00$ | Interrupt Enable Register 2 | 41 |
| SICON | 0x9B | $0 \times 00$ | Serial Port 1, Control Register | 37 |
| SIBUF | $0 \times 9 \mathrm{C}$ | $0 \times 00$ | Serial Port 1, Data Buffer | 35 |
| SIRELL | 0x9D | 0x00 | Serial Port 1, Reload Register, low byte | 35 |
| P2 | 0xA0 | 0xFF | Port 2 | 35 |
| IEN0 | 0xA8 | $0 \times 00$ | Interrupt Enable Register 0 | 40 |
| IPO | 0xA9 | $0 \times 00$ | Interrupt Priority Register 0 | 43 |
| SORELL | 0xAA | 0xD9 | Serial Port 0, Reload Register, low byte | 35 |
| P3 | 0xB0 | 0xFF | Port 3 | 35 |
| IEN1 | 0xB8 | $0 \times 00$ | Interrupt Enable Register 1 | 40 |
| IPI | 0xB9 | $0 \times 00$ | Interrupt Priority Register 1 | 43 |
| SORELH | 0xBA | $0 \times 03$ | Serial Port 0, Reload Register, high byte | 35 |
| SlRELH | 0xBB | 0x03 | Serial Port 1, Reload Register, high byte | 35 |
| PDATA | 0xBF | $0 \times 00$ | High address byte for MOVX@Ri - also called USR2 | 31 |
| IRCON | $0 \times \mathrm{CO}$ | $0 \times 00$ | Interrupt Request Control Register | 41 |
| T2CON | 0xC8 | $0 \times 00$ | Polarity for INT2 and INT3 | 41 |
| PSW | 0xD0 | $0 \times 00$ | Program Status Word | 34 |
| WDCON | 0xD8 | $0 \times 00$ | Baud Rate Control Register (only WDCON[7] bit used) | 35 |
| A | 0xE0 | 0x00 | Accumulator | 34 |
| B | 0xF0 | $0 \times 00$ | B Register | 34 |

## Accumulator (ACC, A, SFR Ox E0):

$A C C$ is the accumulator register. Most instructions use the accumulator to hold the operand. The mnemonics for accumulator-specific instructions refer to accumulator as $A$, not $A C C$.

## B Register (SFR 0xF0):

The $B$ register is used during multiply and divide instructions. It can also be used as a scratch-pad register to hold temporary data.

## Program Status Word (PSW, SFR 0xD0):

This register contains various flags and control bits for the selection of the register banks (see Table 13).
Table 13: PSW Bit Functions (SFR 0xD0)

| PSW Bit | Symbol | Function |  |  |
| :---: | :---: | :---: | :---: | :---: |
| 7 | CV | Carry flag. |  |  |
| 6 | $A C$ | Auxiliary Carry flag for BCD operations. |  |  |
| 5 | F0 | General purpose Flag 0 available for user. <br> $\sqrt{ }$ F0 is not to be confused with the F0 flag in the CESTATUS register. |  |  |
| 4 | RSI | Register bank select control bits. The contents of RSI and RS0 select the working register bank: |  |  |
|  |  | RSI/RSO | Bank selected | Location |
|  |  | 00 | Bank 0 | 0x00-0x07 |
| 3 | RSO | 01 | Bank 1 | $0 \times 08-0 \times 0 \mathrm{~F}$ |
|  |  | 10 | Bank 2 | 0x10-0x17 |
|  |  | 11 | Bank 3 | 0x18-0x1F |
| 2 | OV | Overflow flag. |  |  |
| 1 | - | User defined flag. |  |  |
| 0 | $P$ | Parity flag, affected by hardware to indicate odd or even number of one bits in the Accumulator, i.e. even parity. |  |  |

## Stack Pointer (SP, SFR 0x81):

The stack pointer is a 1-byte register initialized to $0 \times 07$ after reset. This register is incremented before PUSH and CALL instructions, causing the stack to begin at location 0x08.

## Data Pointer:

The data pointers (DPTR and DPRT1) are 2 bytes wide. The lower part is DPL (SFR 0x82) and DPL1 (SFR $0 x 84$ ), respectively. The highest is $D P H$ (SFR $0 x 83$ ) and $D P H 1$ (SFR $0 \times 85$ ), respectively. The data pointers can be loaded as two registers (e.g. MOV DPL,\#data8). They are generally used to access external code or data space (e.g. MOVC A,@A+DPTR or MOVX A,@DPTR respectively).

## Program Counter:

The program counter $(P C)$ is 2 bytes wide and initialized to $0 \times 0000$ after reset. This register is incremented when fetching operation code or when operating on data from program memory.

## Port Registers:

SEGDIO0 through SEGDIO15 are controlled by Special Function Registers $P 0, P 1, P 2$, and $P 3$ as shown in Table 14. Above SEGDIO15, the LCD_SEGDIOn [ ] registers in I/O RAM are used. Since the direction bits are contained in the upper nibble of each SFR Pn register and the DIO bits are contained in the lower nibble, it is possible to configure the direction of a given DIO pin and set its output value with a single write operation, thus facilitating the implementation of bit-banged interfaces. Writing a 1 to a DIO_DIR bit configures the corresponding DIO as an output, while writing a 0 configures it as an input. Writing a 1 to a DIO bit causes the corresponding pin to be at high level (V3P3), while writing a 0 causes the corresponding pin to be held at a low level (GND). See 2.5.10 Digital I/O for additional details.

Table 14: Port Registers (SEGDIOO-15)

| SFR <br> Name | SFR <br> Address | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $P 0$ | 80 | DIO_DIR[3:0] |  |  | $D I O[3: 0]$ |  |  |  |  |
| $P 1$ | 90 | $D I O \_D I R[7: 4]$ |  |  | $D I O[7: 4]$ |  |  |  |  |
| $P 2$ | A0 | $D I O \_D I R[11: 8]$ |  |  | $D I 1: 8]$ |  |  |  |  |
| $P 3$ | B0 | $D I O_{2} D I R[15: 12]$ |  |  | $D I O[15: 11]$ |  |  |  |  |

All DIO ports on the chip are bi-directional. Each of them consists of a latch (SFR P0 to P3), an output driver and an input buffer, therefore the MPU can output or read data through any of these ports. Even if a DIO pin is configured as an output, the state of the pin can still be read by the MPU, for example when counting pulses issued via DIO pins that are under CE control.

At power-up SEGDIO0-15 are configured as outputs, but the pins are in a high-impedance state because PORT_E = 0 (I/O RAM 0x270C[5]). Host firmware should first configure SEGDIO0-15 to the desired state, then set $P O R T_{-} E=1$ to enable the function.

## Clock Stretching (CKCON[2:0], SFR 0x8E)

The CKCON[2:0] field defines the stretch memory cycles that are used for MOVX instructions when accessing external peripherals. The practical value of this register for the 71 M 6543 is to guarantee access to XRAM between CE, MPU, and SPI. The default setting of CKCON[2:0] (001) should be changed to 000 for best performance.
Table 15 shows how the signals of the External Memory Interface change when stretch values are set from 0 to 7 . The widths of the signals are counted in MPU clock cycles. The post-reset state of the CKCON[2:0] field (001), which is shown in bold in the table, performs the MOVX instructions with a stretch value equal to 1 .

Table 15: Stretch Memory Cycle Width

| CKCON[2:0] | Stretch <br> Value | Read Signal Width |  | Write Signal Width |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | memrd | memaddr | memwr |  |
| 000 | 0 | 1 | 1 | 2 | 1 |
| $\mathbf{0 0 1}$ | $\mathbf{1}$ | $\mathbf{2}$ | $\mathbf{2}$ | $\mathbf{3}$ | $\mathbf{1}$ |
| 010 | 2 | 3 | 3 | 4 | 2 |
| 011 | 3 | 4 | 4 | 5 | 3 |
| 100 | 4 | 5 | 5 | 6 | 4 |
| 101 | 5 | 6 | 6 | 7 | 5 |
| 110 | 6 | 7 | 7 | 8 | 6 |
| 111 | 7 | 8 | 8 | 9 | 7 |

### 2.4.4 Instruction Set

All instructions of the generic 8051 microcontroller are supported. A complete list of the instruction set and of the associated op-codes is contained in the 71M654x Software User's Guide (SUG).

### 2.4.5 UARTs

The 71M6543 include a UART (UARTO) that can be programmed to communicate with a variety of AMR modules and other external devices. A second UART (UART1) is connected to the optical port, as described in the 2.5.9 UART and Optical Interface on page 56.
The UARTs are dedicated 2-wire serial interfaces, which can communicate with an external host processor at up to 38,400 bits $/ \mathrm{s}$ (with MPU clock $=1.2288 \mathrm{MHz}$ ). The operation of the RX and TX UARTO pins is as follows:

- UARTO RX: Serial input data are applied at this pin. Conforming to RS-232 standard, the bytes are input LSB first.
- UARTO TX: This pin is used to output the serial data. The bytes are output LSB first.

The 71M6543 has several UART-related registers for the control and buffering of serial data.
A single SFR register serves as both the transmit buffer and receive buffer (S0BUF, SFR $0 x 99$ for UART0 and SlBUF, SFR 0x9C for UART1). When written by the MPU, SxBUF acts as the transmit buffer, and when read by the MPU, it acts as the receive buffer. Writing data to the transmit buffer starts the transmission by the associated UART. Received data are available by reading from the receive buffer. Both UARTs can simultaneously transmit and receive data.

WDCON[7] (SFR 0xD8) selects whether timer 1 or the internal baud rate generator is used. All UART transfers are programmable for parity enable, parity, 2 stop bits/1 stop bit and XON/XOFF options for variable communication baud rates from 300 to 38400 bps. Table 16 shows how the baud rates are calculated. Table 17 shows the selectable UART operation modes.

Table 16: Baud Rate Generation

|  | Using Timer 1 $(\text { WDCON[7] }=0)$ | Using Internal Baud Rate Generator ( WDCON[7] = 1) |
| :---: | :---: | :---: |
| UARTO | $2^{\text {smod }}{ }^{\text {f }}$ CKMPU $/\left(384{ }^{\text {* }}\right.$ (256-TH1) $)$ | $2^{\text {smod * }} \mathrm{f}_{\mathrm{CKMPU}} /\left(64{ }^{\text {* }}\left(2^{10}-\right.\right.$ SOREL $\left.)\right)$ |
| UART1 | N/A | $\mathrm{f}_{\text {CKMPU }} /\left(32\right.$ * (2 ${ }^{10}$-SlREL) $)$ |

SOREL and S1REL are 10-bit values derived by combining bits from the respective timer reload registers. (SORELL, SORELH, S1RELL, SIRELH are SFR 0xAA, SFR 0xBA, SFR 0x9D and SFR 0xBB, respectively) SMOD is the SMOD bit in the SFR PCON register (SFR 0x87). TH1 (SFR 0x8D) is the high byte of timer 1.

Table 17: UART Modes

|  | UART 0 | UART 1 |
| :---: | :--- | :--- |
| Mode 0 | N/A | Start bit, 8 data bits, parity, stop bit, variable <br> baud rate (internal baud rate generator) |
| Mode 1 | Start bit, 8 data bits, stop bit, variable <br> baud rate (internal baud rate generator <br> or timer 1) | Start bit, 8 data bits, stop bit, variable baud <br> rate (internal baud rate generator) |
| Mode 2 | Start bit, 8 data bits, parity, stop bit, <br> fixed baud rate 1/32 or 1/64 of f fKMPU | N/A |
| Mode 3 | Start bit, 8 data bits, parity, stop bit, <br> variable baud rate (internal baud rate <br> generator or timer 1) | N/A |

Parity of serial data is available through the $P$ flag of the accumulator. 7-bit serial modes with parity, such as those used by the FLAG protocol, can be simulated by setting and reading bit 7 of 8 -bit output data. 7 -bit serial modes without parity can be simulated by setting bit 7 to a constant 1. 8 -bit serial modes with parity can be simulated by setting and reading the $9{ }^{\text {th }}$ bit, using the control bits TB80 (S0CON[3]) and TB81 (S1CON[3]) in the S0CON (SFR 0x98) and S1CON (SFR 0x9B) registers for transmit and RB81 (S1CON[2]) for receive operations.

All supported operation modes use oversampling for the incoming bit stream when receiving data. Each bit is sampled three times at the projected middle of the bit duration. This technique allows for deviations of the received baud rate from nominal of up to $3.5 \%$.

The feature of receiving 9 bits (Mode 3 for UART0, Mode A for UART1) can be used as handshake signals for inter-processor communication in multi-processor systems. In this case, the slave processors have bit SM20 (S0CON[5]) for UART0, or SM21 (SICON[5] for UART1, set to 1. When the master processor outputs the slave's address, it sets the $9^{\text {th }}$ bit to 1 , causing a serial port receive interrupt in all the slaves. The slave processors compare the received byte with their address. If there is a match, the addressed slave clears SM20 or SM21 and receive the rest of the message. The rest of the slaves ignore the message. After
addressing the slave, the host outputs the rest of the message with the $9^{\text {th }}$ bit set to 0 , so no additional serial port receive interrupts is generated.

## UART Control Registers:

The functions of UART0 and UART1 depend on the setting of the Serial Port Control Registers S0CON and S1CON shown in Table 18 and Table 19, respectively, and the PCON register shown in Table 20.


Since the TIO, RIO, TI1 and RI1 bits are in an SFR bit addressable byte, common practice would be to clear them with a bit operation, but this must be avoided. The hardware implements bit operations as a byte wide read-modify-write hardware macro. If an interrupt occurs after the read, but before the write, its flag is cleared unintentionally.

The proper way to clear these flag bits is to write a byte mask consisting of all ones except for a zero in the location of the bit to be cleared. The flag bits are configured in hardware to ignore ones written to them.

Table 18: The S0CON (UART0) Register (SFR 0x98)

| Bit | Symbol | Function |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| S0CON[7] | SM0 | The SM0 and SM1 bits set the UART0 mode: |  |  |  |
|  |  | Mode | Description | SM0 | SM1 |
|  |  | 0 | N/A | 0 | 0 |
|  |  | 1 | 8-bit UART | 0 | 1 |
| SOCON[6] | SM1 | 2 | 9-bit UART | 1 | 0 |
|  |  | 3 | 9-bit UART | 1 | 1 |
| S0CON[5] | SM20 | Enables the inter-processor communication feature. |  |  |  |
| SOCON[4] | REN0 | If set, enables serial reception. Cleared by software to disable reception. |  |  |  |
| SOCON[3] | TB80 | The 9th transmitted data bit in Modes 2 and 3 . Set or cleared by the MPU, depending on the function it performs (parity check, multiprocessor communication etc.) |  |  |  |
| S0CON[2] | RB80 | In Modes 2 and 3 it is the $9^{\text {th }}$ data bit received. In Mode 1, SM20 is 0, RB80 is the stop bit. In mode 0, this bit is not used. Must be cleared by software. |  |  |  |
| S0CON[1] | TIO | Transmit interrupt flag; set by hardware after completion of a serial transfer. Must be cleared by software (see Caution above). |  |  |  |
| S0CON[0] | RIO | Receive interrupt flag; set by hardware after completion of a serial reception. Must be cleared by software (see Caution above). |  |  |  |

Table 19: The S1CON (UART1) Register (SFR 0x9B)

| Bit | Symbol | Function |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| SICON[7] | SM | Sets the baud rate and mode for UART1. |  |  |  |
|  |  | SM | Mode | Description | Baud Rate |
|  |  | 0 | A | 9-bit UART | variable |
|  |  | 1 | B | 8-bit UART | variable |
| SlCON[5] | SM21 | Enables the inter-processor communication feature. |  |  |  |
| SlCON[4] | REN1 | If set, enables serial reception. Cleared by software to disable reception. |  |  |  |
| SlCON[3] | TB81 | The $9^{\text {th }}$ transmitted data bit in Mode A. Set or cleared by the MPU, depending on the function it performs (parity check, multiprocessor communication etc.) |  |  |  |
| SICON[2] | RB81 | In Modes A and B , it is the $9^{\text {th }}$ data bit received. In Mode B , if SM21 is $0, R B 81$ is the stop bit. Must be cleared by software |  |  |  |
| SlCON[1] | TII | Transmit interrupt flag, set by hardware after completion of a serial transfer. Must be cleared by software (see Caution above). |  |  |  |
| SICON[0] | RII | Receive interrupt flag, set by hardware after completion of a serial reception. Must be cleared by software (see Caution above). |  |  |  |

Table 20: PCON Register Bit Description (SFR 0x87)

| Bit | Symbol | Function |
| :---: | :--- | :--- |
| $P C O N[7]$ | $S M O D$ | The $S M O D$ bit doubles the baud rate when set |

### 2.4.6 Timers and Counters

The 80515 has two 16-bit timer/counter registers: Timer 0 and Timer 1. These registers can be configured for counter or timer operations.

In timer mode, the register is incremented every machine cycle, i.e. it counts up once for every 12 periods of the MPU clock. In counter mode, the register is incremented when the falling edge is observed at the corresponding input signal T0 or T1 (T0 and T1 are the timer gating inputs derived from certain DIO pins, see 2.5.10 Digital I/O). Since it takes 2 machine cycles to recognize a 1-to-0 event, the maximum input count rate is $1 / 2$ of the clock frequency (CKMPU). There are no restrictions on the duty cycle, however to ensure proper recognition of the 0 or 1 state, an input should be stable for at least 1 machine cycle.
Four operating modes can be selected for Timer 0 and Timer 1, as shown in Table 21 and Table 22. The TMOD (SFR 0x89) register, shown in
Table 23, is used to select the appropriate mode. The timer/counter operation is controlled by the TCON (SFR 0x88) register, which is shown in Table 24. Bits TR1 (TCON[6]) and TR0 (TCON[4]) in the TCON register start their associated timers when set.

Table 21: Timers/Counters Mode Description

| M1 | M0 | Mode | Function |
| :---: | :---: | :---: | :---: |
| 0 | 0 | Mode 0 | 13-bit Counter/Timer mode with 5 lower bits in the TLO or TL1 (SFR $0 x 8 A$ or $S F R 0 \times 8 B$ ) register and the remaining 8 bits in the TH0 or TH1 (SFR 0x8C or SFR 0x8D) register (for Timer 0 and Timer 1, respectively). The 3 high order bits of TLO and TL1 are held at zero. |
| 0 | 1 | Mode 1 | 16-bit Counter/Timer mode. |
| 1 | 0 | Mode 2 | 8-bit auto-reload Counter/Timer. The reload value is kept in TH 0 or TH1, while TLO or TL1 is incremented every machine cycle. When $T L(\mathrm{x})$ overflows, a value from $T H(\mathrm{x})$ is copied to $T L(\mathrm{x})$ (where x is 0 for counter/timer 0 or 1 for counter/timer 1. |
| 1 | 1 | Mode 3 | If Timer 1 Ml and $\mathrm{M0}$ bits are set to 1 , Timer 1 stops. <br> If Timer $0 M 1$ and $M 0$ bits are set to 1 , Timer 0 acts as two independent 8 -bit Timer/Counters. |

$\sqrt{ }$In Mode 3, TLO is affected by TR0 and gate control bits, and sets the TF0 flag on overflow, while TH0 is affected by the TR1 bit, and the TF1 flag is set on overflow.
Table 22 specifies the combinations of operation modes allowed for Timer 0 and Timer 1.
Table 22: Allowed Timer/Counter Mode Combinations

|  | Timer 1 |  |  |
| :---: | :---: | :---: | :---: |
|  | Mode 0 | Mode 1 | Mode 2 |
| Timer 0 - mode 0 | Yes | Yes | Yes |
| Timer 0 - mode 1 | Yes | Yes | Yes |
| Timer 0 - mode 2 | Not allowed | Not allowed | Yes |

Table 23: TMOD Register Bit Description (SFR 0x89)

| Bit | Symbol | Function |
| :---: | :---: | :---: |
| Timer/Counter 1: |  |  |
| TMOD [7] | Gate | If TMOD[7] is set, external input signal control is enabled for Counter 1. The TR0 bit in the TCON register (SFR 0x88) must also be set in order for Counter 0 to increment. With these settings, Counter 0 increments on every falling edge of the logic signal applied to one or more of the SEGDIO2-11 pins, as specified by the contents of the $D I O \_R 2$ through $D I O \_R 11$ registers. See 2.5.10 Digital I/O and LCD Segment Drivers and Table 46. |
| TMOD[6] | $C / T$ | Selects timer or counter operation. When set to 1 , a counter operation is performed. When cleared to 0 , the corresponding register functions as a timer. |
| TMOD[5:4] | M1:M0 | Selects the mode for Timer/Counter 0 as shown in Table 21. |
| Timer/Counter 0 |  |  |
| TMOD [3] | Gate | If $T M O D[3]$ is set, external input signal control is enabled for Counter 0 . The TR1 bit in the TCON register (SFR 0x88) must also be set in order for Counter 1 to increment. With these settings, Counter 1 increments on every falling edge of the logic signal applied to one or more of the SEGDIO2-11 pins, as specified by the contents of the $D I O \_R 2$ through $D I O \_R 11$ registers. See 2.5.10 Digital I/O and LCD Segment Drivers and Table 46. |
| TMOD[2] | $C / T$ | Selects timer or counter operation. When set to 1 , a counter operation is performed. When cleared to 0 , the corresponding register functions as a timer. |
| TMOD [1:0] | M1:M0 | Selects the mode for Timer/Counter 1, as shown in Table 21. |

Table 24: The TCON Register Bit Functions (SFR 0x88)

| Bit | Symbol | Function |
| :--- | :--- | :--- |
| TCON[7] | TF1 | The Timer 1 overflow flag is set by hardware when Timer 1 overflows. <br> This flag can be cleared by software and is automatically cleared when an <br> interrupt is processed. |
| TCON[6] | TR1 | Timer 1 run control bit. If cleared, Timer 1 stops. |
| TCON[5] | TF0 | Timer 0 overflow flag set by hardware when Timer 0 overflows. This flag <br> can be cleared by software and is automatically cleared when an interrupt <br> is processed. |
| TCON[4] | TR0 | Timer 0 Run control bit. If cleared, Timer 0 stops. |
| TCON[3] | IE1 | Interrupt 1 edge flag is set by hardware when the falling edge on external <br> pin int1 is observed. Cleared when an interrupt is processed. |
| TCON[2] | IT1 | Interrupt 1 type control bit. Selects either the falling edge or low level on <br> input pin to cause an interrupt. |
| $T C O N[1]$ | IE0 | Interrupt 0 edge flag is set by hardware when the falling edge on external <br> pin int0 is observed. Cleared when an interrupt is processed. |
| $T C O N[0]$ | IT0 | Interrupt 0 type control bit. Selects either the falling edge or low level on <br> input pin to cause interrupt. |

### 2.4.7 WD Timer (Software Watchdog Timer)

There is no internal software watchdog timer. Use the standard hardware watchdog timer instead (see 2.5.13 Hardware Watchdog Timer).

### 2.4.8 Interrupts

The 80515 provides 11 interrupt sources with four priority levels. Each source has its own interrupt request flag(s) located in a special function register (TCON, IRCON, and SCON). Each interrupt requested by the corresponding flag can be individually enabled or disabled by the enable bits in IEN0 (SFR 0xA8), IEN1 (SFR 0xB8), and IEN2 (SFR 0x9A). Figure 12 shows the device interrupt structure.

Referring to Figure 12, interrupt sources can originate from within the 80515 MPU core (referred to as Internal Sources) or can originate from other parts of the 71 M 6543 SoC (referred to as External Sources). There are seven external interrupt sources, as seen in the leftmost part of Figure 12, and in Table 25 and Table 26 (i.e., EX0-EX6).

## Interrupt Overview

When an interrupt occurs, the MPU vectors to the predetermined address as shown in Table 37. Once the interrupt service has begun, it can be interrupted only by a higher priority interrupt. The interrupt service is terminated by a return from instruction, RETI. When an RETI is performed, the processor returns to the instruction that would have been next when the interrupt occurred.

When the interrupt condition occurs, the processor also indicates this by setting a flag bit. This bit is set regardless of whether the interrupt is enabled or disabled. Each interrupt flag is sampled once per machine cycle, then samples are polled by the hardware. If the sample indicates a pending interrupt when the interrupt is enabled, then the interrupt request flag is set. On the next instruction cycle, the interrupt is acknowledged by hardware forcing an LCALL to the appropriate vector address, if the following conditions are met:

- No interrupt of equal or higher priority is already in progress.
- An instruction is currently being executed and is not completed.
- The instruction in progress is not RETI or any write access to the registers IEN0, IEN1, IEN2, IP0 or IP1.


## Special Function Registers for Interrupts

The following SFR registers control the interrupt functions:

- The interrupt enable registers: IENO, IEN1 and IEN2 (see Table 25, Table 26 and Table 27).
- The Timer/Counter control registers, TCON and T2CON (see Table 28 and Table 29).
- The interrupt request register, IRCON (see Table 30).
- The interrupt priority registers: IP0 and IP1 (see Table 35).

Table 25: The IEN0 Bit Functions (SFR 0xA8)

| Bit | Symbol | $\quad$ Function |
| :---: | :---: | :--- |
| $I E N O[7]$ | $E A L$ | $E A L=0$ disables all interrupts. |
| $I E N O[6]$ | - | Not used. |
| $I E N O[5]$ | - | Not used. |
| $I E N O[4]$ | $E S O$ | $E S 0=0$ disables serial channel 0 interrupt. |
| $I E N O[3]$ | $E T 1$ | $E T 1=0$ disables timer 1 overflow interrupt. |
| $I E N O[2]$ | $E X 1$ | $E X 1=0$ disables external interrupt 1. |
| $I E N O[1]$ | $E T 0$ | $E T 0=0$ disables timer 0 overflow interrupt. |
| $I E N O[0]$ | $E X 0$ | $E X 0=0$ disables external interrupt 0. |

Table 26: The IEN1 Bit Functions (SFR 0xB8)

| Bit | Symbol | Function |
| :---: | :---: | :--- |
| $I E N 1[7]$ | - | Not used. |
| $I E N 1[6]$ | - | Not used. |
| $I E N 1[5]$ | $E X 6$ | $E X 6=0$ disables external interrupt 6. |
| $I E N 1[4]$ | $E X 5$ | $E X 5=0$ disables external interrupt 5. |
| $I E N 1[3]$ | $E X 4$ | $E X 4=0$ disables external interrupt 4. |
| $I E N 1[2]$ | $E X 3$ | $E X 3=0$ disables external interrupt 3. |
| $I E N 1[1]$ | $E X 2$ | $E X 2=0$ disables external interrupt 2. |
| $I E N 1[0]$ | - | Not used. |

Table 27: The IEN2 Bit Functions (SFR 0x9A)

| Bit | Symbol | Function |
| :---: | :---: | :--- |
| $I E N 2[0]$ | $E S 1$ | $E S 1=0$ disables the serial channel 1 interrupt. |

Table 28: TCON Bit Functions (SFR 0x88)

| Bit | Symbol | Function |
| :---: | :---: | :--- |
| $T C O N[7]$ | $T F 1$ | Timer 1 overflow flag. |
| $T C O N[6]$ | $T R 1$ | Not used for interrupt control. |
| $T C O N[5]$ | $T F 0$ | Timer 0 overflow flag. |
| $T C O N[4]$ | $T R 0$ | Not used for interrupt control. |
| $T C O N[3]$ | IE1 | External interrupt 1 flag. |
| TCON[2] | IT1 | External interrupt 1 type control bit: <br> $0=$ interrupt on low level. <br> = interrupt on falling edge. |
| $T C O N[1]$ | IE0 | External interrupt 0 flag |
| $T C O N[0]$ | IT0 | External interrupt 0 type control bit: <br> $0=$ interrupt on low level. <br> $1=$ interrupt on falling edge. |

Table 29: The T2CON Bit Functions (SFR 0xC8)

| Bit | Symbol | Function |
| :---: | :---: | :--- |
| $T 2 C O N[7]$ | - | Not used. |
| $T 2 C O N[6]$ | $I 3 F R$ | Polarity control for INT3: <br> $0=$ falling edge. <br> $1=$ rising edge. |
| $T 2 C O N[5]$ | $I 2 F R$ | Polarity control for INT2: <br> $0=$ falling edge. <br> $1=$ rising edge. |
| $T 2 C O N[4: 0]$ | - | Not used. |

Table 30: The IRCON Bit Functions (SFR 0xC0)

| Bit | Symbol |  |
| :---: | :---: | :--- |
| IRCON[7] | - | Not used. |
| IRCON[6] | - | Not used. |
| IRCON[5] | IEX6 | 1 = External interrupt 6 flag. |
| IRCON[4] | IEX5 | 1 = External interrupt 5 flag. |
| IRCON $[3]$ | IEX4 | 1 = External interrupt 4 flag. |
| IRCON $[2]$ | IEX3 | 1 = External interrupt 3 flag. |
| IRCON[1] | IEX2 | 1 = External interrupt 2 flag. |
| IRCON[0] | - | Not used. |

TF0 and TF1 (Timer 0 and Timer 1 overflow flags) is automatically cleared by hardware when the service routine is called (Signals T0ACK and T1ACK - port ISR - active high when the service routine is called). IE0, IE1, and IEX2-IEX6 are cleared automatically when hardware causes execution to vector to the interrupt service routine.

## External MPU Interrupts

The seven external interrupts are the interrupts external to the 80515 core, i.e. signals that originate in other parts of the 71M6543, for example the CE, DIO, RTC, or EEPROM interface.

The external interrupts are connected as shown in Table 31. The polarity of interrupts 2 and 3 is programmable in the MPU via the $I 3 F R$ and $I 2 F R$ bits in $T 2 C O N$ (SFR $0 x C 8$ ). Interrupts 2 and 3 should be programmed for falling sensitivity $(I 3 F R=I 2 F R=0)$. The generic 8051 MPU literature states that interrupts 4 through 6 are defined as rising-edge sensitive. Thus, the hardware signals attached to interrupts 5 and 6 are inverted to achieve the edge polarity shown in Table 31.

Table 31: External MPU Interrupts

| External <br> Interrupt | Connection | Polarity | Flag Reset |
| :---: | :--- | :---: | :---: |
| 0 | Digital I/O (IE0) | see 2.5 .10 | automatic |
| 1 | Digital I/O (IE1) | see 2.5 .10 | automatic |
| 2 | CE_PULSE (IE_XPULSE, IE_YPULSE, IE_WPULSE, <br> IE_VPULSE) | rising | manual |
| 3 | CE_BUSY (IE3) | falling | automatic |
| 4 | VSTAT (VSTAT[2:0] changed) (IE4) | rising | automatic |
| 5 | EEPROM busy (falling), SPI (rising) (IE_EEX, IE_SPI) | - | manual |
| 6 | XFER_BUSY (falling), RTC_1SEC, RTC_1MIN, RTC_T <br> (IE_XFER, IE_RTC1S, IE_RTC1M, IE_RTCT) | falling | manual |

External interrupt 0 and 1 can be mapped to pins on the device using DIO resource maps. See 2.5.10 Digital I/O for more information.

SFR enable bits must be set to permit any of these interrupts to occur. Likewise, each interrupt has its own flag bit, which is set by the interrupt hardware, and reset by the MPU interrupt handler. XFER_BUSY, RTC_1SEC, RTC_1MIN, RTC_T, SPI, PLLRISE and PLLFALL have their own enable and flag bits in addition to the interrupt 6, 4 and enable and flag bits (see Table 32: Interrupt Enable and Flag Bits).


IE0 through IEX6 are cleared automatically when the hardware vectors to the interrupt handler. The other flags, IE_XFER through IE_VPULSE, are cleared by writing a zero to them.

Since these bits are in an SFR bit addressable byte, common practice would be to clear them with a bit operation, but this must be avoided. The hardware implements bit operations as a byte wide read-modify-write hardware macro. If an interrupt occurs after the read, but before the write, its flag is cleared unintentionally.

The proper way to clear the flag bits is to write a byte mask consisting of all ones except for a zero in the location of the bit to be cleared. The flag bits are configured in hardware to ignore ones written to them.

Table 32: Interrupt Enable and Flag Bits

| Interrupt Enable |  | Interrupt Flag |  | Interrupt Description |
| :---: | :---: | :---: | :---: | :--- |
| Name | Location | Name | Location |  |
| $E X 0$ | SFR A8[[0] | IE0 | SFR 88[1] | External interrupt 0 |
| $E X 1$ | SFR A8[2] | IE1 | SFR 88[3] | External interrupt 1 |
| $E X 2$ | SFR B8[1] | IEX2 | SFR C0[1] | External interrupt 2 |
| $E X 3$ | SFR B8[2] | IEX3 | SFR C0[2] | External interrupt 3 |
| $E X 4$ | SFR B8[3] | IEX4 | SFR C0[3] | External interrupt 4 |
| $E X 5$ | SFR B8[4] | IEX5 | SFR C0[4] | External interrupt 5 |
| $E X 6$ | SFR B8[5] | IEX6 | SFR C0[5] | External interrupt 6 |
| $E X X X E R$ | $2700[0]$ | IE_XFER | SFR E8[0] | XFER_BUSY interrupt (int 6) |
| $E X \_R T C 1 S ~$ | $2700[1]$ | IE_RTC1S | SFR E8[1] | RTC_1SEC interrupt (int 6) |


| Interrupt Enable |  | Interrupt Flag |  | Interrupt Description |
| :---: | :---: | :---: | :---: | :---: |
| Name | Location | Name | Location |  |
| EX_RTCIM | 2700[2] | IE_RTC1M | SFR E8[2] | RTC_1MIN interrupt (int 6) |
| EX_RTCT | 2700[4] | IE_RTCT | SFR E8[4] | RTC_T interrupt (int 6) |
| EX_SPI | 2701 [7] | IE_SPI | SFR F8[7] | SPI interrupt |
| $E X_{-E E X}$ | 2700[7] | IE_EEX | SFR E8[7] | EEPROM interrupt |
| EX_XPULSE | 2700[6] | IE_XPULSE | SFR E8[6] | CE_Xpulse interrupt (int 2) |
| EX_YPULSE | 2700[5] | IE_YPULSE | SFR E8[5] | CE_Ypulse interrupt (int 2) |
| EX_WPULSE | 2701[6] | IE_WPULSE | SFR F8[6] | CE_Wpulse interrupt (int 2) |
| EX_VPULSE | 2701[5] | IE_VPULSE | SFR F8[5] | CE_Vpulse interrupt (int 2) |

## Interrupt Priority Level Structure

All interrupt sources are combined in groups, as shown in Table 33.
Table 33: Interrupt Priority Level Groups

| Group | Group Members |  |
| :---: | :--- | :--- |
| 0 | External interrupt 0 | Serial channel 1 interrupt |
| 1 | Timer 0 interrupt | External interrupt 2 |
| 2 | External interrupt 1 | External interrupt 3 |
| 3 | Timer 1 interrupt | External interrupt 4 |
| 4 | Serial channel 0 interrupt | External interrupt 5 |
| 5 | - | External interrupt 6 |

Each group of interrupt sources can be programmed individually to one of four priority levels (as shown in Table 34) by setting or clearing one bit in the SFR interrupt priority register IPO (SFR 0xA9) and one in IPI(SFR 0xB9) (Table 35). If requests of the same priority level are received simultaneously, an internal polling sequence as shown in Table 36 determines which request is serviced first.

Changing interrupt priorities while interrupts are enabled can easily cause software defects. It is best to set the interrupt priority registers only once during initialization before interrupts are enabled.

Table 34: Interrupt Priority Levels

| $\boldsymbol{I P I}[\mathbf{x}]$ | $\boldsymbol{I P 0}[\mathrm{x}]$ | Priority Level |
| :---: | :---: | :--- |
| 0 | 0 | Level 0 (lowest) |
| 0 | 1 | Level 1 |
| 1 | 0 | Level 2 |
| 1 | 1 | Level 3 (highest) |

Table 35: Interrupt Priority Registers (IP0 and IPI)

| Register | Address | Bit 7 <br> (MSB) | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | Bit 0 <br> (LSB) |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $I P 0$ | SFR 0xA9 | - | - | $I P 0[5]$ | $I P 0[4]$ | $I P 0[3]$ | $I P 0[2]$ | $I P 0[1]$ | $I P 0[0]$ |
| $I P 1$ | SFR 0xB9 | - | - | $I P 1[5]$ | $I P I[4]$ | $I P 1[3]$ | $I P 1[2]$ | $I P 1[1]$ | $I P 1[0]$ |

Table 36: Interrupt Polling Sequence


## Interrupt Sources and Vectors

Table 37 shows the interrupts with their associated flags and vector addresses.
Table 37: Interrupt Vectors

| Interrupt <br> Request Flag | Description | Interrupt Vector <br> Address |
| :---: | :--- | :---: |
| $I E 0$ | External interrupt 0 | $0 \times 0003$ |
| $T F 0$ | Timer 0 interrupt | $0 \times 000 \mathrm{~B}$ |
| $I E 1$ | External interrupt 1 | $0 \times 0013$ |
| $T F 1$ | Timer 1 interrupt | $0 \times 001 \mathrm{~B}$ |
| RIO/TIO | Serial channel 0 interrupt | $0 \times 0023$ |
| RII/TI1 | Serial channel 1 interrupt | $0 \times 0083$ |
| $I E X 2$ | External interrupt 2 | $0 \times 004 \mathrm{~B}$ |
| $I E X 3$ | External interrupt 3 | $0 \times 0053$ |
| $I E X 4$ | External interrupt 4 | $0 \times 005 \mathrm{~B}$ |
| $I E X 5$ | External interrupt 5 | $0 \times 0063$ |
| $I E X 6$ | External interrupt 6 | $0 \times 006 \mathrm{~B}$ |



Figure 12: Interrupt Structure

### 2.5 On-Chip Resources

### 2.5.1 Physical Memory

### 2.5.1.1 Flash Memory

The device includes 64 KB (71M6543F) or 128 KB (71M6543G) of on-chip flash memory. The flash memory primarily contains MPU and CE program code. It also contains images of the CE RAM and I/O RAM. On power-up, before enabling the CE, the MPU copies these images to their respective locations.
Flash space allocated for the CE program is limited to 4096 16-bit words ( 8 KB ). The CE program must begin on a 1-KB boundary of the flash address space. The CE_LCTN[6/5:0] (I/O RAM 0x2109[5:07) field on the 71M6543F and the CE_LCTN[6:0] (I/O RAM 0x2109[6:0]) field on the 71M6543G define which 1-KB boundary contains the CE code. Thus, the first CE instruction is located at $1024^{*} C E \_L C T N[6 / 5: 0]$ on the 71M6543F and at 1024*CE_LCTN[6:0] on the 71M6543G.
Flash memory can be accessed by the MPU, the CE, and by the SPI interface (R/W).
Table 38: Flash Memory Access

| Access by | Access <br> Type | Condition |
| :---: | :---: | :--- |
| MPU | R/W/E | W/E only if CE is disabled. |
| CE | $R$ |  |
| SPI | R/W/E | Access only when SFM is invoked (MPU halted). |

## Flash Write Procedures

If the FLSH_UNLOCK[3:0] (I/O RAM 0x2702[7:4]) key is correctly programmed, the MPU may write to the flash memory. This is one of the non-volatile storage options available to the user in addition to external EEPROM.

The flash program write enable bit, FLSH_PSTWR (SFR 0xB2[0]), differentiates 80515 data store instructions (MOVX@DPTR,A) between Flash and XRAM writes. This bit is automatically cleared by hardware after each byte write operation. Write operations to this bit are inhibited when interrupts are enabled.

If the CE is enabled ( $C E=E=1, I / O R A M 0 x 2106[07$ ), flash write operations must not be attempted unless $F L S H_{-} P S T W R$ is set. This bit enables the "posted flash write" capability. FLSH_PSTWR has no effect when $C E \_E=0$ ). When $C E \_E=1$, however, $F L S H_{-} P S T W R$ delays a flash write until the time interval between the CE code passes. During this delay time, the FLSH_PEND (SFR 0xB2[3]) bit is high, and the MPU continues to execute commands. When the CE code pass ends (CE_BUSY falls), the FLSH_PEND bit falls and the write operation occurs. The MPU can query the $F L S H_{-} P E N D$ bit to determine when the write operation has been completed. While $F L S H_{-} P E N D=1$, further flash write requests are ignored.

## Updating Individual Bytes in Flash Memory

The original state of a flash byte is $0 x F F$ (all bits are 1). Once a value other than $0 x F F$ is written to a flash memory cell, overwriting with a different value usually requires that the cell be erased first. Since cells cannot be erased individually, the page has to be first copied to RAM, followed by a page erase. After this, the page can be updated in RAM and then written back to the flash memory.

## Flash Erase Procedures

Flash erasure is initiated by writing a specific data pattern to specific SFR registers in the proper sequence. These special pattern/sequence requirements prevent inadvertent erasure of the flash memory.

The mass erase sequence is:

- Write 1 to the FLSH_MEEN bit (SFR 0xB2[1]).
- Write the pattern 0xAA to the FLSH_ERASE (SFR 0x94) register.

The mass erase cycle can only be initiated when the ICE port is enabled.

The page erase sequence is:

- Write the page address to FLSH_PGADR[5:0] (SFR 0xB7[7:2]).
- Write the pattern $0 \times 55$ to the FLSH_ERASE register (SFR 0x94).


## Bank-Switching in the 71M6543G

The 128 KB program memory in the 71M6543G consists of a fixed lower bank of 32 KB , addressable at $0 \times 0000$ to $0 x 7 F F F$ plus an upper banked area of 32 KB , addressable at $0 \times 8000$ to $0 x F F F F$. The I/O RAM register FL_BANK[1:0] (SFR 0xB6[1:0]) is used to switch four memory banks of 32 KB each into the address range from $0 x 8000$ to $0 x F F F F$. Note that when $F L_{-} B A N K[1: 0]$ (SFR 0xB6[1:0]) $=0$, the upper bank is the same as the lower bank.

Table 39: Bank Switching with FL_BANK[1:0] (SFR 0xB6[1:0])in the 71M6543G

| 71M6543G <br> FL_BANK[1:0] | Address Range for Lower <br> Bank (0x0000-0x7FFF) | Address Range for Upper <br> Bank (0x8000-0xFFFF) |
| :---: | :---: | :---: |
| 00 | $0 \times 0000-0 \times 7 F F F$ | $0 \times 0000-0 \times 7 F F F$ |
| 01 | $0 \times 0000-0 \times 7 F F F$ | $0 \times 8000-0 \times F F F F$ |
| 10 | $0 \times 0000-0 \times 7 F F F$ | $0 \times 10000-0 \times 17 F F F$ |
| 11 | $0 \times 0000-0 \times 7 F F F$ | $0 \times 18000-0 \times 1 F F F F$ |

In the 71M6543G, the address that the FLSH_PGADR[6:0] (SFR 0xB7[7:1]) points to in the program address space can reference different flash memory locations, depending on the setting of the FL_BANK[1:0] (SFR 0xB6[1:0]) bits. The CE_LCTN[6:0] (I/O RAM 0x2109[6:0]) field on the 71M6543G on the other hand, points directly to a location in the flash memory are not affected by the FL_BANK[1:0] (SFR 0xB6[1:0]) bits
Program Security
When enabled, the security feature limits the ICE to global flash erase operations only. All other ICE operations, such as reading via the SPI or ICE port, are blocked. This guarantees the security of the user's MPU and CE program code. Security is enabled by MPU code that is executed in a 64 CKMPU cycle pre-boot interval before the primary boot sequence begins. Once security is enabled, the only way to disable it is to perform a global erase of the flash, followed by a chip reset.

The first 64 cycles of the MPU boot code are called the pre-boot phase because during this phase the ICE is inhibited. A read-only status bit, PREBOOT (SFR 0xB2[7]), identifies these cycles to the MPU. Upon completion of pre-boot, the ICE can be enabled and is permitted to take control of the MPU.

The security enable bit, SECURE (SFR $0 x B 2[6]$ ), is reset whenever the chip is reset. Hardware associated with the bit allows only ones to be written to it. Thus, pre-boot code may set SECURE to enable the security feature but may not reset it. Once $S E C U R E$ is set, the pre-boot and CE code are protected from erasure, and no external read of program code is possible.
Specifically, when the SECURE bit is set, the following applies:

- The ICE is limited to bulk flash erase only.
- Page zero of flash memory, the preferred location for the user's pre-boot code, may not be page-erased by either MPU or ICE. Page zero may only be erased with global flash erase.
- Write operations to page zero, whether by MPU or ICE are inhibited.

The 71M6543 also includes hardware to protect against unintentional Flash write and erase. To enable flash write and erase operations, a 4-bit hardware key that must be written to the FLSH_UNLOCK[3:0] field. The key is the binary number ' 0010 '. If $F L S H \_U N L O C K[3: 0]$ is not ' 0010 ', the Flash erase and write operation is inhibited by hardware. Proper operation of this security key requires that there be no firmware function that writes '0010' to FLSH_UNLOCK[3:0]. The key should be written by the external SPI master, in the case of SPI flash programming (SFM mode), or through the ICE interface in the case of ICE flash programming. When a boot loader is used, the key should be sent to the boot load code which then writes it to

FLSH_UNLOCK[3:0]. FLSH_UNLOCK[3:0] is not automatically reset. It should be cleared when the SPI or ICE has finished changing the Flash. Table 40 summarizes the I/O RAM registers used for flash security.

Table 40: Flash Security

| Name | Location | Rst | Wk | Dir | Description |
| :--- | :---: | :---: | :---: | :---: | :--- |
| FLSH_UNLOCK[3:0] | 2702[7:4] | 0 | 0 | R/W | Must be a 2 to enable any flash modification. <br> See the description of Flash security for <br> more details. |
| SECURE | SFR B2[6] | 0 | 0 | R/W | Inhibits erasure of page 0 and flash addresses <br> above the beginning of CE code as defined <br> by $C E \_L C T N[6 / 5: 0](I / O R A M ~ 0 x 2109[5: 0])$ on <br> the 71M6543F and $C E \_L C T N[6: 0] ~ I / O R A M$ <br> Ox2109[6:0]) on the 71M6543G. Also inhibits <br> the read of flash via the ICE and SPI ports. |

## SPI Flash Mode

In normal operation, the SPI slave interface cannot read or write the flash memory. However, the 71M6543 contains a Special Flash Mode (SFM) that facilitates initial (production) programming of the flash memory. When the 71M6543 is in SFM mode, the SPI interface can erase, read, and write the flash. Other memory elements such as XRAM and I/O RAM are not accessible to the SPI in this mode. In order to protect the flash contents, several operations are required before the SFM mode is successfully invoked.

When the 71M6543G is operating SFM, SPI single-byte transactions are used to write to FL_BANK[1:0] (SFR 0xB6[1:0]). During an SPI single-byte transaction, SPI_CMD[1:0] will over-write the contents of FL_BANK[1:0] (SFR 0xB6[1:0]). This will allow for access of the entire 128 KB flash memory while operating in SFM.
If the SPI port is used for code updates (in lieu of a programmer that uses the ICE port), then a code that disables the flash access via SPI can potentially lock out flash program updates.

Details on the SFM can be found in 2.5.12 SPI Slave Port.

### 2.5.1.2 MPU/CE RAM

The 71 M 6543 includes 5 KB of static RAM memory on-chip (XRAM) plus 256 bytes of internal RAM in the MPU core. The 5KB of static RAM are used for data storage by both MPU and CE and for the communication between MPU and CE.

### 2.5.1.3 I/O RAM (Configuration RAM)

The I/O RAM can be seen as a series of hardware registers that control basic hardware functions. I/O RAM address space starts at 0x2000. The registers of the I/O RAM are listed in Table 68.

The 71M6543 includes 128 bytes non-volatile RAM memory on-chip in the I/O RAM address space (addresses $0 \times 2800$ to $0 x 287 \mathrm{~F}$ ). This memory section is supported by the voltage applied at VBAT_RTC, and the data in it are preserved in BRN, LCD, and SLP modes as long as the voltage at VBAT_RTC is within specification.

### 2.5.2 Oscillator

The 71 M 6543 oscillator drives a standard 32.768 kHz watch crystal. This type of crystal is accurate and does not require a high-current oscillator circuit. The oscillator has been designed specifically to handle watch crystals and is compatible with their high impedance and limited power handling capability. The oscillator power dissipation is very low to maximize the lifetime of any battery attached to VBAT_RTC.
Oscillator calibration can improve the accuracy of both the RTC and metering. Refer to 2.5.4, Real-Time Clock (RTC) for more information.

The oscillator is powered from the V3P3SYS pin or from the VBAT_RTC pin, depending on the V3OK internal bit (i.e., V3OK $=1$ if V3P3SYS $\geq 2.8 \mathrm{VDC}$ and $V 3 O K=0$ if $\mathrm{V} 3 \mathrm{P} 3 \mathrm{SYS}<2.8 \mathrm{VDC}$ ). The oscillator requires approximately 100 nA , which is negligible compared to the internal leakage of a battery.

Although the oscillator may appear to work when VBAT is not connected, this mode of operation is not recommended.

$$
\begin{aligned}
& \text { If VBAT_RTC is connected to a drained battery or disconnected, a battery test that sets } \\
& \text { TEMP_BAT may drain the supply connected to VBAT_RTC and cause the oscillator to stop. A } \\
& \text { stopped oscillator may force the device to reset. Therefore, an unexpected reset during a battery } \\
& \text { test should be interpreted as a battery failure. }
\end{aligned}
$$

### 2.5.3 PLL and Internal Clocks

Timing for the device is derived from the 32.768 kHz crystal oscillator output that is multiplied by a PLL by 600 to obtain 19.660800 MHz , the master clock (MCK). All on-chip timing, except for the RTC clock, is derived from MCK. Table 41 provides a summary of the clock functions and their controls.

The two general-purpose counter/timers contained in the MPU are controlled by CKMPU (see 2.4.6 Timers and Counters).
The master clock can be boosted to 19.66 MHz by setting the PLL_FAST bit = 1 (I/O RAM 0x2200[4]) and can be reduced to 6.29 MHz by $P L L \_F A S T=0$. The MPU clock frequency CKMPU is determined by another divider controlled by the I/O RAM control field MPU_DIV[2:0] (I/O RAM 0x2200[2:0]) and can be set to $\mathrm{MCK}^{*} 2^{-\left(M P U_{-} D I V+2\right)}$ where MPU_DIV[2:0] may vary from 0 to 4 . When the ICE_E pin is high, the circuit also generates the 9.83 MHz clock for use by the emulator.
The PLL is only turned off in SLP mode or in LCD mode when $L C D_{-} B S T E$ is disabled. The $L C D_{-} B S T E$ value depends on the setting of the $L C D \_V M O D E[1: 0]$ field (see Table 51).
When the part is waking up from SLP or LCD modes, the PLL is turned on in 6.29 MHz mode, and the PLL frequency is not be accurate until the PLL_OK (SFR OxF9[4]) flag rises. Due to potential overshoot, the MPU should not change the value of $P L L_{-} F A S T$ until $P L L_{-} O K$ is true.

Table 41: Clock System Summary

| Clock | Derived From | Fixed Frequency or Range |  |  | Function |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | PLL_FAST $=1$ | PLL_FAST $=0$ | Controlled by |  |
| OSC | Crystal | 32.768 kHz |  | - | Crystal clock |
| MCK | Crystal/PLL | $\begin{gathered} 19.660800 \mathrm{MHz} \\ (600 * \mathrm{CK} 32) \end{gathered}$ | $\begin{gathered} \hline 6.291456 \mathrm{MHz} \\ \left(192^{*}\right. \text { CK32) } \end{gathered}$ | PLL_FAST | Master clock |
| CKCE | MCK | 4.9152 MHz | 1.5728 MHz | - | CE clock |
| CKADC | MCK | $\begin{aligned} & 4.9152 \mathrm{MHz}, \\ & 2.4576 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 1.572864 \mathrm{MHz}, \\ & 0.786432 \mathrm{MHz} \end{aligned}$ | ADC_DIV | ADC clock |
| CKMPU | MCK | $\begin{gathered} 4.9152 \mathrm{MHz} \ldots \\ 307.2 \mathrm{kHz} \end{gathered}$ | $\begin{gathered} 1.572864 \mathrm{MHz} . . \\ 98.304 \mathrm{kHz} \end{gathered}$ | MPU_DIV[2:0] | MPU clock |
| CKICE | MCK | $\begin{gathered} 9.8304 \mathrm{MHz} . . \\ 614.4 \mathrm{kHz} \end{gathered}$ | $\begin{gathered} 3.145728 \mathrm{MHz} \ldots \\ 196.608 \mathrm{kHz} \end{gathered}$ | MPU_DIV[2:0] | ICE clock |
| CKOPTMOD | MCK | 38.40 kHz | 38.6 kHz | - | Optical UART Modulation |
| CK32 | MCK | 32.768 kHz |  | - | 32 kHz clock |

### 2.5.4 Real-Time Clock (RTC)

### 2.5.4.1 RTC General Description

The RTC is driven directly by the crystal oscillator and is powered by either the V3P3SYS pin or the VBAT_RTC pin, depending on the V3OK internal bit. The RTC consists of a counter chain and output registers. The counter chain consists of registers for seconds, minutes, hours, day of week, day of month, month, and year. The chain registers are supported by a shadow register that facilitates read and write operations.

Table 42 shows the I/O RAM registers for accessing the RTC.

### 2.5.4.2 Accessing the RTC

Two bits, RTC_RD (I/O RAM 0x2890[6]) and RTC_WR (I/O RAM 0x2890[7]), control the behavior of the shadow register.
When $R T C_{-} R D$ is low, the shadow register is updated by the RTC after each two milliseconds. When $R T C \_R D$ is high, this update is halted and the shadow register contents become stationary and are suitable to be read by the MPU. Thus, when the MPU wishes to read the RTC, it freezes the shadow register by setting the $R T C_{-} R D$ bit, reads the shadow register, and then lowers the $R T C_{-} R D$ bit to let updates to the shadow register resume. Since the RTC clock is only 500 Hz , there may be a delay of approximately 2 ms from when the $R T C_{-} R D$ bit is lowered until the shadow register receives its first update. Reads to $R T C_{-} R D$ continues to return a one until the first shadow update occurs.

When $R T C \_W R$ is high, the update of the shadow register is also inhibited. During this time, the MPU may overwrite the contents of the shadow register. When $R T C \_W R$ is lowered, the shadow register is written into the RTC counter on the next 500 Hz RTC clock. A 'change' bit is included for each word in the shadow register to ensure that only programmed words are updated when the MPU writes a zero to $R T C \_W R$. Reads of $R T C_{-} W R$ returns one until the counter has actually been updated by the register.
The sub-second register of the RTC, RTC_SBSC (I/O RAM 0x2892), can be read by the MPU after the one second interrupt and before reaching the next one second boundary. RTC_SBSC contains the count since the last full second, in $1 / 128$ second nominal clock periods, until the next one-second boundary. When the RST_SUBSEC bit is written, the SUBSEC counter is restarted, counting from 0 to 127. Reading and resetting the sub-second counter can be used as part of an algorithm to accurately set the RTC.

The RTC is capable of processing leap years. Each counter has its own output register. The RTC chain registers are not be affected by the reset pin, watchdog timer resets, or by transitions between the battery modes and mission mode.

Table 42: RTC Control Registers

| Name | Location | Rst | Wk | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| RTCA_ADJ[6:0] | 2504[6:0] | 40 | -- | R/W | Register for analog RTC frequency adjustment. |
| RTC_P[16:14] <br> RTC_P[13:6] <br> RTC P [5:0] | 289B[2:0] 289C[7:0] 289D[7:2 | $0$ | $0$ | R/W | Registers for digital RTC adjustment. <br> $0 \times 0$ FFBF $\leq R T C \_P \leq 0 \times 10040$ |
| RTC_Q[1:0] | 289D[1:0] | 0 | 0 | R/W | Register for digital RTC adjustment. |
| RTC_RD | 2890[6] | 0 | 0 | R/W | Freezes the RTC shadow register so it is suitable for MPU reads. When $R T C \quad R D$ is read, it returns the status of the shadow register: $0=$ up to date, $1=$ frozen. <br> Writing 0 to RTC_RD bit to enable shadow register update, and writing 1 to RTC_RD to disable update |
| RTC_WR | 2890[7] | 0 | 0 | R/W | Freezes the RTC shadow register so it is suitable for MPU write operations. When RTC WR is cleared, the contents of the shadow register are written to the RTC counter on the next RTC clock ( $\sim 1 \mathrm{kHz}$ ). When $R T C_{-} W R$ is read, it returns 1 as long as $R T C_{-} W R$ is set, and continues to return one until the RTC counter is updated. <br> Writing 0 to RTC_WR bit to enable copying the shadow register contents to RTC counter, and writing 1 to RTC_WR to disable copying |
| RTC_FAIL | 2890[4] | 0 | 0 | R/W | Indicates that a count error has occurred in the RTC and that the time is not trustworthy. This bit can be cleared by writing a 0 . |
| RTC_SBSC[7:0] | 2892[7:0] |  |  | R | Time remaining since the last 1 second boundary. $L S B=1 / 128$ second. |

### 2.5.4.3 RTC Rate Control

The 71M6543 has two rate adjustment mechanisms:

- The first rate adjustment mechanism is an analog rate adjustment, using the I/O RAM register $R T C A \_A D J[6: 0]$, that trims the crystal load capacitance.
- The second rate adjustment mechanism is a digital rate adjust that affects the way the clock frequency is processed in the RTC.

Setting $R T C A \_A D J[6: 0]$ to 00 minimizes the load capacitance, maximizing the oscillator frequency. Setting $R T C A \_A D J[6: 0]$ to $0 x 7 F$ maximizes the load capacitance, minimizing the oscillator frequency. The adjustable capacitance is approximately:

$$
C_{A D J}=\frac{R T C A_{-} A D J}{128} \cdot 16.5 p F
$$

The precise amount of adjustment depends on the crystal properties, the PCB layout and the value of the external crystal capacitors (see CXS and CXS in Table 87). The adjustment may occur at any time, and the resulting clock frequency should be measured over a one-second interval.

The second rate adjustment is digital, and can be used to adjust the clock rate up to $\pm 988 \mathrm{ppm}$, with a resolution of 3.8 ppm . The rate adjustment is implemented starting at the next second-boundary following the adjustment. Since the LSB (define first) results in an adjustment every four seconds, the frequency should be measured over an interval that is a multiple of four seconds.
The clock rate is adjusted by writing the appropriate values to RTC_P[16:0] (I/O RAM 0x289B[2:0], 0x289C, 0x289D[7:2]) and RTC_Q[1:0] (I/O RAM 0x289D[1:0]). Updates to RTC rate adjust registers, RTC_P and $R T C \_Q$, are done through the shadow register described above. The new values are loaded into the counters when RTC_WR (I/O RAM 0x2890[7]) is lowered.
The default frequency is 32,768 RTCLK cycles per second. To shift the clock frequency by $\Delta \mathrm{ppm}$, $R T C_{-} P$ and $R T C_{-} Q$ are calculated using the following equation:

$$
4 \cdot \mathrm{RTC} \text { - }+ \text { RTC_ } \mathrm{Q}=\text { floor }\left(\frac{32768 \cdot 8}{1+\Delta \cdot 10^{-6}}+0.5\right)
$$

Conversely, the amount of ppm shift for a given value of $4 R T C_{-} P+R T C \_Q$ is:

$$
\Delta(p p m)=\left(\frac{32768 \cdot 8}{4 \cdot R T C_{P}+R T C_{Q}}-1\right) \cdot 10^{6}
$$

For example, for a shift of $-988 \mathrm{ppm}, 4 \cdot R T C_{-} P+R T C_{-} Q=262403=0 \times 40103$. RTC_P[16:0] $=0 \times 10040$, (I/O RAM 0x289B[2:0], 0x289C, 0x289D[7:2]) and RTC_Q[1:0] = 0x03 (I/O RAM 0x289D[1:0]. The default values of RTC_P[16:0] and RTC_Q[1:0], corresponding to zero adjustment, are $0 \times 10000$ and $0 \times 0$, respectively.

Two settings for the TMUX2OUT test pin, PULSE_1S and PULSE_4S, are available for measuring and calibrating the RTC clock frequency. These are waveforms of approximately $25 \%$ duty cycle with 1 s or 4 s period.

$\checkmark$
Default values for $R T C A \_A D J[6: 0], R T C_{-} P[16: 0]$ and $R T C \_Q[1: 0]$ should be nominal values, at the center of the adjustment range. Un-calibrated extreme values (zero, for example) can cause incorrect operation.

If the crystal temperature coefficient is known, the MPU can integrate temperature and correct the RTC time as necessary. Alternatively, the characteristics can be loaded into an NV RAM and the OSC_COMP (I/O RAM 0x28A0[5]) bit may be set. In this case, the oscillator is adjusted automatically, even in SLP mode. See 2.5.4.4 RTC Temperature Compensation for details.

### 2.5.4.4 RTC Temperature Compensation

The 71M6543 can be configured to regularly measure die temperature, including in SLP and LCD modes and while the MPU is halted. If enabled by OSC_COMP, this temperature information is automatically used to correct for the temperature variation of the crystal. A table lookup method is used.

Table 43 shows I/O RAM registers involved in automatic RTC temperature compensation.
Table 43: I/O RAM Registers for RTC Temperature Compensation

| Name | Location | Rst | Wk | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| OSC_COMP | 28A0[5] | 0 | 0 | R/W | Enables the automatic update of $R T C_{-} P[16: 0]$ and $R T C \_Q[1: 0]$ every time the temperature is measured. |
| $\begin{aligned} & \text { STEMP[10:3] } \\ & \text { STEMP[2:0] } \end{aligned}$ | $\begin{aligned} & 2881[7: 0] \\ & 2882[7: 5] \\ & \hline \end{aligned}$ | - | - | R | The result of the temperature measurement (10-bits of magnitude data plus a sign bit). |
| LKPADDR[6:0] | 2887[6:0] | 0 | 0 | R/W | The address for reading and writing the RTC lookup RAM. |
| LKPAUTOI | 2887[7] | 0 | 0 | R/W | Auto-increment flag. When set, LKPADDR[6:0] auto increments every time $L K P_{-} R D$ or $L K P_{-} W R$ is pulsed. The incremented address can be read at LKPADDR[6:0]. |
| LKPDAT[7:0] | 2888[7:0] | 0 | 0 | R/W | The data for reading and writing the RTC lookup RAM. |
| $\begin{aligned} & L K P_{-} R D \\ & L K P_{-} W R \end{aligned}$ | $\begin{aligned} & 2889[1] \\ & 2889[0] \end{aligned}$ | 0 |  | R/W R/W | Strobe bits for the RTC lookup RAM read and write. When set, the LKPADDR[6:0] and LKPDAT registers are used in a read or write operation. When a strobe is set, it stays set until the operation completes, at which time the strobe is cleared and LKPADDR[6:0] is incremented if $L K P A U T O I$ is set. |

Referring to Figure 13 the table lookup method uses the 10-bits plus sign-bit value in STEMP[10:0] right-shifted by two bits to obtain an 8 -bit plus sign value (i.e., NV RAM Address $=$ STEMP[10:0]/4). A limiter ensures that the resulting look-up address is in the 6 -bit plus sign range of -64 to +63 (decimal). The 8 -bit NV RAM content pointed to by the address is added as a 2's complement value to $0 \times 40000$, the nominal value of $4^{*} R T C_{-} P[16: 0]+R T C \_Q[1: 0]$.

Refer to 2.5.4.3 RTC Rate Control for information on the rate adjustments performed by registers RTC_P[16:0] and RTC_Q[1:0]. The 8-bit values loaded in to NV RAM must be scaled correctly to produce rate adjustments that are consistent with the equations given in 2.5.4.3 RTC Rate Control for RTC_P [16:0] and $R T C \_Q[1: 0]$. Note that the sum of the looked-up 8 -bit 2's complement value and $0 \times 40000$ form a 19bit value, which is equal to $4^{*} R T C_{-} P[16: 0]+R T C \_Q[1: 0]$, as shown in Figure 13. The output of the Temperature Compensation is automatically loaded into the $R T C_{-} P[16: 0]$ and $R T C \_Q[1: 0]$ locations after each look-up and summation operation.


Figure 13: Automatic Temperature Compensation
The 128 NV RAM locations are organized in 2's complement format. As mentioned above, the STEMP [10:0] digital temperature values are scaled such that the corresponding NV RAM addresses are equal to STEMP[10:0]/4 (limited in the range of -64 to +63). See 2.5.5 71M6543 Temperature Sensor on page 53 for the equations to calculate temperature in degrees ${ }^{\circ} \mathrm{C}$ from the STEMP[10:0] reading.

For proper operation, the MPU has to load the lookup table with values that reflect the crystal properties with respect to temperature, which is typically done once during initialization. Since the lookup table is not directly addressable, the MPU uses the following procedure to load the NV RAM table:

1. Set the LKPAUTOI bit (I/O RAM 0x2887[7]) to enable address auto-increment.
2. Write zero into the I/O RAM register LKPADDR[6:0] (I/O RAM 0x2887[6:0]).
3. Write the 8-bit datum into I/O RAM register LKPDAT (I/O RAM 0x2888).
4. Set the $L K P$ _WR bit (I/O RAM Ox2889[0]) to write the 8-bit datum into NV_RAM
5. Wait for $L K P_{-} W R$ to clear ( $L K P_{-} W R$ auto-clears when the data has been copied to NV RAM).
6. Repeat steps 3 through 5 until all data has been written to NV RAM.

The NV RAM table can also be read by writing a 1 into the $L K P$ _RD bit (I/O RAM 0x2889[1]). The process of reading from and writing to the NV RAM is accelerated by setting the LKPAUTOI bit (I/O RAM 0x2887[7]). When LKPAUTOI is set, LKPADDR[6:0] (I/O RAM 0x2887[6:0]) auto-increments every time LKP_RD or $L K P P_{-} W R$ is pulsed. It is also possible to perform random access of the NV RAM by writing a 0 to the LKPAUTOI bit and loading the desired address into LKPADDR[6:0].

If the oscillator temperature compensation feature is not being used, it is possible to use the NV RAM storage area as ordinary battery-backed NV storage space using the procedure described above to read and write NV RAM data. In this case, the OSC_COMP bit (I/O RAM 0x28A0[5]) is reset to disable the automatic oscillator temperature compensation feature.

### 2.5.4.5 RTC Interrupts

The RTC generates interrupts each second and each minute. These interrupts are called RTC_1SEC and RTC_1MIN. In addition, the RTC functions as an alarm clock by generating an interrupt when the minutes and hours registers both equal their respective target counts as defined in Table 44. The alarm clock interrupt is called RTC_T. All three interrupts appear in the MPU's external interrupt 6. See Table 32 in the interrupt section for the enable bits and flags for these interrupts.
The minute and hour target registers are listed in Table 44.
Table 44: I/O RAM Registers for RTC Interrupts

| Name | Location | Rst | Wk | Dir | Description |
| :--- | :---: | :---: | :---: | :---: | :--- |
| RTC_TMIN[5:0] | 289E[5:0] | 0 | 0 | R/W | The target minutes register. See below. |
| RTC_THR[4:0] | 289F[4:0] | 0 | 0 | R/W | The target hours register. The $R T C \_T$ interrupt occurs <br> when $R T C_{-} M I N[5: 0] ~ b e c o m e s ~ e q u a l ~ t o ~$ <br> RTC_TMIN[5:0] <br> and $R T C_{-} H R[4: 0] ~ b e c o m e s ~ e q u a l ~ t o ~$ <br> and_THR[4:0]. |

### 2.5.5 71M6543 Temperature Sensor

The 71M6543 includes an on-chip temperature sensor for determining the temperature of its bandgap reference. The primary use of the temperature data is to determine the magnitude of compensation required to offset the thermal drift in the system for the compensation of current, voltage and energy measurement and the RTC. See 4.5 Metrology Temperature Compensation on page 88. Also see 2.5.4.4 RTC Temperature Compensation on page 52.

Unlike earlier generation Maxim SoCs, the 71M6543 does not use the ADC to read the temperature sensor. Instead, it uses a technique that is operational in SLP and LCD mode, as well as BRN and MSN modes. This means that the temperature sensor can be used to compensate for the frequency variation of the crystal, even in SLP mode while the MPU is halted. See 2.5.4.4 RTC Temperature Compensation on page 52.
In MSN and BRN modes, the temperature sensor is awakened on command from the MPU by setting the TEMP_START (I/O RAM 0x28B4[6]) control bit. In SLP and LCD modes, it is awakened at a regular rate set by TEMP_PER[2:0] (I/O RAM 0x28A0[2:0]).

The result of the temperature measurement is read from the two I/O RAM locations STEMP[10:3] (I/O RAM 0x2881) and STEMP[2:0] (I/O RAM 0x2882[7:5]). Note that both of these I/O RAM locations must be
read and properly combined to form the STEMP[10:0] 11-bit value (see STEMP in Table 45). The resulting 11-bit value is in 2's complement form and ranges from -1024 to +1023 (decimal).
The equations below are used to calculate the sensed temperature. The first equation applies when the 71M6543F and 71M6543G are in MSN mode and TEMP_PWR $=1$. The second equation applies when the 71 M 6543 F and 71 M 6543 G are in BRN mode, and in this case, the $T E M P \_P W R$ and $T E M P \_B S E L$ bits must both be set to the same value, so that the battery that supplies the temperature sensor is also the battery that is measured and reported in BSENSE. Thus, the second equation requires reading STEMP and BSENSE. In the second equation, BSENSE (the sensed battery voltage) is used to obtain a more accurate temperature reading when the IC is in BRN mode. The coefficients provided in the various STEMP equations below are typical.
For the 71M6543F and 71M6543G in MSN Mode (with $T E M P_{-} P W R=1$ ):

$$
\operatorname{Temp}\left({ }^{\circ} \mathrm{C}\right)=0.325 \cdot S T E M P+22
$$

For the 71M6543F and 71M6543G in BRN Mode, (with $T E M P P_{-} P W R=T E M P{ }_{-} B S E L$ ):

$$
\operatorname{Temp}\left({ }^{\circ} C\right)=0.325 \cdot S T E M P+0.00218 \cdot B S E N S E^{2}-0.609 \cdot B S E N S E+64.4
$$

Table 45 shows the I/O RAM registers used for temperature and battery measurement.

If $T E M P_{-} P W R$ selects $V B A T_{-} R T C$ when the battery is nearly discharged, the temperature measurement may not finish. In this case, firmware may complete the measurement by selecting V3P3D (TEMP_PWR = 1).

Table 45: I/O RAM Registers for Temperature and Battery Measurement

| Name | Location | Rst | Wk | Dir | Description |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| TBYTE_BUSY | 28A0[3] | 0 | 0 | R | Indicates that hardware is still writing the 0x28A0 byte. Additional writes to this byte are locked out while it is one. Write duration could be as long as 6 ms . |  |
| TEMP_PER[2:0] | 28A0[2:0] | 0 | - | R/W | Sets the period between temperature measurements. Automatic measurements can be enabled in any mode (MSN, BRN, LCD, or SLP). |  |
|  |  |  |  |  | TEMP_PER | Time |
|  |  |  |  |  | 0 | Manual updates (see TEMP_START) |
|  |  |  |  |  | 1-6 | 2 ^ (3+TEMP_PER) (seconds) |
|  |  |  |  |  | 7 | Continuous |
| TEMP_BAT | 28A0[4] | 0 | - | R/W | Causes VBAT to be measured whenever a temperature measurement is performed. |  |
| TEMP_START | 28B4[6] | 0 | - | R/W | TEMP_PER[2:0] must be zero in order for TEMP_START to function. If $T E M P$ _PER[2:0] $=0$, then setting TEMP_START starts a temperature measurement. Ignored in SLP and LCD modes. Hardware clears TEMP_START when the temperature measurement is complete. |  |
| TEMP_PWR | 28A0[6] | 0 | - | R/W | Selects the power source for the temperature sensor: $1=$ V3P3D, $0=$ VBAT_RTC. This bit is ignored in SLP and LCD modes, where the temperature sensor is always powered by VBAT_RTC. |  |
| TEMP_BSEL | 28A0[7] | 0 | - | R/W | Selects which battery is monitored by the temperature sensor: $1=$ VBAT, $0=$ VBAT_RTC |  |
| TEMP_TEST[1:0] | 2500[1:0] | 0 | - | R/W | Test bits for the temperature monitor VCO. TEMP_TEST must be 00 in regular operation. Any other value causes the VCO to run continuously with the control voltage described below. |  |
|  |  |  |  |  | TEMP_TEST | Function |
|  |  |  |  |  | 00 | Normal operation |
|  |  |  |  |  | 01 | Reserved for factory test |
|  |  |  |  |  | 1X | Reserved for factory test |
| $\begin{array}{\|l} \hline \text { STEMP[10:3] } \\ \text { STEMP[2:0] } \end{array}$ | $\begin{aligned} & \hline 2881[7: 0] \\ & 2882[7: 5] \end{aligned}$ |  |  | $\begin{aligned} & \hline R \\ & R \end{aligned}$ | The result of the temperature measurement. The STEMP[10:0] value may be obtained in C with a single 16 -bit read and divide by 32 operation as follows: <br> volatile int16_t xdata STEMP _at_0x2881; $\mathrm{fa}=(\mathrm{float})(\mathrm{ST} E M P / 32)$; |  |
| BSENSE[7:0] | 2885[7:0] | - | - | R | The result of the battery measurement. |  |
| BCURR | 2704[3] | 0 | 0 | R/W | Connects a $100 \mu \mathrm{~A}$ load to the battery selected by TEMP BSEL. |  |

### 2.5.6 71M6xx3 Temperature Sensor

The 71M6xx3 includes an on-chip temperature sensor for determining the temperature of its bandgap reference. The primary use of the temperature data is to determine the magnitude of compensation required to offset the thermal drift in the system for the compensation of the current measurement performed by the71M6xx3. See the 71M6xxx Data Sheet for the equation to calculate temperature from the 71M6xx3 STEMP[10:0] reading. Also, see 4.5 Metrology Temperature Compensation on page 88.

See 2.2.8.3 Control of the 71M6xx3 Isolated Sensor on page 22 for information on how to read the STEMP[10:0] information from the 71M6xx3.

### 2.5.7 71M6543 Battery Monitor

The 71M6543 temperature measurement circuit can also monitor the batteries at the VBAT and VBAT_RTC pins. The battery to be tested (i.e., VBAT or VBAT_RTC pin) is selected by TEMP_BSEL (I/O RAM 0x28A0[7]).

When TEMP_BAT (I/O RAM 0x28A0[4]) is set, a battery measurement is performed as part of each temperature measurement. The value of the battery reading is stored in register BSENSE[7:0] (I/O RAM 0x2885). The following equations are used to calculate the voltage measured on the VBAT pin (or VBAT_RTC pin) from the BSENSE[7:0] and STEMP[10:0] values. The result of the equation below is in volts. A slightly different equation is used for MSN mode and BRN mode, as follows.
In MSN mode, TEMP_PWR = 1 use:

$$
V B A T(\text { orVBAT_RTC })=3.3 V+(B S E N S E-142) \cdot 0.0246 V+S T E M P \cdot 0.000297 V
$$

In BRN mode, TEMP_PWR = TEMP_BSEL use:

$$
V B A T(\text { orVBAT_RTC })=3.291 V+(B S E N S E-142) \cdot 0.0255 V+S T E M P \cdot 0.000328 V
$$

In MSN mode, a $100 \mu \mathrm{~A}$ de-passivation load can be applied to the selected battery (i.e., selected by the $T E M P \_B S E L$ bit) by setting the $B C U R R$ (I/O RAM 0x2704[3]) bit. Battery impedance can be measured by taking a battery measurement with and without BCURR. Regardless of the BCURR bit setting, the battery load is never applied in BRN, LCD, and SLP modes.

### 2.5.8 71M6xx3 VCC Monitor

The 71M6xx3 monitors its VCC pin voltage. The voltage of the VCC pin can be obtained by the 71 M 6543 by issuing a read command to the 71M6xx3. The 71 M 6543 must request both the VSENSE[7:0] and STEMP [10:0] values from the 71M6xx3. See the 71M6xxx Data Sheet for the equation to calculate the 71M6xx3 VCC pin voltage from the VSENSE[7:0] and STEMP[10:0] values read from the 71M6xx3.
See 2.2.8.3 Control of the 71M6xx3 Isolated Sensor on page 22 for information on how to read VSENSE[7:0] and STEMP[10:0] from the 71M6xx3 remote sensors.

### 2.5.9 UART and Optical Interface

The 71M6543 provides two asynchronous interfaces, UART0 and UART1. Both can be used to connect to AMR modules, user interfaces, etc., and also support a mechanism for programming the on-chip flash memory.
Referring to Figure 14, UART1 includes an interface to implement an IR/optical port. The pin OPT_TX is designed to directly drive an external LED for transmitting data on an optical link. The pin OPT_RX has the same threshold as the RX pin, but can also be used to sense the input from an external photo detector used as the receiver for the optical link. OPT_TX and OPT_RX are connected to a dedicated UART port (UART1).

The OPT_TX and OPT_RX pins can be inverted with configuration bits OPT_TXINV (I/O RAM 0x2456[0]) and $O P T$ _RXINV (I/O RAM Ox2457[1]), respectively. Additionally, the OPT_TX output may be modulated at 38 kHz . Modulation is available in MSN and BRN modes (see Table 61). The OPT_TXMOD bit (I/O RAM $0 \times 2456[1]$ ) enables modulation. The duty cycle is controlled by OPT_FDC[1:0] (I/O $\bar{R} A M 0 \times 2457[5: 4]$ ), which can select $50 \%, 25 \%, 12.5 \%$, and $6.25 \%$ duty cycle. A $6.25 \%$ duty cycle means that OPT_TX is low for $6.25 \%$ of the period.

When not needed for UART1, OPT_TX can alternatively be configured as SEGDIO51. Configuration is via the OPT_TXE[1:0] (I/O RAM 0x2456[3:2]) field and LCD_MAP[51] (I/O RAM 0x2405[0]). The OPT_TXE[1:0] field allows the MPU to select VPULSE, WPULSE, SEGDIO51 or the output of the pulse modulator to be sourced onto the OPT_TX pin. Likewise, the OPT_RX pin can alternately be configured as SEGDIO55, and its control is OPT_ $\bar{R} X D I S$ (I/O RAM Ox2457[2]) and LCD_MAP[55] (I/O RAM 0x2405[4]).


Figure 14: Optical Interface

## Bit Banged Optical UART (Third UART)

As shown in Figure 15, the 71M6543 can also be configured to drive the optical UART with a DIO signal in a bit banged configuration. When control bit $O P T_{-} B B$ (I/O RAM 0x2022[0]) is set, the optical port is driven by DIO5 and the SEGDIO5 pin is driven by UART1_TX. This configuration is typically used when the two dedicated UARTs must be connected to high speed clients and a slower optical UART is permissible.


Figure 15: Optical Interface (UART1)

### 2.5.10 Digital I/O and LCD Segment Drivers

### 2.5.10.1 General Information

The 71M6543 combines most DIO pins with LCD segment drivers. Each SEG/DIO pin can be configured as a DIO pin or as a segment driver pin (SEG).

On reset or power-up, all DIO pins are DIO inputs (except for SEGDIO0-15, see caution note below) until they are configured as desired under MPU control. The pin function can be configured by the I/O RAM
registers $L C D \_M A P n(0 x 2405-0 \times 240 B)$. Setting the bit corresponding to the pin in $L C D \_M A P n$ to 1 configures the pin for LCD, setting $L C D_{-} M A P n$ to 0 configures it for DIO.


After reset or power up, pins SEGDIO0 through SEGDIO15 are initially DIO outputs, but are disabled by PORT_E = 0 (I/O RAM 0x270C[5]) to avoid unwanted pulses during reset. After configuring pins SĒGDIO0 through SEGDIO15 the MPU must enable the pe pins by setting PORT_E.

Once a pin is configured as DIO, it can be configured independently as an input or output. For SEGDIO0 to SEGDIO15, this is done with the SFR registers P0 (SFR 0x80), P1 (SFR 0x90), P2 (SFR 0xA0) and P3 (SFR 0xB0), as shown in Table 47.

Example: SEGDIO12 (pin 32 in Table 47) is configured as a DIO output pin with a value of 1 (high) by writing 0 to bit 4 of $L C D$ _MAP[15:8], and writing 1 to both P3[4]and P3[0]. The same pin is configured as an LCD driver by writing 1 to bit 4 of $L C D \_M A P[15: 8]$. The display information is written to bits 0 to 5 of $L C D$ _SEG12.

The PB pin is a dedicated digital input and is not part of the SEGDIO system.


The CE features pulse counting registers and each pulse counter interrupt output is internally routed to the pulse interrupt logic. Thus, no routing of pulse signals to external pins is required in order to generate pulse interrupts. See interrupt source No. 2 in Figure 12.
A 3-bit configuration word, I/O RAM register DIO_Rn (I/O RAM 0x2009[2:0] through 0x200E[6:4]) can be used for pins SEGDIO2 through SEGDIO11 (whēn configured as DIO) and PB to individually assign an internal resource such as an interrupt or a timer control (DIO_RPB[2:0], I/O RAM 0x2450[2:0], configures the PB pin). This way, DIO pins can be tracked even if they are configured as outputs. Table 47 lists the internal resources which can be assigned using $D I O_{-} R 2[2: 0]$ through $D I O_{-} R 11[2: 0]$ and $D I O \_R P B[2: 0]$. If more than one input is connected to the same resource, the resources are combined using a logical OR.

Table 46: Selectable Resources using the DIO_Rn[2:0] Bits

| Value in DIO_Rn[2:0] | Resource Selected for SEGDIOn or PB Pin |
| :--- | :--- |
| 0 | None |
| 1 | Reserved |
| 2 | T0 (counter0 clock) |
| 3 | T1 (counter1 clock) |
| 4 | High priority I/O interrupt (INT0) |
| 5 | Low priority I/O interrupt (INT1) |
| Note: <br> Resources are selectable only on SEGDIO2 through SEGDIO11 and the <br> PB pin. See Table 48. |  |



When driving LEDs, relay coils etc., the DIO pins should sink the current into GNDD (as shown in Figure 16, right), not source it from V3P3D (as shown in Figure 16, left). This is due to the resistance of the internal switch that connects V3P3D to either V3P3SYS or VBAT. See 6.4.6 V3P3D Switch on page 136.

Sourcing current in or out of DIO pins other than those dedicated for wake functions, for example with pullup or pulldown resistors, must be avoided. Violating this rule leads to increased quiescent current in sleep and LCD modes.


Figure 16: Connecting an External Load to DIO Pins

### 2.5.10.2 Combined DIO and SEG Pins

A total of 51 combined DIO/LCD pins are available. These pins can be categorized as follows:
39 combined DIO/LCD segment pins:

- SEGDIO4...SEGDIO25 (22 pins)
- SEGDIO28...SEGDIO35 (8 pins)
- SEGDIO40...SEGDIO45 (6 pins)
- SEGDIO52...SEGDIO54 (3 pins)

12 combined DIO/LCD segment pins shared with other functions:

- SEGDIOO/WPULSE, SEGDIO1/VPULSE (2 pins)
- SEGDIO2/SDCK, SEGDIO3/SDATA (2 pins)
- SEGDIO26/COM5, SEGDIO27/COM4 (2 pins)
- SEGDIO36/SPI_CSZ...SEGDIO39/SPI_CKI (4 pins)
- SEGDIO51/OPT_TX, SEGDIO55/OPT_RX (2 pins)

Additionally, 5 LCD segment (SEG) pins are available. These pins can be categorized as follows:

- 3 SEG pins combined with the ICE interface (SEG48/E_RXTX, SEG49/E_TCLK, SEG50/E_RST)
- 2 SEG pins combined with the test multiplexer outputs (SEG46/TMUX2OUT, SEG47/TMUXOUT)

Thus, a total of 51 DIO pins are available with minimum LCD configuration, and a total of 56 LCD pins are available with minimum DIO configuration.

Table 47: Data/Direction Registers and Internal Resources for SEGDIO0 to SEGDIO15

| SEGDIO | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | 15 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Pin \# | 45 | 44 | 43 | 42 | 41 | 39 | 38 | 37 | 36 | 35 | 34 | 33 | 32 | 31 | 30 | 29 |
| Configuration:$0=\mathrm{DIO}, 1=\mathrm{LCD}$ | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
|  | LCD_MAP[7:0] (I/O RAM 0x240B) |  |  |  |  |  |  |  | LCD_MAP[15:8] (I/O RAM 0x240A) |  |  |  |  |  |  |  |
| SEG Data Register | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 | 13 | 14 | 15 |
|  | LCD_SEG0[5:0] to LCD_SEG15[5:0] (I/O RAM 0x2410[5:0] to Ox241F[5:0] |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| DIO Data Register | 0 | 1 | 2 | 3 | 0 | 1 | 2 | 3 | 0 | 1 | 2 | 3 | 0 | 1 | 2 | 3 |
|  | P0 (SFR80) |  |  |  | P1 (SFR 0x90) |  |  |  | P2 (SFR OxAO) |  |  |  | P3 (SFR OxB0) |  |  |  |
| Direction Register | 4 | 5 | 6 | 7 | 4 | 5 | 6 | 7 | 4 | 5 | 6 | 7 | 4 | 5 | 6 | 7 |
| $0=\text { input, } 1=\text { output }$ | PO (SFR 0x80) |  |  |  | P1 (SFR 0x90) |  |  |  | P2 (SFR OxAO) |  |  |  | P3 (SFR 0xB0) |  |  |  |
| Internal Resources Configurable (see Table 46) | - | - | Y | Y | Y | Y | Y | Y | Y | Y | Y | Y | - | - | - | - |

The configuration for pins SEGDIO16 to SEGDIO31 is shown in Table 48, and the configuration for pins SEGDIO32 to SEGDIO45 is shown in Table 49. The configuration for pins SEGDIO51 to SEGDIO55 is shown in Table 50.

Table 48: Data/Direction Registers for SEGDIO16 to SEGDIO31

| SEGDIO | 16 | 17 | 18 | 19 | 20 | 21 | 22 | 23 | 24 | 25 | 26 | 27 | 28 | 29 | 30 | 31 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Pin \# | 28 | 27 | 25 | 24 | 23 | 22 | 21 | 20 | 19 | 18 | 17 | 16 | 11 | 10 | 9 | 8 |
| Configuration:$0 \text { = DIO, } 1 \text { = LCD }$ | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 |
|  | LCD_MAP[23:16] (I/O RAM 0x2409) |  |  |  |  |  |  |  | LCD_MAP[31:24] (I/O RAM 0x2408) |  |  |  |  |  |  |  |
| SEG Data Register | 16 | 17 | 18 | 19 | 20 | 21 | 22 | 23 | 24 | 25 | 26 | 27 | 28 | 29 | 30 | 31 |
|  | LCD_SEGDIO16[5:0] to LCD_SEGDIO31[5:0] (I/O RAM 0x2420[5:0] to 0x242F[5:0]) |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| DIO Data Register | 16 | 17 | 18 | 19 | 20 | 21 | 22 | 23 | 24 | 25 | 26 | 27 | 28 | 29 | 30 | 31 |
|  | LCD_SEGDIO16[0] to LCD_SEGDIO31[0] (I/O RAM 0x2420[0] to 0x242F[0]) |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| Direction Register: 0 = input, 1 = output | 16 | 17 | 18 | 19 | 20 | 21 | 22 | 23 | 24 | 25 | 26 | 27 | 28 | 29 | 30 | 31 |
|  | LCD_SEGDIO16[1] to LCD_SEGDIO31[1] <br> (I/O RAM 0x2420[1] to 0x242F[1]) |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |

Table 49: Data/Direction Registers for SEGDIO32 to SEGDIO45

| SEGDIO | 32 | 33 | 34 | 35 | 36 | 37 | 38 | 39 | 40 | 41 | 42 | 43 | 44 | 45 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Pin \# | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 100 | 99 | 98 | 97 | 96 | 95 | 94 |
| Configuration:$0 \text { = DIO, } 1 \text { = LCD }$ | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 0 | 1 | 2 | 3 | 4 | 5 |
|  | $\begin{aligned} & \text { LCD_MAP[39:32] } \\ & (I / O-R A M ~ 0 \times 2407) \end{aligned}$ |  |  |  |  |  |  |  | $\begin{gathered} \text { LCD_MAP[45:40] } \\ \text { (I/O RAM } 0 \times 2406[5: 0]) \end{gathered}$ |  |  |  |  |  |
| SEG Data Register | 32 | 33 | 34 | 35 | 36 | 37 | 38 | 39 | 40 | 41 | 42 | 43 | 44 | 45 |
|  | LCD_SEGDIO32[5:0] to LCD_SEGDIO45[5:0] (I/O RAM 0x2430[5:0] to 0x243D [5:0]) |  |  |  |  |  |  |  |  |  |  |  |  |  |
| DIO Data Register | 32 | 33 | 34 | 35 | 36 | 37 | 38 | 39 | 40 | 41 | 42 | 43 | 44 | 45 |
|  | LCD_SEGDIO32[0] to LCD_SEGDIO45/0] (I/O RAM 0x2430[0] to 0x243D[0]) |  |  |  |  |  |  |  |  |  |  |  |  |  |
| Direction Register: 0 = input, 1 = output | 32 | 33 | 34 | 35 | 36 | 37 | 38 | 39 | 40 | 41 | 42 | 43 | 44 | 45 |
|  | LCD_SEGDIO32[1] to LCD_SEGDIO45[1] <br> (I/O RAM 0x2430[1] to Ox243D[1]) |  |  |  |  |  |  |  |  |  |  |  |  |  |

Table 50: Data/Direction Registers for SEGDIO51 to SEGDIO55

| SEGDIO | 51 | 52 | 53 | 54 | 55 |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Pin \# | 53 | 52 | 51 | 47 | 46 | - | - | - |
| Configuration:$0=\mathrm{DIO}, 1 \text { = LCD }$ | 3 | 4 | 5 | 6 | 7 | - | - | - |
|  | LCD_MAP[55:48] <br> (I/O RAM 0x2405) |  |  |  |  |  |  |  |
| SEG Data Register | 51 | 52 | 53 | 54 | 55 | - | - | - |
|  | LCD_SEGDIO51[5:0] to LCD_SEGDIO55[5:0] (I/O RAM 0x2443[5:0] to 0x2447[5:0]) |  |  |  |  |  |  |  |
| DIO Data Register | 51 | 52 | 53 | 54 | 55 | - | - | - |
|  | LCD_SEGDIO51[0] to LCD_SEGDIO55/0] (I/O RAM 0x2443[0] to 0x2447[0]) |  |  |  |  |  |  |  |
| Direction Register: 0 = input, 1 = output | 51 | 52 | 53 | 54 | 55 | - | - | - |
|  | LCD_SEGDIO51[1] to LCD_SEGDIO55[I] (I/O RAM 0x2443[1] to 0 $x 2447$ [1]) |  |  |  |  |  |  |  |

### 2.5.10.3 LCD Drivers

The LCD drivers are grouped into up to six commons (COM0 - COM5) and up to 56 segment drivers. The LCD interface is flexible and can drive 7 -segment digits, 14 -segment digits or enunciator symbols.
A voltage doubler and a contrast DAC generate VLCD from either VBAT or V3P3SYS, depending on the V3P3SYS voltage. The voltage doubler, while capable of driving into a $500 \mathrm{k} \Omega$ load, is able to generate a maximum LCD voltage that is within 1 V of twice the supply voltage. The doubler and DAC operate from a trimmed low-power reference.

The configuration of the VLCD generation is controlled by the I/O RAM field LCD_VMODE[1:0] (I/O RAM $0 \times 2401[7: 6])$. It is decoded into $L C D \_E X T, L D A C \_E$, and $L C D \_B S T E$. Table 51 details the $L C D \_V M O D E[1: 0]$ configurations.

Table 51: LCD_VMODE Configurations

| LCD_VMODE[1:0] | LCD_EXT | LDAC_E | LCD_BSTE | Description |
| :---: | :---: | :---: | :---: | :--- |
| 11 | 1 | 0 | 0 | External VLCD connected to the VLCD pin. |
| 10 | 0 | 1 | 1 | LCD boost is enabled. Maximum VLCD voltage is <br> $2^{*}$ V3P3L-1. <br> VLCD $=\max \left(2^{*}\right.$ V3P3L-1, 2.65(1+LCD_DAC[4:0]/31) |
| 01 | 0 | 1 | 0 | LCD boost is disabled. The maximum VLCD <br> voltage is V3P3L. <br> VLCD $=\max \left(V 3 P 3 L, ~ 2.65\left(1+L C D \_D A C[4: 0] / 31\right)\right.$ |
| 00 | 0 | 0 | 0 | VLCD=V3P3L, the LCD DAC and LCD boost are dis- <br> abled. In LCD mode, this setting causes the lowest <br> battery current. |

## Notes:

1. LCD_EXT, LDAC_E and LCD_BSTE are 71 M 6543 internal signals which are decoded from the $\overline{L C D}$ VMODE[1:0] control field setting (I/O RAM 0x2401[7:6]). Each of these decoded signals, when asserted, has the effect indicated in the description column above, and as summarized below.

LCD_EXT : When set, the VLCD pin expects an external supply voltage
LDAC_E : When set, LCD DAC is enabled
LCD_BSTE : When set, the LCD boost circuit is enabled
2. V3P3L is an internal supply rail that is supplied from either the VBAT pin or the V3P3SYS pin, depending on the V3P3SYS pin voltage. When the V3P3SYS pin drops below 3.0 VDC, the 71 M 6543 switches to BRN mode and V3P3L is sourced from the VBAT pin, otherwise V3P3L is sourced from the V3P3SYS pin while in MSN mode.

When using the VLCD boost circuit, use care when setting the LCD_DAC[4:0] (I/O RAM 0x240D[4:0]) value to ensure that the LCD manufacturer's recommended operating voltage specification is not exceeded.

The voltage doubler is active in all LCD modes including the LCD mode when $L C D \_B S T E=1$. Current dissipation in LCD mode can be reduced if the boost circuit is disabled and the LCD system is operated directly from VBAT.
The LCD DAC uses a low-power reference and, within the constraints of VBAT and the voltage doubler, generates a VLCD voltage of $2.65 \mathrm{VDC}+2.65^{*} L C D \_D A C[4: 0] / 31$. Two fuse bytes increase the accuracy of the LCD_DAC. LCDADJ12 and LCDADJ0 indicate the actual VLCD output voltage when the DAC is programmed to 12 and 0 respectively.

The LCD_BAT (I/O RAM 0x2402[7]) bit causes the LCD system to use the battery voltage in all power modes. This may be useful when an external supply is available for the LCD system. The advantage of connecting the external supply to VBAT, rather than VLCD is that the LCD DAC is still active.

If $L C D \_E X T=1$, the VLCD pin must be driven from an external source. In this case, the LCD DAC has no effect.

The LCD system has the ability to drive up to six segments per SEG driver. If the display is configured with six back planes, the 6-way multiplexing reduces the number of SEG pins required to drive a display and therefore enhances the number of DIO pins available to the application. Refer to the $L C D \_M O D E[2: 0]$ field (I/O RAM 0x2400[6:4]) settings (Table 52) for the different LCD multiplexing choices. If $\overline{5}$-state multiplexing is selected, SEGDIO27 is converted to COM4. If 6-state multiplexing is selected, SEGDIO26 is converted to COM5. These conversions override the SEG/DIO mapping of SEGDIO26 and SEGDIO27. Additionally, independent of $L C D_{-} M O D E[2: 0]$, if $L C D \_A L L C O M=1$ (I/O RAM 0x2400[3]), then SEGDIO26 and SEGDIO27 become COM4 and COM5 if their $L C D \_M A P[]$ bits are set.
The LCD_ON (I/O RAM 0x240C[0]) and LCD_BLANK (I/O RAM 0x240C[1]) bits are an easy way to either blank the LCD display or turn it fully on. Neither bit affects the contents of the LCD data stored in the $L C D S E G_{-} D I O\left[\right.$ ] registers. In comparison, $L C D \_R S T$ (I/O RAM 0x240C[2]) clears all LCD data to zero. $L C D \_R S T$ affects only pins that are configured as LCD.

A small amount of power can be saved by programming the LCD frequency to the lowest value that provides satisfactory LCD visibility over the required temperature range.

Table 52 shows all I/O RAM registers that control the operation of the LCD interface.

Table 52: LCD Configurations

| Name | Location | Rst | Wk | Dir | Description |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LCD_ALLCOM | 2400[3] | 0 | - | R/W | Configures all 6 SEG/COM pins as COM. Has no effect on pins whose $L C D \_M A P$ bit is zero. |  |
| LCD_BAT | 2402[7] | 0 | - | R/W | Connects the LCD power supply to VBAT in all modes. |  |
| $L C D \_E$ | 2400[7] | 0 | - | R/W | Enables the LCD display. When disabled, VLC2, VLC1, and VLC0 are ground as are the COM and SEG outputs if their $L C D_{-} M A P$ bit is 1 . |  |
| $\begin{aligned} & L C D \_O N \\ & L C D_{-} B L A N K \end{aligned}$ | $\begin{aligned} & 240 C[0] \\ & 240 C[1] \end{aligned}$ | $\begin{aligned} & 0 \\ & 0 \end{aligned}$ | - | $\begin{aligned} & \text { R/W } \\ & \text { R/W } \end{aligned}$ | $L C D \_O N=1$ turns on all LCD segments without affecting the LCD data. Similarly, $L C D \_B L A N K=1$ turns off all LCD segments without affecting the LCD data. If both bits are set, all LCD segments are turned on. |  |
| $L C D \_R S T$ | 240C[2] | 0 | - | R/W | Clear all bits of LCD data. These bits affect SEGDIO pins that are configured as LCD drivers. |  |
| $L C D \_D A C[4: 0]$ | 240D[4:0] | 0 | - | R/W | This register controls the LCD contrast DAC which adjusts the VLCD voltage and has an output range of 2.65 VDC to 5.3 VDC. The VLCD voltage is $\text { VLCD }=2.65+2.65 \text { * LCD_DAC[4:0]/31 }$ <br> Thus, the LSB of the DAC is 85.5 mV . The maximum DAC output voltage is limited by V3P3SYS, VBAT, and whether $L C D$ BSTE is set. |  |
| LCD_CLK[1:0] | 2400[1:0] | 0 | - | R/W | Sets the LCD clock frequency (1/T). See definition of T in Figure 17. Note: $\mathrm{fw}=32768 \mathrm{~Hz}$$00-\mathrm{fw} / 2^{\wedge} 9,01-\mathrm{fw} / 2^{\wedge} 8,10-\mathrm{fw} / 2^{\wedge} 7,11-\mathrm{fw} / 2^{\wedge} 6$ |  |
| $L C D \_M O D E[2: 0]$ | 2400[6:4] | 0 | - | R/W | The LCD bias and multiplex mode. |  |
|  |  |  |  |  | LCD MODE | Output |
|  |  |  |  |  | 000 | 4 states, 1/3 bias |
|  |  |  |  |  | 001 | 3 states, 1/3 bias |
|  |  |  |  |  | 010 | 2 states, $1 / 2$ bias |
|  |  |  |  |  | 011 | 3 states, 1/2 bias |
|  |  |  |  |  | 100 | Static display |
|  |  |  |  |  | 101 | 5 states, 1/3 bias |
|  |  |  |  |  | 110 | 6 states, 1/3 bias |
| LCD_VMODE[1:0] | 2401[7:6] | 00 | 00 | R/W | This register specifies how VLCD is generated. |  |
|  |  |  |  |  | LCD_VMODE | Description |
|  |  |  |  |  | 11 | External VLCD |
|  |  |  |  |  | 10 | LCD boost and LCD DAC enabled |
|  |  |  |  |  | 01 | LCD DAC enabled |
|  |  |  |  |  | 00 | No boost and no DAC. VLCD $=$ VBAT or V3P3SYS |

The LCD can be driven in static, $1 / 2$ bias, and $1 / 3$ bias modes. Figure 17 defines the COM waveforms. Note that COM pins that are not required in a specific mode maintain a segment off state rather than GND, VCC, or high impedance.

The segment drivers SEGDIO22 and SEGDIO23 can be configured to blink at either 0.5 Hz or 1 Hz . The blink rate is controlled by $L C D_{-} Y$ (I/O RAM $0 \times 2400[2]$ ). There can be up to six pixels/segments connected to each of these driver pins. The I/O RAM fields LCD_BLKMAP22[5:0] (I/O RAM 0x2402[5:0]) and $L C D \_B L K M A P 23[5: 0]$ (I/O RAM 0x2401[5:0]) identify which pixels, if any, are to blink.
$L C D \_B L K M A P 22[5: 0]$ and $L C D \_B L K M A P 23[5: 0]$ are non-volatile.

The LCD bias may be compensated for temperature using the $L C D \_D A C[4: 0]$ field (I/O RAM 0x240D[4:0]). The bias may be adjusted from 1.4 V below the 3.3 V supply (V3P3SYS in MSN mode and VBAT in BRN and LCD modes). When the $L C D_{-} D A C[4: 0]$ field is set to 000 , the DAC is bypassed and powered down. This setting can be used to reduce current in LCD mode.


Figure 17: LCD Waveforms
SEG46 through SEG50 cannot be configured as DIO pins. Display data for these pins are written to I/O RAM registers $L C D \_S E G 46[5: 0]$ through $L C D \_S E G 50[5: 0]$ (see Table 53).

Table 53: LCD Data Registers for SEGDIO46 to SEGDIO55

| SEGDIO | 46 | 47 | 48 | 49 | 50 | 51 | 52 | 53 | 54 | 55 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Pin \# | 93 | 92 | 58 | 57 | 56 | 53 | 52 | 51 | 47 | 46 |
| Configuration: | Always LCD pins |  |  |  |  | See 2.5.10.2 |  |  |  |  |
| SEG Data Register |  |  |  |  |  |  |  |  |  |  |

The $L C D$ _MAP[47:46] (I/O RAM $0 x 2406[7: 6]$ ) bits are used to determine whether SEG46 and SEG47 are SEG pins or their alternate function (see pins 93 and 92 in Figure 42). If the $L C D \_M A P[47: 46]$ bits are 1, then the pins are configured as SEG pins. If the $L C D_{-} M A P[47: 46]$ bits are 0 , then the pins are configured as their alternate functions (TMUX2OUT and TMUXOUT, respectively).

For example, if $L C D_{-} M A P[46]=1$, then pin 93 (TMUX2OUT/SEG46) is configured as SEG46, and if $L C D \_M A P[46]=0$, then pin 93 is configured as TMUX2OUT.

The SEG pins with alternate ICE interface function (see pins 56-58 in Figure 42) are forced to their alternate ICE interface function (i.e., E_RXTX, E_TCLK and E_RST) if the ICE_E pin (pin 59) is driven high, and in this case, the bits $L C D_{-} M A P[50: 48]$ (I/O RAM $0 x 2405[2: 0]$ ) bits are "don't care" bits. If the ICE_E pin is driven low, then $L C D \_M A P[50: 48]$ bits must written with 1 in order to configure these pins as SEG pins. If the ICE_E pin is low and $L C D_{-} M A P[50: 48]$ are written with 0 , then these pins are tied to an internal pullup.

### 2.5.11 EEPROM Interface

The 71M6543 provides hardware support for either a two-pin or a three-wire ( $\mu$-wire) type of EEPROM interface. The interfaces use the EECTRL (SFR 0x9F) and EEDATA (SFR 0x9E) registers for communication.

### 2.5.11.1 Two-pin EEPROM Interface

The dedicated 2-pin serial interface communicates with external EEPROM devices. The interface is multiplexed onto the SEGDIO2 (SDCK) and SEGDIO3 (SDATA) pins and is selected by setting $D I O \_E E X[1: 0]=01$ (I/O RAM 0x2456[7:6]). The MPU communicates with the interface through the SFR registers EEDATA and EECTRL. If the MPU wishes to write a byte of data to the EEPROM, it places the data in EEDATA and then writes the Transmit code to EECTRL. This initiates the transmit operation which is finished when the BUSY bit falls. INT5 is also asserted when $B U S Y$ falls. The MPU can then check the $R X_{-} A C K$ bit to see if the EEPROM acknowledged the transmission.

A byte is read by writing the Receive command to EECTRL and waiting for the BUSY bit to fall. Upon completion, the received data is in EEDATA. The serial transmit and receive clock is 78 kHz during each transmission, and then holds in a high state until the next transmission. The EECTRL bits when the two-pin interface is selected are shown in Table 54.

Table 54: EECTRL Bits for 2-pin Interface

| Status <br> Bit | Name | Read/ <br> Write | Reset <br> State | Polarity | Description |  |
| :---: | :--- | :---: | :---: | :--- | :--- | :--- |
| 7 | $E R R O R$ | R | 0 | Positive | 1 when an illegal command is received. |  |
| 6 | $B U S Y$ | R | 0 | Positive | 1 when serial data bus is busy. |  |
| 5 | $R X_{-} A C K$ | R | 1 | Positive | 1 indicates that the EEPROM sent an ACK bit. |  |
| 4 | $T X_{-} A C K$ | R | 1 | Positive | 1 indicates when an ACK bit has been sent to the <br> EEPROM. |  |
|  |  |  |  |  |  |  |
|  |  |  |  |  |  |  |

The EEPROM interface can also be operated by controlling the DIO2 and DIO3 pins directly. The direction of the DIO line can be changed from input to output and an output value can be written with a single write operation, thus avoiding collisions (see Table 14 Port Registers (SEGDIO0-15)). Therefore, no resistor is required in series SDATA to protect against collisions.

### 2.5.11.2 Three-Wire ( $\mu$-Wire) EEPROM Interface with Single Data Pin

A 500 kHz three-wire interface, using SDATA, SDCK, and a DIO pin for CS is available. The interface is selected by setting $D I O \_E E X[1: 0]=10$. The $E E C T R L$ bits when the three-wire interface is selected are shown in Table 55. When EECTRL is written, up to 8 bits from EEDATA are either written to the EEPROM or read from the EEPROM, depending on the values of the EECTRL bits.

### 2.5.11.3 Three-Wire ( $\mu$-Wire/SPI) EEPROM Interface with Separate Di/DO Pins

If $D I O$ _ $E E X[1: 0]=11$, the 71 M 6543 three-wire interface is the same as above, except DI and DO are separate pins. In this case, SEGDIO3 becomes DO and SEGDIO8 becomes DI. The timing diagrams are the same as for $D I O_{-} E E X[1: 0]=10$ except that all output data appears on DO and all input data is expected on DI. In this mode, DI is ignored while data is being received on DO. This mode is compatible with SPI modes 0,0 and 1,1 where data is shifted out on the falling edge of the clock and is strobed in on the rising edge of the clock.

Table 55: EECTRL Bits for the 3-wire Interface

| Control <br> Bit | Name | Read/ <br> Write | Description |
| :---: | :---: | :---: | :--- |
| 7 | $W F R$ | W | Wait for Ready. If this bit is set, the trailing edge of BUSY is delayed until <br> a rising edge is seen on the data line. This bit can be used during the <br> last byte of a Write command to cause the INT5 interrupt to occur when <br> the EEPROM has finished its internal write sequence. This bit is <br> ignored if HiZ=0. |
| 6 | $B U S Y$ | R | Asserted while the serial data bus is busy. When the BUSY bit falls, an <br> INT5 interrupt occurs. |
| 5 | $H i Z$ | W | Indicates that the SD signal is to be floated to high impedance immediately <br> after the last SDCK rising edge. |
| 4 | $R D$ | W | Indicates that $E E D A T A(S F R$ 0x9E) is to be filled with data from EEPROM. <br> $3: 0$$C N T[3: 0]$ |

The timing diagrams in Figure 18 through Figure 22 describe the 3-wire EEPROM interface behavior. All commands begin when the EECTRL register is written. Transactions start by first raising the DIO pin that is connected to CS. Multiple 8-bit or less commands such as those shown in Figure 18 through Figure 22 are then sent via EECTRL and EEDATA.

When the transaction is finished, CS must be lowered. At the end of a Read transaction, the EEPROM drives SDATA, but transitions to HiZ (high impedance) when CS falls. The firmware should then immediately issue a write command with $\mathrm{CNT}=0$ and $\mathrm{HiZ}=0$ to take control of SDATA and force it to a low-Z state.


Figure 18: 3-wire Interface. Write Command, HiZ=0.


Figure 19: 3-wire Interface. Write Command, HiZ=1


Figure 20: 3-wire Interface. Read Command.
$B U S Y$ (bit) $\qquad$

$B U S Y$ (bit) $\qquad$

Figure 21: 3-Wire Interface. Write Command when CNT=0


Figure 22: 3-wire Interface. Write Command when HiZ=1 and WFR=1.

### 2.5.12 SPI Slave Port

The slave SPI port communicates directly with the MPU data bus and is able to read and write Data RAM and Configuration RAM (I/O RAM) locations. It is also able to send commands to the MPU. The interface to the slave port consists of the SPI_CSZ, SPI_CKI, SPI_DI and SPI_DO pins. These pins are multiplexed with the combined DIO/LCD segment driver pins SEGDIO36 to SEGDIO39 (pins 3, 2, 1 and 100).
Additionally, the SPI interface allows flash memory to be read and to be programmed. To facilitate flash programming, cycling power or asserting RESET causes the SPI port pins to default to SPI mode. The SPI port is disabled by clearing the SPI_E bit (I/O RAM 0x270C[4]).

Possible applications for the SPI interface are:

1) An external host reads data from CE locations to obtain metering information. This can be used in applications where the 71 M 6543 function as a smart front-end with preprocessing capability. Since the addresses are in 16-bit format, any type of XRAM data can be accessed: CE, MPU, I/O RAM, but not SFRs or the 80515-internal register bank.
2) A communication link can be established via the SPI interface: By writing into MPU memory locations, the external host can initiate and control processes in the 71 M 6543 MPU . Writing to a CE or MPU location normally generates an interrupt, a function that can be used to signal to the MPU that the byte that had just been written by the external host must be read and processed. Data can also be inserted by the external host without generating an interrupt.
3) An external DSP can access front-end data generated by the ADC. This mode of operation uses the 71 M 6543 as an analog front-end (AFE).
4) Flash programming by the external host (SPI Flash Mode).

## SPI Transactions

A typical SPI transaction is as follows. While SPI_CSZ is high, the port is held in an initialized/reset state. During this state, SPI_DO is held in high impedance state and all transitions on SPI_CLK and SPI_DI are ignored. When SPI_C CSZ falls, the port begins the transaction on the first rising edge of SPI_CLK. As shown in Table 56, a transaction consists of an optional 16 bit address, an 8 bit command, an 8 bit status byte, followed by one or more bytes of data. The transaction ends when SPI_CSZ is raised. Some transactions may consist of a command only.
When SPI_CSZ rises, SPI command bytes that are not of the form $x 0000000$ cause the SPI_CMD (SFR $0 \times F D$ ) register to be updated and then cause an interrupt to be issued to the MPU. The exception is if the transaction was a single byte. In this case, the SPI_CMD byte is always updated and the interrupt issued. SPI_CMD is not cleared when SPI_CSZ is high.

The SPI port supports data transfers up to $10 \mathrm{Mb} / \mathrm{s}$. A serial read or write operation requires at least 8 clocks per byte, guaranteeing SPI access to the RAM is no faster than 1.25 MHz , thus ensuring that SPI access to DRAM is always possible.

Table 56: SPI Transaction Fields

| Field <br> Name | Required | Size <br> (bytes) | Description |
| :---: | :---: | :---: | :--- |
| Address | Yes, except <br> single byte <br> transaction | 2 | 16-bit address. The address field is not required if the transaction <br> is a simple SPI command. |
| Command | Yes | 1 | 8-bit command. This byte can be used as a command to the <br> MPU. In multi-byte transactions, the MSB is the RM bit. Unless <br> the transaction is multi-byte and SPI_CMD is exactly 0x80 or <br> 0x00, the SPI_CMD register is upda_ed and an SPI interrupt is <br> issued. Otherwise, the SPI_CMD register is unchanged and the <br> interrupt is not issued. |
| Status | Yes, if transaction <br> includes DATA | 1 | 8-bit status field, indicating the status of the previous transaction. <br> This byte is also available in the MPU memory map as <br> SPI_STAT (I/O RAM 0x2708). See Table 58 for the contents. |
| Data | Yes, if transaction <br> includes DATA | 1 or <br> more | The read or write data. Address is auto incremented for each <br> new byte. |

The SPI_STAT byte is output on every SPI transaction and indicates the parity of the previous transaction and the error status of the previous transaction. Potential error sources are:

- 71M6543 not ready
- Transaction not ending on a byte boundary.


## SPI Safe Mode

Sometimes it is desirable to prevent the SPI interface from writing to arbitrary RAM locations and thus disturbing MPU and CE operation. This is especially true in AFE applications. For this reason, the SPI SAFE mode was created. In SPI SAFE mode, SPI write operations are disabled except for a 16 byte transfer region at address $0 \times 400$ to $0 x 40 \mathrm{~F}$. If the SPI host needs to write to other addresses, it must use the SPI_CMD register to request the write operation from the MPU. SPI SAFE mode is enabled by the SPI_SAFE bit (I/O RAM 0x270C[3]).

## Single-Byte Transaction

If a transaction is a single byte, the byte is interpreted as SPI_CMD. Regardless of the byte value, single-byte transactions always update the SPI_CMD register and cause an SPI interrupt to be generated.

## Multi-Byte Transaction

As shown in Figure 23, multi-byte operations consist of a 16 bit address field, an 8 bit CMD, a status byte, and a sequence of data bytes. A multi byte transaction is three or more bytes.


Figure 23: SPI Slave Port - Typical Multi-Byte Read and Write operations

Table 57: SPI Command Sequences

| Command Sequence | Description |
| :--- | :--- |
| ADDR 1xxx xxxx STATUS | Read data starting at ADDR. ADDR is auto-incremented until SPI_CSZ <br> is raised. Upon completion, SPI_CMD (SFR 0xFD) is updated to 1xxx xxx <br> and an SPI interrupt is generated. The exception is if the command <br> byte is 1000 0000. In this case, no MPU interrupt is generated and <br> SPI_CMD is not updated. |
| Ayte0 ... ByteN | Write data starting at ADDR. ADDR is auto-incremented until SPI_CSZ is <br> raised. Upon completion, SPI_CMD is updated to 0xxx xxxx and an SPI <br> ADDR 0xxx xxxx STATUS <br> interrupt is generated. The exception is if the command byte is 0000 <br> Byte0 ... ByteN |
| 0000. In this case, no MPU interrupt is generated and SPI_CMD is not <br> updated. |  |

Table 58: SPI Registers

| Name | Location | Rst | Wk | Dir | Description |
| :--- | :---: | :---: | :---: | :---: | :--- |
| $E X \_S P I$ | $2701[7]$ | 0 | 0 | R/W | SPI interrupt enable bit. |
| SPI_CMD | SFR FD[7:0] | - | - | R | SPI command. The 8-bit command from the bus master. |
| SPI_E | $270 C[4]$ | 1 | 1 | R/W | SPI port enable bit. It enables the SPI interface on pins <br> SEGDIO36 - SEGDIO39. |
| IE_SPI | SFR F8[7] | 0 | 0 | R/W | SPI interrupt flag. Set by hardware, cleared by writing a 0. |

\(\left.$$
\begin{array}{|l|c|c|c|c|l|}\hline \text { Name } & \text { Location } & \text { Rst } & \text { Wk } & \text { Dir } & \text { Description } \\
\hline \text { SPI_SAFE } & \text { 270C[3] } & 0 & 0 & \text { R/W } & \begin{array}{l}\text { Limits SPI writes to SPI_CMD and a 16 byte region in } \\
\text { DRAM when set. No other write operations are permitted. }\end{array} \\
\hline \text { SPI_STAT } & \text { 2708[7:0] } & 0 & 0 & \begin{array}{l}\text { SPI_STAT contains the status results from the previous } \\
\text { SPI transaction } \\
\text { Bit 7-71M6543 ready error: the 71M6543 was not } \\
\text { ready to read or write as directed by the previous } \\
\text { command. } \\
\text { Bit 6-Read data parity: This bit is the parity of all bytes } \\
\text { read from the 71M6543 in the previous command. Does } \\
\text { not include the SPI_STAT byte. } \\
\text { Bit 5-Write data parity: This bit is the overall parity of } \\
\text { the bytes written to the 71M6543 in the previous } \\
\text { command. It includes CMD and ADDR bytes. } \\
\text { Bit 4:2-Bottom 3 bits of the byte count. Does not }\end{array}
$$ <br>
include ADDR and CMD bytes. One, two, and three <br>
byte instructions return 111. <br>

Bit 1-SPI FLASH mode: This bit is zero when the\end{array}\right\}\)| TEST pin is zero. |
| :--- |
| Bit 0-SPI FLASH mode ready: Used in SPI FLASH |
| mode. Indicates that the flash is ready to receive |
| another write instruction. |

## SPI Flash Mode (SFM)

In normal operation, the SPI slave interface cannot read or write the flash memory. However, the 71M6543 supports a special flash mode (SFM) which facilitates initial programming of the flash memory. When the 71M6543 is in this mode, the SPI can erase, read, and write the flash memory. Other memory elements such as XRAM and IO RAM are not accessible in this mode. In order to protect the flash contents, several operations are required before the SFM mode is successfully invoked.
In SFM mode, the 71M6543 supports $n$ byte reads and dual-byte writes to flash memory. See the SPI Transaction description on Page 68 for the format of read and write commands. Since the flash write operation is always based on a two-byte word, the initial address must always be even. Data is written to the 16-bit flash memory bus after the odd word is written.

When the 71M6543G is operating SFM, SPI single-byte transactions are used to write to FL_BANK[1:0] (SFR 0xB6[1:0]). During an SPI single-byte transaction, SPI_CMD[1:0] will over-write the contents of FL_BANK[1:0] (SFR 0xB6[1:0]). This will allow for access of the entire 128 KB flash memory while operating in SFM.

In SFM mode, the MPU is completely halted. For this reason, the interrupt feature described in the SPI Transaction section above is not available in SFM mode. The 71M6543 must be reset by the WD timer or by the RESET pin in order to exit SFM mode.

## Invoking SFM

The following conditions must be met prior to invoking SFM:

- ICE_E = 1. This disables the watchdog and adds another layer of protection against inadvertent Flash corruption.
- The external power source (V3P3SYS, V3P3A) is at the proper level (> 3.0 VDC).
- PREBOOT $=0$ (SFR 0xB2[7]). This validates the state of the SECURE bit (SFR 0xB2[6]).
- $\operatorname{SECURE}=0$. This I/O RAM register indicates that SPI secure mode is not enabled. Operations are limited to SFM Mass Erase mode if the SECURE bit = 1 (Flash read back is not allowed in Secure mode).
- FLSH_UNLOCK[3:0] = 0010 (I/O RAM 0x2702[7:4]).

The I/O RAM registers SFMM (I/O RAM 0x2080) and SFMS (I/O RAM 0x2081) are used to invoke SFM. Only the SPI interface has access to these two registers. This eliminates an indirect path from the MPU for disabling the watchdog. $S F M M$ and $S F M S$ need to be written to in sequence in order to invoke SFM. This sequential write process prevents inadvertent entering of SFM. The sequence for invoking SFM is:

- First, write to SFMM (I/O RAM 0x2080) register. The value written to this register defines the SFM mode.
- 0xD1: Mass Erase mode. A Flash Mass erase cycle is invoked upon entering SFM.
- 0x2E: Flash Read back mode. SFM is entered for Flash read back purposes. Flash writes will not be blocked and it is up to the user to guarantee that only previously unwritten locations are written. This mode is not accessible when SPI secure mode is set.
- SFM is not invoked if any other pattern is written to the SFMM register.
- Next, write 0x96 to the SFMS (I/O RAM 0x2081) register. This write invokes SFM provided that the previous write operation to $S F M M$ met the requirements. Writing any other pattern to this register does not invoke SFM. Additionally, any write operations to this register automatically reset the previously written SFMM register values to zero.


## SFM Details

The following occurs upon entering SFM.

- The CE is disabled.
- The MPU is halted. Once the MPU is halted it can only be restarted with a reset. This reset can be accomplished with the RESET pin, a watchdog reset, or by cycling power (without battery at the VBAT pin).
- The Flash control logic is reset in case the MPU was in the middle of a Flash write operation or Erase cycle.
- Mass erase is invoked if specified in the SFMM (I/O RAM 0x2080) register (see Invoking SFM, above). The SECURE bit (SFR 0xB2[6]) is cleared at the end of this and all Mass Erase cycles.
- All SPI read and write operations now refer to Flash instead of XRAM space.

The SPI host can access the current state of the pending multi-cycle Flash access by performing a 4-byte SPI write of any address and checking the status field.

All SPI write operations in SFM mode must be 6-byte write transactions that write two bytes to an even address. The write transactions must contain a command byte of $0 x 00$ which is the form that does not create an MPU interrupt. Auto incrementing is disabled for write operations.
SPI read transactions can make use of auto increment and may access single bytes. The command byte must always be 0x80 in SFM read transactions.

## SPI commands in SFM

Interrupts are not generated in SFM since the MPU is halted. The format of the commands is shown in the SPI Transactions description on Page 68.SPI Transactions

### 2.5.13 Hardware Watchdog Timer

An independent, robust, fixed-duration, watchdog timer (WDT) is included in the 71M6543. It uses the RTC crystal oscillator as its time base and must be refreshed by the MPU firmware at least every 1.5 seconds. When not refreshed on time, the WDT overflows and the part is reset as if the RESET pin were pulled high, except that the I/O RAM bits are in the same state as after a wake-up from SLP or LCD modes (see the I/O RAM description in 5.2 for a list of I/O RAM bit states after RESET and wake-up). Four thousand, one hundred CK32 cycles (or 125 ms ) after the WDT overflow, the MPU is launched from program address 0x0000.
The watchdog timer is also reset when the internal signal WAKE=0 (see 3.4 Wake-Up Behavior). The WDT is disabled when the ICE_E pin is pulled high.

For details, see 3.3.4 Watchdog Timer (WDT) Reset.

### 2.5.14 Test Ports (TMUXOUT and TMUX2OUT Pins)

Two independent multiplexers allow the selection of internal analog and digital signals for the TMUXOUT and TMUX2OUT pins. These pins are multiplexed with the SEG47 and SEG46 function. In order to function as test pins, LCD_MAP[46] (I/O RAM 0x2406[6]) and LCD_MAP[47] (I/O RAM 0x2406[7]) must be 0.

One of the digital or analog signals listed in Table 60 can be selected to be output on the TMUXOUT pin. The function of the multiplexer is controlled with the I/O RAM register TMUX[4:0] (I/O RAM 0x2502[4:0], as shown in Table 59.

One of the digital or analog signals listed in Table 60 can be selected to be output on the TMUX2OUT pin. The function of the multiplexer is controlled with the I/O RAM register TMUX2[4:0] (I/O RAM 0x2503[4:0]), as shown in.

$\sqrt{ }$The TMUX and TMUX2 I/O RAM locations are non-volatile and their contents are preserved by battery power and across resets.

The TMUXOUT and TMUX2OUT pins may be used for diagnosis purposes or in production test. The RTC 1-second output may be used to calibrate the crystal oscillator. The RTC 4-second output provides even higher precision.

Table 59: TMUX[4:0] Selections

| TMUX[5:0] | Signal Name | Description |
| :---: | :---: | :---: |
| 1 | RTCLK | 32.768 kHz clock waveform |
| 9 | WD_RST | Indicates when the MPU has reset the watchdog timer. Can be monitored to determine spare time in the watchdog timer. |
| A | CKMPU | MPU clock - see Table 8 |
| D | V3AOK bit | Indicates that the V3P3A pin voltage is $\geq 3.0 \mathrm{~V}$. The V3P3A and V3P3SYS pins are expected to be tied together at the PCB level. The 71M6543 monitors the V3P3A pin voltage only. |
| E | V3OK bit | Indicates that the V3P3A pin voltage is $\geq 2.8 \mathrm{~V}$. The V3P3A and V3P3SYS pins are expected to be tied together at the PCB level. The 71M654 monitors the V3P3A pin voltage only. |
| 1B | MUX_SYNC | Internal multiplexer frame SYNC signal. See Figure 4 and Figure 5. |
| 1C | CE_BUSY interrupt |  |
| 1D | CE_XFER interrupt | 2.3.3 on page 25 and Figure 12 on page 45 |
| 1F | RTM output from CE | See 2.3.5 on page 26 |
| Note: <br> All $T M U X[5: 0]$ values which are not shown are reserved. |  |  |

Table 60: TMUX2[4:0] Selections

| TMUX2[4:0] | Signal Name | Description |
| :---: | :---: | :---: |
| 0 | WD_OVF | Indicates when the watchdog timer has expired (overflowed). |
| 1 | PULSE_1S | One second pulse with $25 \%$ Duty Cycle. This signal can be used to measure the deviation of the RTC from an ideal 1 second interval. Multiple cycles should be averaged together to filter out jitter. |
| 2 | PULSE_4S | Four second pulse with $25 \%$ Duty Cycle. This signal can be used to measure the deviation of the RTC from an ideal 4 second interval. Multiple cycles should be averaged together to filter out jitter. The 4 second pulse provides a more precise measurement than the 1 second pulse. |
| 3 | RTCLK | 32.768 kHz clock waveform |
| 8 | $\begin{aligned} & \text { SPARE[1] bit - I/O RAM } \\ & \text { Ox2704[1] } \end{aligned}$ | Copies the value of the bit stored in $0 \times 2704[1]$. For general purpose use. |
| 9 | SPARE[2] bit - I/O RAM 0x2704[2] | Copies the value of the bit stored in $0 \times 2704[2]$. For general purpose use. |
| A | WAKE | Indicates when a WAKE event has occurred. |
| B | MUX_SYNC | Internal multiplexer frame SYNC signal. See Figure 4 and Figure 5. |
| C | MCK | See 2.5.3 on page 49. |
| E | GNDD | Digital GND. Use this signal to make the TMUX2OUT pin static. |
| 12 | INT0 - DIG I/O |  |
| 13 | INT1 - DIG I/O |  |
| 14 | INT2 - CE_PULSE |  |
| 15 | INT3-CE_BUSY | Interrupt 0. See 2.4.8 on page 39. Also see Figure 12 on page 45. |
| 16 | INT4-VSTAT |  |
| 17 | INT5 - EEPROM/SPI |  |
| 18 | INT6 - XFER, RTC |  |
| 1F | RTM_CK (flash) | See 2.3.5 on page 26. |
| Note: <br> All TMUX2[4:0] values which are not shown are reserved. |  |  |

## 3 Functional Description

### 3.1 Theory of Operation

The energy delivered by a power source into a load can be expressed as:

$$
E=\int_{0}^{t} V(t) I(t) d t
$$

Assuming phase angles are constant, the following formulae apply:

$$
\begin{aligned}
& \text { - } \mathrm{P}=\text { Real Energy }[\mathrm{Wh}]=\mathrm{V}^{*} \mathrm{~A}^{*} \cos \varphi^{*} \mathrm{t} \\
& \text { - } \mathrm{Q}=\text { Reactive Energy }[\mathrm{VARh}]=\mathrm{V}^{*} \mathrm{~A}^{*} \sin \varphi^{*} \mathrm{t} \\
& \text { - } \mathrm{S}=\text { Apparent Energy }[\mathrm{VAh}]=\sqrt{P^{2}+Q^{2}}
\end{aligned}
$$

For a practical meter, not only voltage and current amplitudes, but also phase angles and harmonic content may change constantly. Thus, simple RMS measurements are inherently inaccurate. A modern solid-state electricity meter IC such as the 71M6543 functions by emulating the integral operation above, i.e. it processes current and voltage samples through an ADC at a constant frequency. As long as the ADC resolution is high enough and the sample frequency is beyond the harmonic range of interest, the current and voltage samples, multiplied with the time period of sampling yields an accurate quantity for the momentary energy. Summing-up the momentary energy quantities over time results in accumulated energy.


Figure 24: Voltage, Current, Momentary and Accumulated Energy
Figure 24 shows the shapes of $V(t), I(t)$, the momentary power and the accumulated power, resulting from 50 samples of the voltage and current signals over a period of 20 ms . The application of 240 VAC and 100 A results in an accumulation of $480 \mathrm{Ws}(=0.133 \mathrm{~Wh})$ over the 20 ms period, as indicated by the accumulated power curve. The described sampling method works reliably, even in the presence of dynamic phase shift and harmonic distortion.

### 3.2 Battery Modes

Shortly after system power (V3P3SYS) is applied, the 71M6543 is in mission mode (MSN mode). MSN mode means that the part is operating with system power and that the internal PLL is stable. This mode is the normal operating mode where the part is capable of measuring energy.

When system power is not available, the 71 M 6543 is in one of three battery modes:

- BRN mode (brownout mode)
- LCD mode (LCD-only mode)
- SLP mode (sleep mode).

An internal comparator monitors the voltage at the V3P3SYS pin (note that V3P3SYS and V3P3A are typically connected together at the PCB level). When the V3P3SYS dc voltage drops below 2.8 VDC , the comparator resets an internal power status bit called $V 3 O K$. As soon as system power is removed and $V 3 O K=0$, the 71 M 6543 is forced to BRN mode. The MPU continues to execute code when the system transitions from MSN to BRN mode or from BRN to MSN mode. A soft reset should be executed when returning from BRN to MSN mode in order to re-initialize the I/O RAM. Depending on the MPU code, the MPU can choose to stay in BRN mode, or transition to LCD or to SLP mode (via the I/O RAM bits LCD_ONLY, I/O RAM 0x28B2[6] and SLEEP, I/O RAM Ox28B2[7]). BRN mode is similar to MSN mode except that resources powered by system power, such as the ADC and the CE, are not available (see Table 61), and that the supply current is drawn from the VBAT pin. In BRN mode, the PLL continues to function at the same frequency as in MSN mode. The MPU can configure BRN mode as it desires. For instance, it may choose to minimize battery power by reducing the PLL or MPU clock speed (see 3.2.1 BRN Mode, for the recommended settings to realize minimum power consumption in BRN mode).

When system power is restored, the 71M6543 automatically transitions from any of the battery modes (BRN, LCD, SLP) back to MSN mode.

Figure 25 shows a state diagram of the various operating modes, with the possible transitions between modes.
When the part wakes-up under battery power, the part automatically enters BRN mode (see 3.4 Wake-Up Behavior). From BRN mode, the part may enter either LCD mode or SLP mode, as controlled by the MPU.


Figure 25: Operation Modes State Diagram

Transitions from both LCD and SLP mode to BRN mode can be initiated by the following events:

- Wake-up timer timeout.
- Pushbutton ( PB ) is activated.
- A rising edge on SEGDIO4, or a high logic level on SEGDIO52 or SEGDIO55.
- Activity on the RX or OPT_RX pins.

The MPU has access to a variety of registers that signal the event that caused the wake up. See 3.4 Wake-Up Behavior for details.
Table 61 shows the circuit functions available in each operating mode.
Table 61: Available Circuit Functions

| Circuit Function | System Power |  | Battery Power |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | MSN (Mission Mode) |  | BRN (Brownout Mode) |  | LCD | SLEEP |
|  | PLL_FAST=1 | PLL_FAST=0 | PLL_FAST=1 | PLL_FAST=0 |  |  |
| CE (Computation Engine) | Yes | Yes | -- ${ }^{1}$ | -- | -- | -- |
| FIR | Yes | Yes | -- | -- | -- | -- |
| ADC, VREF | Yes | Yes | -- | -- | -- | -- |
| PLL | Yes | Yes | Yes | Yes | Boost ${ }^{2}$ | -- |
| Battery Measurement | Yes | Yes | Yes | Yes | -- | -- |
| Temperature sensor | Yes | Yes | Yes | Yes | Yes | Yes |
| Max MPU clock rate | $\begin{gathered} \hline 4.92 \mathrm{MHz} \\ \text { (from PLL) } \end{gathered}$ | $\begin{gathered} 1.57 \mathrm{MHz} \\ \text { (from PLL) } \end{gathered}$ | $\begin{gathered} \hline 4.92 \mathrm{MHz} \\ \text { (from PLL) } \end{gathered}$ | $\begin{gathered} 1.57 \mathrm{MHz} \\ \text { (from PLL) } \end{gathered}$ | -- | -- |
| MPU_DIV clk. divider | Yes | Yes | Yes | Yes | -- | -- |
| ICE | Yes | Yes | Yes | Yes | -- | -- |
| DIO Pins | Yes | Yes | Yes | Yes | -- | -- |
| Watchdog Timer | Yes | Yes | Yes | Yes | -- | -- |
| LCD | Yes | Yes | Yes | Yes | Yes | -- |
| LCD Boost | Yes | Yes | Yes | Yes | Yes |  |
| EEPROM Interface (2-wire) | Yes | Yes | Yes | Yes | -- | -- |
| EEPROM Interface (3-wire) | Yes | Yes | Yes | Yes | -- | -- |
| UART (full speed) | Yes | Yes | Yes | Yes | -- | -- |
| Optical TX modulation | 38.4 kHz | 38.9 kHz | 38.4 kHz | 38.9 kHz | -- | -- |
| Flash Read | Yes | Yes | Yes | Yes | -- | -- |
| Flash Page Erase | Yes | Yes | Yes | Yes | -- | -- |
| Flash Write | Yes | Yes | Yes | Yes | -- | -- |
| RAM Read and Write | Yes | Yes | Yes | Yes | -- | -- |
| Wakeup Timer | Yes | Yes | Yes | Yes | Yes | Yes |
| OSC and RTC | Yes | Yes | Yes | Yes | Yes | Yes |
| DRAM data preservation | Yes | Yes | Yes | Yes | -- | -- |
| NV RAM data preservation | Yes | Yes | Yes | Yes | Yes | Yes |

Notes:

1. "--" indicates that the corresponding circuit is not active
2. "Boost" implies that the LCD boost circuit is active (i.e., LCD_VMODE[1:0] = 10 (I/O RAM 0x2401[7:67)). The LCD boost circuit requires a clock from the PLL to function. Thus, the PLL is automatically kept active if LCD boost is active while in LCD mode, otherwise the PLL is de-activated.

### 3.2.1 BRN Mode

In BRN mode, most non-metering digital functions are active (as shown in Table 61) including ICE, UART, EEPROM, LCD and RTC. In BRN mode, the PLL continues to function at the same frequency as MSN mode. It is up to the MPU to scale down the PLL (using PLL_FAST, I/O RAM 0x2200[4]) or the MPU frequency (using MPU_DIV[2:0], I/O RAM 0x2200[2:0]) in order to save power.

From BRN mode, the MPU can choose to enter LCD or SLP modes. When system power is restored while the 71M6543 is in BRN mode, the part automatically transitions to MSN mode.

The recommended minimum power configuration for BRN mode is as follows:

- $\quad$ RCE0 $=0 \times 00$ (I/O RAM 0x2709[7:0]) - remote sensors disabled
- LCD_BAT = 1 (I/O RAM 0x2402[7]) - LCD powered from VBAT
- LCD_VMODE[1:0] = 0 (I/O RAM 0x2401[7:6]) - 5V LCD boost disabled
- CE6 $=0 \times 00$ (I/O RAM 0x2106) - CE, RTM and CHOP are disabled
- MUX_DIV[3:0] = O(I/O RAM 0x2100[7:4]) - the ADC multiplexer is disabled
- $A D C_{-} E=0(I / O$ RAM 0x2704[4]) - ADC disabled
- VREF_CAL $=0$ (I/O RAM 0x2704[7]) - Vref not driven out
- $V R E F_{-} D I S=1$ (I/O RAM 0x2704[6]) - Vref disabled
- PRE_E $=0$ (I/O RAM 0x2704[5] - pre-amp disabled
- BCURR $=0$ (I/O RAM 0x2704[3]) - battery $100 \mu \mathrm{~A}$ current load OFF
- TMUX[5:0] = 0x0E (I/O RAM 0x2502[5:07) - TMUXOUT output set to a dc value
- TMUX2[4:0] = 0x0E (I/O RAM 0x2503[4:0]) - TMUXOUT2 output set to a dc value
- CKGN = 0x24 (I/O RAM 0x2200) - PLL set slow, and MPU_DIV[2:0] (I/O RAM 0x2200[2:0]) set to maximum
- TEMP_PER[2:0] = 6 (I/O RAM 0x28A0[2:0]) - temp measurement set to automatic every 512 s
- TEMP_BSEL $=1$ (I/O RAM 0x28A0[7]) - temperature sensor monitors VBAT
- $\quad P C O N \mid=1$ (SFR 0x87) - at the end of the main BRN loop, halt the MPU and wait for an interrupt
- The baud rate registers are adjusted as needed
- All unused interrupts are disabled


### 3.2.2 LCD Mode

LCD mode may be commanded by the MPU at any time by setting the LCD_ONLY control bit (I/O RAM 0x28B2[6]). However, it is recommended that the LCD_ONLY control bit be set by the MPU only after the 71M6543 has entered BRN mode. For example, if the 71 M 6543 is in MSN mode when $L C D \_O N L Y$ is set, the duration of LCD mode is very brief and the 71M6543 immediately 'wakes'.

In LCD mode, V3P3D is disabled, and the VBAT pin supplies the LCD current. Before asserting $L C D \_O N L Y$ mode, it is recommended that the MPU minimize PLL current by reducing the output frequency of the PLL to 6.29 MHz (i.e., write PLL_FAST = 0, I/O RAM 0x2200[4]). The LCD boost system requires a clock from the PLL for its operation. Thus, if the LCD boost system is enabled (i.e., $L C D \_V M O D E[1: 0]=10, I / O$ RAM 0x2401[7:67), then the PLL is automatically kept active during LCD mode, otherwise the PLL is de-activated.
In LCD mode, the data contained in the $L C D \_S E G$ registers is displayed using the segment driver pins. Up to two LCD segments connected to the pins SEGDIO22 and SEGDIO23 can be made to blink without the involvement of the MPU, which is disabled in LCD mode. To minimize battery power consumption, only segments that are used should be enabled.
After the transition from LCD mode to MSN or BRN mode, the PC (Program Counter) is at 0x0000, the XRAM is in an undefined state, and configuration I/O RAM bits are reset (see Table 70 for I/O RAM state upon wake). The data stored in non-volatile I/O RAM locations is preserved in LCD mode (the shaded locations in Table 70 are non-volatile).

### 3.2.3 SLP Mode

The SLP mode may be commanded by the MPU whenever main system power is absent by asserting the SLEEP bit (I/O RAM 0x28B2[7]). The purpose of the SLP mode is to consume the least power while still maintaining the RTC, temperature compensation of the RTC, and the non-volatile portions of the I/O RAM.
In SLP mode, the V3P3D pin is disconnected, removing all sources of leakage from VBAT and V3P3SYS. The non-volatile memory domain and the basic functions, such as temperature sensor, oscillator, and RTC, are powered by the VBAT_RTC input. In this mode, the I/O configuration bits, LCD configuration bits, and NV RAM values are preserved and RTC and oscillator continue to run. This mode can be exited only by system power-up or one of the wake methods described in 3.4 Wake-Up Behavior.
If the SLEEP bit is asserted when V3P3SYS pin power is present (i.e., while in MSN mode), the 71M6543 enters SLP mode, resetting the internal WAKE signal, at which point the 71M6543 begins the standard wake from sleep procedures as described in 3.4 Wake-Up Behavior.
After the transition from SLP mode to MSN or BRN mode the $P C$ is at $0 \times 0000$, the XRAM is in an undefined state, and the I/O RAM is only partially preserved (see the description of I/O RAM states in 5.2). The non-volatile sections of the I/O RAM are preserved unless RESET goes high.

### 3.3 Fault and Reset Behavior

### 3.3.1 Events at Power-Down

Power fault detection is performed by internal comparators that monitor the voltage at the V3P3A pin and also monitor the internally generated VDD pin voltage ( 2.5 VDC ). The V3P3SYS and V3P3A pins must be tied together at the PCB level, so that the comparators, which are internally connected only to the V3P3A pin, are able to simultaneously monitor the common V3P3SYS and V3P3A pin voltage. The following discussion assumes that the V3P3A and V3P3SYS pins are tied together at the PCB level.
During a power failure, as V3P3A falls, two thresholds are detected:

- The first threshold, at $3.0 \mathrm{VDC}(\operatorname{VSTAT}[2: 0]=001, \operatorname{SFR} 0 x F 9[2: 0])$, warns the MPU that the analog modules are no longer accurate. Other than warning the MPU, the hardware takes no action when this threshold is crossed. This comparison produces an internal bit named V3OKA.
- The second threshold, at 2.8 VDC , causes the 71 M 6543 to switch to battery power. This switching happens while the FLASH and RAM systems are still able to read and write. This comparison produces an internal bit named V3OK.

The power quality is reflected by the VSTAT[2:0] register in I/O RAM space, as shown in Table 62. The VSTAT[2:0] register is located at SFR address F9 and occupies bits 2:0. The VSTAT[2:0] field can only be read.
In addition to the state of the main power, the VSTAT[2:0] register provides information about the internal VDD voltage under battery power. Note that if system power (V3P3A) is above 2.8 VDC , the 71 M 6543 always switches from battery to system power.

Table 62: VSTAT[2:0] (SFR 0xF9[2:0])

| VSTAT[2:0] | Description |
| :---: | :--- |
| 000 | System Power OK. V3P3A >3.0 VDC. Analog modules are functional and accurate. |
| 001 | System Power is low. 2.8 VDC $<$ V3P3A $<3.0$ VDC. Analog modules not accurate. <br> Switch over to battery power is imminent. |
| 010 | The IC is on battery power and VDD is OK. VDD > 2.25 VDC. The IC has full digital <br> functionality. |
| 011 | The IC is on battery power and 2.25 VDC > VDD > 2.0 VDC. Flash write operations are <br> inhibited. |
| 101 | The IC is on battery power and VDD < 2.0, which means that the MPU is nearly out of <br> voltage. A reset occurs in 4 cycles of the crystal clock CK32. |

The response to a system power fault is almost entirely controlled by firmware. During a power failure, system power slowly falls. This fall in power is monitored by internal comparators that cause the hardware to automatically switch over to taking power from the VBAT input. An interrupt notifies the MPU that the part is now battery powered. At this point, it is the MPU's responsibility to reduce power by slowing the clock rate, disabling the PLL, etc.
Precision analog components such as the bandgap reference, the bandgap buffer, and the ADC are powered only by the V3P3A pin and become inaccurate and ultimately unavailable as the V3P3A pin voltage continues to drop (i.e., circuits powered by the V3P3A pin are not backed by the VBAT pin). When the V3P3A pin falls below 2.8 VDC, the ADC clocks are halted and the amplifiers are unbiased. Meanwhile, control bits such as $A D C-E$ bit (I/O RAM 0x2704[4]) are not affected, since their I/O RAM storage is powered from the VDD $\mathrm{pin}^{-}(2.5 \mathrm{VDC})$. The VDD pin is supplied with power through an internal 2.5 VDC regulator that is connected to the V3P3D pin. In turn, the V3P3D pin is switched to receive power from the VBAT pin when the V3P3SYS pin drops below 3.0 VDC. Note that the V3P3SYS and V3P3A pins are typically tied together at the PCB level.

### 3.3.2 IC Behavior at Low Battery Voltage

When system power is not present, the 71M6543 relies on the VBAT pin for power. If the VBAT voltage is not sufficient to maintain VDD at 2.0 VDC or greater, the MPU cannot operate reliably. Low VBAT voltage can occur while the part is operating in BRN mode, or while it is dormant in SLP or LCD mode. Two cases can be distinguished, depending on MPU code:

- Case 1: System power is not present, and the part is waking from SLP or LCD mode. In this case, the hardware checks the value of VDD to determine if processor operation is possible. If it is not possible, the part configures itself for BRN operation, and holds the processor in reset (WAKE=0). In this mode, VBAT powers the 1.0 VDC reference for the LCD system, the VDD regulator, the PLL, and the fault comparator. The part remains in this waiting mode until VDD becomes high due to system power being applied or the VBAT battery being replaced or recharged.
- Case 2: The part is operating under VBAT power and VSTAT[2:0] (SFR 0xF9[2:0]) becomes 101, indicating that VDD falls below 2.0 VDC. In this case, the firmware has two choices:

1) One choice is to assert the SLEEP bit (I/O RAM $0 \times 28 B 2[7]$ ) immediately. This assertion preserves the remaining charge in VBAT. Of course, if the battery voltage is not increased, the 71M6543 enters Case 1 as soon as it tries to wake up.
2) The alternative choice is to enter the waiting mode described in Case 1 immediately. Specifically, if the firmware does not assert the SLEEP bit, the hardware resets the processor four CE32 clock cycles (i.e. $122 \mu \mathrm{~s}$ ) after $\operatorname{VSTAT[2:0]}$ becomes 101 and, as described in Case 1, it begins waiting for VDD to become greater than 2.0 VDC. The MPU wakes up when system power returns, or when VDD becomes greater than 2.0 VDC.

In either case, when VDD recovers, and when the MPU wakes up, the WF_BADVDD flag (I/O RAM 0x28B0[2]) can be read to determine that the processor is recovering from a bad VBAT condition. The WF_BADVDD flag remains set until the next time WAKE falls. This flag is independent of the other WF flags.
In all cases, low VBAT voltage does not corrupt RTC operation, the state of NV memory, or the state of non-volatile memory. These circuits depend on the VBAT_RTC pin for power.

### 3.3.3 Reset Sequence

When the RESET pin is pulled high, all digital activity in the chip stops, with the exception of the oscillator and RTC. Additionally, all I/O RAM bits are forced to their RST state. A reliable reset does not occur until RESET has been high at least for $2 \mu \mathrm{~s}$. Note that TMUX and the RTC are not reset unless the TEST pin is pulled high while RESET is high.
The RESET control bit (I/O RAM 0x 2200[3]) performs an identical reset to the RESET pin except that a significantly shorter reset timer is used.

Once initiated, the reset sequence waits until the reset timer times out. The time out occurs in 4100 CE32 cycles ( 125 ms ), at which time the MPU begins executing its pre-boot and boot sequences from address $0 \times 0000$. See 2.5.1.1 for a detailed description of the pre-boot and boot sequences.
If system power is not present, the reset timer duration is two CE32 cycles, at which time the MPU begins executing in BRN mode, starting at address $0 \times 0000$.
A softer form of reset is initiated when the E_RST pin of the ICE interface is pulled low. This event causes the MPU and other registers in the MPU core to be reset but does not reset the remainder of the 71M6543. It does not trigger the reset sequence. This type of reset is intended to reset the MPU program, but not to make other changes to the chip's state.

### 3.3.4 Watchdog Timer (WDT) Reset

The watchdog timer (WDT) is described in 2.5.13.
A status bit, WF_OVF (I/O RAM 0x28B0[4]), is set when a WDT overflow occurs. Similar to the other wake flags, this bit is powered by the non-volatile supply and can be read by the MPU to determine if the part is initializing after a WD overflow event or after a power-up. The $W F \_O V F$ bit is cleared by the RESET pin.
There is no internal digital state that could deactivate the WDT. For debug purposes, however, the WDT can be disabled by raising the ICE_E pin to 3.3 VDC.

In normal operation, the WDT is reset by periodically writing a one to the $W D \_R S T$ control bit $I / O R A M$ $0 x 28 B 4$ [7]). The watchdog timer is also reset when the 71 M 6543 wakes from LCD or SLP mode, and when ICE_E=1.

### 3.4 Wake-Up Behavior

As described above, the part always wakes up in MSN mode when system power is restored. As stated in 3.2 Battery Modes, transitions from both LCD and SLP mode to BRN mode can be initiated by a wakeup timer timeout, when the pushbutton (PB) input is activated, a rising edge on SEGDIO4, or a high logic level on SEGDIO52 or SEGDIO55, or by activity on the RX or OPT_RX pins.

### 3.4.1 Wake on Hardware Events

The following pin signal events wake the 71 M 6543 from SLP or LCD mode: a high level on the PB pin, either edge on the RX pin, a rising edge on the SEGDIO4 pin, a high level on the SEGDIO52 pin, or a high level on the SEGDIO55 pin or either edge on the OPT_RX pin. See Table 63 for de-bounce details on each pin and for further details on the OPT_RX/SEGDIO55 pin. The SEGDIO4, SEGDIO52, and SEGDIO55 pins must be configured as DIO inputs and their wake enable ( $E W_{-} x$ bits) must be set. In SLP and LCD modes, the MPU is held in reset and cannot poll pins or react to interrupts. When one of the hardware wake events occurs, the internal WAKE signal rises and within three CK32 cycles the MPU begins to execute. The MPU can determine which one of the pins awakened it by checking the $W F_{-} P B, W F_{-} R X, W F S_{-} S E G D I O 4$, $W F_{-} D I O 52$, or $W F_{-} D I O 55$ flags (see Table 63).

If the part is in SLP or LCD mode, it can be awakened by a high level on the PB pin. This pin is normally pulled to GND and can be connected externally so it may be pulled high by a push button depression.
Some pins are de-bounced to reject EMI noise. Detection hardware ignores all transitions after the initial transition. Table 63 shows which pins are equipped with de-bounce circuitry.

Pins that do not have de-bounce circuits must still be high for at least $2 \mu \mathrm{~s}$ to be recognized.
The wake enable and flag bits are shown in Table 63. The wake flag bits are set by hardware when the MPU wakes from a wake event. Note that the PB flag is set whenever the PB is pushed, even if the part is already awake. Table 65 lists the events that clear the WF flags.

In addition to push buttons and timers, the part can also reboot due to the RESET pin, the RESET bit (I/O RAM 0x2200[3]), the WDT, the cold start detector, and E_RST. As seen in Table 63, each of these mechanisms has a flag bit to alert the MPU to the source of the wakeup. If the wakeup is caused by return of system power, there is no active WF flag and the VSTAT[2:0] field (SFR 0xF9[2:0]) indicates that system power is stable.

Table 63: Wake Enable and Flag Bits

| Wake Enable |  | Wake Flag |  | De-bounce | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Name | Location | Name | Location |  |  |
| WAKE_ARM | 28B2[5] | WF_TMR | 28B1[5] | No | Wake on Timer. |
| $E W_{-} P B$ | 28B3[3] | $W F_{-} P B$ | 28B1[3] | Yes | Wake on PB.* |
| $E W_{-} R X$ | 28B3[4] | $W F_{-} R X$ | 28B1[4] | $2 \mu \mathrm{~s}$ | Wake on either edge of RX. |
| EW_DIO4 | 28B3[2] | WF_DIO4 | 28B1[2] | $2 \mu \mathrm{~s}$ | Wake on SEGDIO4. |
| $E W_{-}$DIO52 | 28B3[1] | WF_DIO52 | 28B1[1] | Yes | Wake on SEGDIO52.* |
| $E W_{-}$DIO55 | 28B3[0] | WF_DIO55 | 28B1[0] | Yes | OPT_RXDIS = 1: Wake on DIO55 with 64 ms de-bounce.* $O P T_{-} R X D I S=0$ : Wake on either edge of OPT_RX with $2 \mu \mathrm{~s}$ de-bounce. OPT_RXDIS: I/O RAM 0x2457[2] |
| Always Enabled |  | WF_RST | 28B0[6] | $2 \mu \mathrm{~s}$ | Wake after RESET. |
| Always Enabled |  | WF_RSTBIT | 28B0[5] | No | Wake after RESET bit. |
| Always Enabled |  | WF_ERST | 28B0[3] | $2 \mu \mathrm{~s}$ | Wake after E_RST. (ICE must be enabled) |


| Wake Enable |  | Wake Flag |  | De-bounce | Description |
| :---: | :---: | :---: | :---: | :--- | :--- |
| Name | Location | Name | Location |  |  |
| Always Enabled | $W F_{-} O V F$ | $28 \mathrm{~B} 0[4]$ | Wake after WD reset. |  |  |
| Always Enabled | $W F_{-} C S T A R T$ | $28 \mathrm{~B} 0[7]$ | No | Wake after cold start - the first <br> application of power. |  |
| Always Enabled | $W F_{-} B A D V D D$ | $28 \mathrm{~B} 0[2]$ | No | Wake after insufficient VBAT <br> voltage. |  |

*This pin is sampled every 2 ms and must remain high for 64 ms to be declared a valid high level. This pin is highlevel sensitive.

Table 64: Wake Bits

| Name | Location | RST | WK | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| EW_DIOR | 28B3[2] | 0 | - | R/W | Connects SEGDIO4 to the WAKE logic and permits SEGDIO4 rising to wake the part. This bit has no effect unless SEGDIO4 is configured as a digital input. |
| EW_DIO52 | 28B3[1] | 0 | - | R/W | Connects DIO52 to the WAKE logic and permits DIO52 high level to wake the part. This bit has no effect unless DIO52 is configured as a digital input. |
| EW_DIO55 | 28B3[0] | 0 | - | R/W | Connects DIO55 to the WAKE logic and permits DIO55 high level to wake the part. This bit has no effect unless DIO55 is configured as a digital input. |
| WAKE_ARM | 28B2[5] | 0 | - | R/W | Arms the WAKE timer and loads it with the value in WAKE_TMR (I/O RAM 0x2880) register. When SLP or LCD mode is asserted by the MPU, the WAKE timer becomes active. |
| $E W_{-} P B$ | 28B3[3] | 0 | - | R/W | Connects the PB pin to the WAKE logic and permits PB high level to wake the part. PB is always configured as an input. |
| $E W_{-} R X$ | 28B3[4] | 0 | - | R/W | Connects the RX pin to the WAKE logic and permits $R X$ rising to wake the part. See 3.4.1 for de-bounce issues. |
| WF_DIO4 | 28B1[2] | 0 | - | R | SEGDIO4 flag bit. If SEGDIO4 is configured to wake the part, this bit is set whenever SEGDIO4 rises. It is held in reset if SEGDIO4 is not configured for wakeup. |
| WF_DIO52 | 28B1[1] | 0 | - | R | SEGDIO52 flag bit. If SEGDIO52 is configured to wake the part, this bit is set whenever SEGDIO52 is a high level. It is held in reset if SEGDIO52 is not configured for wakeup. |
| WF_DIO55 | 28B1[0] | 0 | - | R | SEGDIO55 flag bit. If SEGDIO55 is configured to wake the part, this bit is set whenever SEGDIO55 is a high level. It is held in reset if SEGDIO55 is not configured for wakeup. |
| WF_TMR | 28B1[5] | 0 | - | R | Indicates that the Wake timer caused the part to wake up. |
| $W F_{\sim} P B$ | 28B1[3] | 0 | - | R | Indicates that the PB pin caused the part to wake. |
| WF_RX | 28B1[4] | 0 | - | R | Indicates that RX pin caused the part to wake. |
| $\begin{gathered} \text { WF RST } \\ \text { WF_- } R S T B I T \\ W \bar{F}_{-} \text {ERST } \\ W F_{-}^{C S T A R T} \\ W F_{-} \text {BADVVDD } \end{gathered}$ | 28BO[6] $28 \mathrm{BO}[5]$ $28 \mathrm{BO}[3]$ $28 \mathrm{BO} 0[7]$ $28 \mathrm{BO} 0[2]$ |  | - | R | Indicates that the RST pin, E_RST pin, RESET bit (I/O RAM 0x2200[3]), the cold start detector, or low voltage on the VBAT pin caused the part to reset. *See Table 65 for details. |

Table 65: Clear Events for WAKE flags

| Flag | Wake on: | Clear Events |
| :---: | :--- | :--- |
| $W F_{-} T M R$ | Timer expiration | WAKE falls |
| $W F_{-} P B$ | PB pin high level | WAKE falls |
| $W F_{-} R X$ | Either edge RX pin | WAKE falls |
| $W F_{-} D I O 4$ | SEGDIO4 rising edge | WAKE falls |
| $W F_{-} D I O 52$ | SEGDIO52 high level <br> If $O P T_{-} R X D I S=1 ~(I / O ~ R A M ~ 0 x 2457[2]), ~$ <br> wake on SEGDIO55 high <br> If $O P T \_R X D I S ~=~ 0$ <br> wake on either edge of OPT_RX | WAKE falls |
| $W F_{-}$WIO55 | RESET pin driven high | WAKE falls, WF_CSTART, WF_RSTBIT, <br> WF_OVF, WF_BADVDD |
| $W F_{-} R S T B I T$ | RESET bit is set (I/O RAM 0x2200[3]) | WAKE falls, WF_CSTART, WF_OVF, <br> WF_BADVDD, WF_RST |
| $W F_{-} E R S T$ | E_RST pin driven high and the ICE <br> interface must be enabled by driving the <br> ICE_E pin high. | WAKE falls, WF_CSTART, WF_RST, <br> WF_OVF, WF_RSTBIT |
| $W F_{-} O V F$ | Watchdog (WD) reset | WAKE falls, WF_CSTART, WF_RSTBIT, <br> WF_BADVDD, WF_RST |
| $W F_{-} C S T A R T$ | Cold-start (i.e., after the application of <br> first power) | WAKE falls, WF_RSTBIT, WF_OVF, <br> WF_BADVDD, WF_RST |

Note:
"WAKE falls" implies that the internal WAKE signal has been reset, which happens automatically upon entry into LCD mode or SLEEP mode (i.e., when the MPU sets the LCD ONLY bit (I/O RAM 0x28B2[67) or the SLEEP (I/O RAM 0x28B2[7]) bit). When the internal WAKE signal resets, all wake flags are reset. Since the various wake flags are automatically reset when WAKE falls, it is not necessary for the MPU to reset these flags before entering LCD mode or SLEEP mode. Also, other wake events can cause the wake flag to reset, as indicated above (e.g., the $W F_{-} R S T$ flag can also be reset by any of the following flags setting: $\left.W F \_C S T A R T, W S \_R S T B I T, W F \_O V F, W F \_B A D V D D\right)$

### 3.4.2 Wake on Timer

If the part is in SLP or LCD mode, it can be awakened by the Wake Timer. Until this timer times out, the MPU is in reset due to the internal WAKE signal being low. When the Wake Timer times out, WAKE rises and within three CK32 cycles, the MPU begins to execute. The MPU can determine that the timer woke it by checking the $W F_{-}$TMR (I/O RAM 0x28B1[2]) wake flag.
The Wake Timer begins timing when the part enters LCD or SLP mode. Its duration is controlled by the WAKE_TMR[7:0] register (I/O RAM 0x2880). The timer duration is WAKE_TMR[7:0] +1 seconds.
The Wake Timer is armed by setting WAKE_ARM $=1$ (I/O RAM $0 \times 28 B 2[57$ ). It must be armed at least three RTC cycles before either SLP or LCD modes are initiated. Setting WAKE_ARM presets the timer with the value in WAKE_TMR and readies the timer to start when the MPU writes to the SLEEP (I/O RAM $0 \times 28 B 2[7]$ ) or $L C D \_O N L Y$ (I/O RAM $0 \times 28 B 2$ [6]) bits. The timer is neither reset nor disarmed when the MPU wakes-up. Thus, once armed and set, the MPU continues to be awakened WAKE_TMR[7:0] seconds after it requests SLP mode or LCD mode (i.e., once written, the WAKE_TMR[7: $\overline{0}]$ register holds its value and does not have to be re-written each time the MPU enters SLP or LCD mode. Also, since WAKE_TMR[7:0] is non-volatile, it also holds its value through resets and power failures).

### 3.5 Data Flow and MPU/CE Communication

The data flow between the Compute Engine (CE) and the MPU is shown in Figure 26. In a typical application, the 32-bit CE sequentially processes the samples from the ADC inputs, performing calculations to measure
active power (Wh), reactive power (VARh), $A^{2} h$, and $V^{2} h$ for four-quadrant metering. These measurements are then accessed by the MPU, processed further and output using the peripheral devices available to the MPU.

Both the CE and multiplexer are controlled by the MPU via shared registers in the I/O RAM and in RAM.
The CE outputs a total of six discrete signals to the MPU. These consist of four pulses and two interrupts:

- CE_BUSY
- XFER_BUSY
- WPULSE, VPULSE (pulses for active and reactive energy)
- XPULSE, YPULSE (auxiliary pulses)

These interrupts are connected to the MPU interrupt service inputs as external interrupts. CE_BUSY indicates that the CE is actively processing data. This signal occurs once every multiplexer cycle (typically $396 \mu \mathrm{~s}$ ), and indicates that the CE has updated status information in its CESTATUS register (CE RAM 0x80).
XFER_BUSY indicates that the CE is updating data to the output region of the RAM. This update occurs whenever the CE has finished generating a sum by completing an accumulation interval determined by SUM_SAMPS[12:0], I/O RAM 0x2107[4:0], 2108[7:0], (typically every 1000 ms ). Interrupts to the MPU occur on the falling edges of the XFER_BUSY and CE_BUSY signals.
WPULSE and VPULSE are typically used to signal energy accumulation of real (Wh) and reactive (VARh) energy. Tying WPULSE and VPULSE into the MPU interrupt system can support pulse counting.
XPULSE and YPULSE can be used to signal events such as sags and zero crossings of the mains voltage to the MPU. Tying these outputs into the MPU interrupt system relieves the MPU from having to read the CESTATUS register at every occurrence of the CE_BUSY interrupt in order to detect sag or zero crossing events.
Refer to 5.3 CE Interface Description on page 116 for additional information on setting up the device using the MPU firmware.


Figure 26: MPU/CE Data Flow

## 4 Application Information

### 4.1 Connecting 5 V Devices

All digital input pins of the 71 M 6543 are compatible with external 5 V devices. I/O pins configured as inputs do not require current-limiting resistors when they are connected to external 5 V devices.

### 4.2 Directly Connected Sensors

Figure 27 through Figure 30 show voltage-sensing resistive dividers, current-sensing current transformers (CTs) and current-sensing resistive shunts and how they are connected to the voltage and current inputs of the 71M6543. All input signals to the 71 M 6543 sensor inputs are voltage signals providing a scaled representation of either a sensed voltage or current.

The analog input pins of the 71 M 6543 are designed for sensors with low source impedance. be used. Refer to the Demo Board schematics for complete sensor input circuits and corresponding component values.


Figure 27: Resistive Voltage Divider (Voltage Sensing)


Figure 28. CT with Single-Ended Input Connection (Current Sensing)


Figure 29: CT with Differential Input Connection (Current Sensing)


Figure 30: Differential Resistive Shunt Connections (Current Sensing)

### 4.3 Systems Using 71M6xx3 Isolated Sensors and Current Shunts

Figure 31 shows a typical connection for current shunt sensors; using the $71 \mathrm{M} 6 \times x 3$ (polyphase) isolated sensors. Note that one shunt current sensor is connected without isolation, which is the neutral current sensor in this example (connected to pins IADC0-IADC1). Each 71M6xx3 device is electrically isolated by a low-cost pulse transformer. The 71M6543 current sensor inputs must be configured for remote sensor communications, as described in 2.2.8 71M6xx3 Isolated Sensor Interface (page 22). Flexible remapping using the I/O RAM registers MUXn_SEL[3:0] allows the sequence of analog input pins to be different from the standard configuration (a corresponding CE code must be used). See Figure 2 for the AFE configuration corresponding to Figure 31.


Figure 31: System Using Three-Remotes and One-Local (Neutral) Sensor

### 4.4 System Using Current Transformers

Figure 32 shows a polyphase system using four current transformers to support optional Neutral current sensing for anti-tamper purposes. The Neutral current sensing CT can be omitted if Neutral current sensing is not required. The system is referenced to Neutral (i.e., the Neutral rail is tied to V3P3A and V3P3SYS).


Figure 32. System Using Current Transformers

### 4.5 Metrology Temperature Compensation

### 4.5.1 Temperature Compensation

Since the VREF band-gap amplifier is chopper-stabilized, as set by the CHOP_E[1:0] (I/O RAM 0x2106[3:2]) control field, the dc offset voltage, which is the most significant long-term drift mechanism in the voltage references (VREF), is automatically removed by the chopper circuit. Both the 71M6543 and the 71M6xx3 feature chopper circuits for their respective VREF voltage reference.
Since the variation in the bandgap reference voltage (VREF) is the major contributor to measurement error across temperatures, Maxim implements a two-step procedure to trim and characterize the VREF voltage reference during the device manufacturing process.

The first step in the process is applied to all parts (71M6543F, 71M6543G). In this first step, the reference voltage (VREF) is trimmed to a target value of 1.195V. During this trimming process, the TRIMT[7:0] (I/O RAM 0x2309) value is stored in non-volatile fuses. TRIMT[7:0] is trimmed to a value that results in minimum VREF variation with temperature.
For the 71M6543F and 71M6543G devices, the TRIMT[7:0] value can be read by the MPU during initialization in order to calculate parabolic temperature compensation coefficients suitable for each individual 71M6543F and 71M6543G device. The resulting temperature coefficient for VREF in the 71 M 6543 F and 71 M 6543 G is $\pm 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$.
Considering the factory calibration temperature of VREF to be $+22^{\circ} \mathrm{C}$ and the industrial temperature range $\left(-40^{\circ} \mathrm{C}\right.$ to $\left.+85^{\circ} \mathrm{C}\right)$, the VREF error at the temperature extremes for the 71 M 6543 F and 71 M 6543 G devices can be calculated as:

$$
\begin{gathered}
\left(85^{\circ} \mathrm{C}-22^{\circ} \mathrm{C}\right) \cdot 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}=+2520 \mathrm{ppm}=+0.252 \% \\
\text { and } \\
\left(-40^{\circ} \mathrm{C}-22^{\circ} \mathrm{C}\right) \cdot 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}=-2480 \mathrm{ppm}=-0.248 \%
\end{gathered}
$$

The above calculation implies that both the voltage and the current measurements are individually subject to a theoretical maximum error of approximately $\pm 0.25 \%$. When the voltage sample and current sample are multiplied together to obtain the energy per sample, the voltage error and current error combine resulting in approximately $\pm 0.5 \%$ maximum energy measurement error. However, this theoretical $\pm 0.5 \%$ error considers only the voltage reference (VREF) as an error source. In practice, other error sources exist in the system. The principal remaining error sources are the current sensors (shunts or CTs) and their corresponding signal conditioning circuits, and the resistor voltage divider used to measure the voltage. The 71M6543F and 71M6543G devices should be used in Class 1\% designs, to allow margin for the other error sources in the system.
The preceding discussion in this section also applies to the 71 M 6603 ( $0.5 \%$ ), 71 M 6113 ( $0.5 \%$ ) and 71M6203 ( $0.1 \%$ ) remote sensors. Refer to the 71M6xxx Data Sheet for details.

### 4.5.2 Temperature Coefficients for the 71M6543F and 71M6543G

The equations provided below for calculating TC1 and TC2 apply to the 71M6543F and 71M6543G. In order to obtain TC1 and TC2, the MPU reads TRIMT[7:0] (I/O RAM 0x2309) and uses the TC1 and TC2 equations provided. PPMC and PPMC2 are then calculated from TC1 and TC2, as shown. The resulting tracking of the reference voltage (VREF) is within $\pm 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$.

$$
\begin{gathered}
T C 1\left(\mu V /{ }^{\circ} \mathrm{C}\right)=275-4.95 \cdot \text { TRIMT } \\
\operatorname{TC} 2\left(\mu V /{ }^{\circ} C^{2}\right)=-0.557-0.00028 \cdot \text { TRIMT } \\
P P M C=22.4632 \cdot T C 1 \\
P P M C 2=1150.116 \cdot T C 2
\end{gathered}
$$

See 4.5.4 and 4.5.5 below for further temperature compensation details.

### 4.5.3 Temperature Coefficients for the 71M6xx3

Refer to the 71M6xxx Data sheet for the equations that are applicable to each 71 M 6 xx 3 part number and the corresponding temperature coefficients.

### 4.5.4 Temperature Compensation for VREF and Shunt Sensors

This section discusses metrology temperature compensation for the meter designs where current shunt sensors are used in conjunction with the 71M6xx3 remote isolated sensors, as shown in Figure 31.

Sensors that are directly connected to the 71M6543 are affected by the voltage variation in the 71M6543 VREF due to temperature. On the other hand, shunt sensors that are connected to 71M6xx3 remote sensor are affected by the VREF in the 71M6xx3. The VREF in both the 71M6543 and 71M6xx3 can be compensated digitally using a second-order polynomial function of temperature. The 71M6543 and 71M6xx3 feature temperature sensors for the purposes of temperature compensating their corresponding VREF. The compensation computations must be implemented in MPU firmware.

Referring to Figure 31, the VADC8 (VA), VADC9 (VB) and VADC10 (VC) voltage sensors are always directly connected to the 71M6543. Thus, the precision of the voltage sensors is primarily affected by VREF in the 71M6543. The temperature coefficient of the resistors used to implement the voltage dividers for the voltage sensors (see Figure 27) determine the behavior of the voltage division ratio with respect to temperature. It is recommended to use resistors with low temperature coefficients, while forming the entire voltage divider using resistors belonging to the same technology family, in order to minimize the temperature dependency of the voltage division ratio. The resistors must also have suitable voltage ratings.

The 71M6543 also may have one local current shunt sensor that is connected directly to it via the IADC0IADC1 input pins, and therefore this local current sensor is also affected by the VREF in the 71M6543. The shunt current sensor resistance has a temperature dependency, which also may require compensation, depending on the required accuracy class.

The IADC2-IADC3, IADC4-IADC5 and IADC6-IADC7 current sensors are isolated by the 71M6xx3 and depend on the VREF of the 71M6xx3, plus the variation of the corresponding remote shunt current sensor with temperature.
The MPU has the responsibility of computing the necessary sample gain compensation values required for each sensor channel based on the sensed temperature. Maxim provides demonstration code that implements the GAIN_ADJx compensation equation shown below. The resulting GAIN_ADJx values are stored by the MPU in five CE RAM locations GAIN_ADJ0-GAIN_ADJ5 (CE RAM 0x40-0x $\overline{4} 4$ ). The demonstration code thus provides a suitable implementation of temperature compensation, but other methods are possible in MPU firmware by utilizing the on-chip temperature sensors while storing the sample gain adjustment results in the CE RAM GAIN_ADJx storage locations for use by the CE. The demonstration code maintains five separate sets of $\overline{P P M C}$ and $P P M C 2$ coefficients and computes five separate GAIN_ADJx values based on the sensed temperature using the equation below:

$$
G A I N_{-} A D J x=16385+\frac{10 \cdot T E M P_{-} X \cdot P P M C^{14}}{2^{14}}+\frac{100 \cdot T E M P_{-} X^{2} \cdot P P M C 2}{2^{23}}
$$

The GAIN_ADJx values stored by the MPU in CE RAM are used by the CE to gain adjust (i.e., multiply) the sample in each corresponding sensor channel. A GAIN_ADJx value of 16,384 (i.e., $2^{14}$ )corresponds to unity gain, while values less than 16,384 attenuate the samples and values greater than 16,384 amplify the samples.

In the above equation, TEMP_X is the deviation from nominal or calibration temperature expressed in multiples of $0.1^{\circ} \mathrm{C}$. The 10 x and 100 x factors seen in the above equation are due to $0.1^{\circ} \mathrm{C}$ scaling of $T E M P \quad X$. For example, if the calibration (reference) temperature is $22^{\circ} \mathrm{C}$ and the measured temperature is $27^{\circ} \overline{\mathrm{C}}$, then $10^{*}$ TEMP $X=(27-22) \times 10=50$ (decimal), which represents a $+5^{\circ} \mathrm{C}$ deviation from $22^{\circ} \mathrm{C}$. In the demonstration code, TEMP $X$ is calculated in the MPU from the STEMP [10:0] temperature sensor reading using the equation provided below and is scaled in $0.1^{\circ} \mathrm{C}$ units. See 2.5 .571 M 6543 Temperature Sensor on page 53 for the equation to calculate temperature in degrees ${ }^{\circ} \mathrm{C}$ from the STEMP [10:0] value.
Table 66 shows the five GAIN_ADJx equation output storage locations and the voltage or current sensor channels for which they compensate for the 1 Local / 3 Remote configuration shown in Figure 31.

Table 66: GAIN_ADJn Compensation Channels (Figure 2, Figure 31, Table 1)

| Gain Adjustment Output | CE RAM Address | Sensor Channel(s) <br> (pin names) | Compensation For: |
| :---: | :---: | :---: | :---: |
| $G A I N_{-} A D J 0$ | $0 \times 40$ | VADC8 (VA) <br> VADC9 (VB) <br> VADC10 (VC) | VREF in 71M6543 and Voltage Divider <br> Resistors |
| $G A I N_{-} A D J 1$ | $0 \times 41$ | IADC0-IADC1 | VREF in 71M6543 and Shunt <br> (Neutral Current) |
| $G A I N_{-} A D J 2$ | $0 \times 42$ | IADC2-IADC3 | VREF in 71M6xx3 and Shunt <br> (Phase A) |
| $G A I N_{-} A D J 3$ | $0 \times 43$ | IADC4-IADC5 | VREF in 71M6xx3 and Shunt |
| (Phase B) |  |  |  |

In the demonstration code, the shape of the temperature compensation second-order parabolic curve is determined by the values stored in the PPMC ( $1^{\text {st }}$ order coefficient) and PPMC2 ( $2^{\text {nd }}$ order coefficient), which are typically setup by the MPU at initialization time from values that are stored in EEPROM.
To disable temperature compensation in the demonstration code, PPMC and PPMC2 are both set to zero for each of the five GAIN_ADJx channels. To enable temperature compensation, the PPMC and PPMC2 coefficients are set with values that match the expected temperature variation of the shunt current sensor (if required) and the corresponding VREF voltage reference (summed together).

The shunt sensor requires a second order polynomial compensation which is determined by the PPMC and PPMC2 coefficients for the corresponding current measurement channel. The corresponding VREF voltage reference also requires the $P P M C$ and $P P M C 2$ coefficients to match the second order temperature behavior of the voltage reference. The PPMC and PPMC2 values associated with the shunt and with the corresponding VREF are summed together to obtain the compensation coefficients for a given current-sensing channel (i.e., the $1^{\text {st }}$ order PPMC coefficients are summed together, and the $2^{\text {nd }}$ order PPMC2 coefficients are summed together).
In the 71M6543F and 71M6543G, the required VREF compensation coefficients PPMC and PPMC2 are calculated from readable on-chip non-volatile fuses (see 4.5.2 Temperature Coefficients for the 71 M 6543 F ). These coefficients are designed to achieve $\pm 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$ for VREF in the 71 M 6543 F and 71M6543G. PPMC and PPMC2 coefficients are similarly calculated for the 71M6xx3 remote sensor (see 4.5.3 Temperature Coefficients for the 71M6xx3).

For the current channels, to determine the PPMC and PPMC2 coefficients for the shunt current sensors, the designer must either know the average temperature curve of the shunt from its manufacturer's data sheet or obtain these coefficients by laboratory characterization of the shunt used in the design.

### 4.5.5 Temperature Compensation of VREF and Current Transformers

This section discusses metrology temperature compensation for meter designs where Current Transformer (CT) sensors are used, as shown in Figure 32.
Sensors that are directly connected to the 71M6543 are affected by the voltage variation in the 71M6543 VREF due to temperature. The VREF in the 71M6543 can be compensated digitally using a secondorder polynomial function of temperature. The 71M6543 features a temperature sensor for the purposes of temperature compensating its VREF. The compensation computations must be implemented in MPU firmware and written to the corresponding GAIN_ADJx CE RAM location.
Referring to Figure 32, the VADC8 (VA), VADC9 (VB) and VADC10 (VC) voltage sensors are directly connected to the 71M6543. Thus, the precision of the voltage sensors is primarily affected by VREF in the 71M6543. The temperature coefficient of the resistors used to implement the voltage dividers for the voltage sensors (see Figure 27) determine the behavior of the voltage division ratio with respect to temperature. It is recommended to use resistors with low temperature coefficients, while forming the entire voltage divider using resistors belonging to the same technology family, in order to minimize the temperature dependency of the voltage division ratio. The resistors must also have suitable voltage ratings.

The Current Transformers are directly connected to the 71M6543 and are therefore primarily affected by the VREF temperature dependency in the 71M6543. For best performance, it is recommended to use the
differential signal conditioning circuit, as shown in Figure 29, to connect the CTs to the 71M6543. Current transformers may also require temperature compensation. The copper wire winding in the CT has dc resistance with a temperature coefficient, which makes the voltage delivered to the burden resistor temperature dependent, and the burden resistor also has a temperature coefficient. Thus, each CT sensor channel needs to compensate for the 71M6543 VREF, and optionally for the temperature dependency of the CT and its burden resistor depending on the required accuracy class.

The MPU has the responsibility of computing the necessary sample gain compensation values required for each sensor channel based on the sensed temperature. Maxim provides demonstration code that implements the $G A I N_{-} A D J x$ compensation equation shown below. The resulting $G A I N \_A D J x$ values are stored by the MPU in five CE RAM locations GAIN_ADJ0-GAIN_ADJ5 (CE RAM 0x40-0x44). The demonstration code thus provides a suitable implementation of temperature compensation, but other methods are possible in MPU firmware by utilizing the on-chip temperature sensor while storing the sample gain adjustment results in the CE RAM GAIN_ADJn storage locations. The demonstration code maintains five separate sets of PPMC and PPMC2 coefficients and computes five separate GAIN_ADJn values based on the sensed temperature using the equation below:

$$
G A I N_{-} A D J x=16385+\frac{10 \cdot T E M P_{-} X \cdot P P M C}{2^{14}}+\frac{100 \cdot T E M P_{-} X^{2} \cdot P P M C 2}{2^{23}}
$$

The GAIN_ADJn values stored by the MPU in CE RAM are used by the CE to gain adjust (i.e., multiply) the sample in each corresponding sensor channel. A GAIN_ADJx value of 16,384 (i.e., $2^{14}$ )corresponds to unity gain, while values less than 16,384 attenuate the samples and values greater than 16,384 amplify the samples.

In the above equation, TEMP_X is the deviation from nominal or calibration temperature expressed in multiples of $0.1^{\circ} \mathrm{C}$. The 10 x and 100 x factors seen in the above equation are due to $0.1^{\circ} \mathrm{C}$ scaling of $T E M P \quad X$. For example, if the calibration (reference) temperature is $22^{\circ} \mathrm{C}$ and the measured temperature is $27^{\circ} \mathrm{C}$, then $10^{*}$ TEMP_X $=(27-22) \times 10=50$ (decimal), which represents a $+5^{\circ} \mathrm{C}$ deviation from $22^{\circ} \mathrm{C}$. In the demonstration code, TEMP_X is calculated in the MPU from the STEMP[10:0] temperature sensor reading using the equation provided below and is scaled in $0.1^{\circ} \mathrm{C}$ units. See 2.5 .571 M 6543 Temperature Sensor on page 53 for the equation to calculate temperature in ${ }^{\circ} \mathrm{C}$ from the STEMP [10:0] reading.

Table 67 shows the five GAIN_ADJX equation output storage locations and the voltage or current measurements for which they compensate.

Table 67: GAIN_ADJx Compensation Channels (Figure 3, Figure 32, Table 2)

| Gain Adjustment Output | CE RAM Address | Sensor Channel(s) <br> (pin names) | Compensation For: |
| :---: | :---: | :---: | :---: |
| $G A I N_{-} A D J 0$ | $0 \times 40$ | VADC8 (VA) <br> VADC9 (VB) <br> VADC10 (VC) | VREF in 71M6543 and Voltage Divider <br> Resistors |
| $G A I N_{-} A D J 1$ | $0 \times 41$ | IADC0-IADC1 | VREF in 71M6543, CT and Burden <br> Resistor (Neutral Current) |
| $G A I N_{-} A D J 2$ | $0 \times 42$ | IADC2-IADC3 | VREF in 71M6543, CT and Burden <br> Resistor (Phase A) |
| $G A I N_{-} A D J 3$ | $0 \times 43$ | IADC4-IADC5 | VREF in 71M6543, CT and Burden <br> Resistor (Phase B) |
| $G A I N_{-} A D J 4$ | $0 \times 44$ | IADC6-IADC7 | VREF in 71M6543, CT and Burden <br> Resistor (Phase C) |

In the demonstration code, the shape of the temperature compensation second-order parabolic curve is determined by the values stored in the PPMC ( $1^{\text {st }}$ order coefficient) and PPMC2 ( $2^{\text {nd }}$ order coefficient), which are typically setup by the MPU at initialization time from values that are stored in EEPROM.

To disable temperature compensation in the demonstration code, PPMC and PPMC2 are both set to zero for each of the five GAIN_ADJx channels. To enable temperature compensation, the PPMC and PPMC2 coefficients are set with values that match the expected VREF temperature variation and optionally the
corresponding sensor circuit (i.e., the CT and burden resistor for current channels or the resistor divider network for the voltage channels).

In the 71M6543F and 71M6543G, the required VREF compensation coefficients PPMC and PPMC2 are calculated from readable on-chip non-volatile fuses (see 4.5.2Temperature Coefficients for the 71 M 6543 F ). These coefficients are designed to achieve $\pm 40 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$ for VREF.

### 4.6 Connecting $I^{2} C$ EEPROMs

$I^{2} \mathrm{C}$ EEPROMs or other $I^{2} \mathrm{C}$ compatible devices should be connected to the DIO pins SEGDIO2 and SEGDIO3, as shown in Figure 33.
Pullup resistors of roughly $10 \mathrm{k} \Omega$ to V 3 P 3 D (to ensure operation in BRN mode) should be used for both SDCK and SDATA signals. The DIO_EEX (I/O RAM 0x2456[7:6]) field must be set to 01 in order to convert the DIO pins SEGDIO2 and SEGDIO3 to $I^{2} \mathrm{C}$ pins SCL and SDATA.


Figure 33: $I^{2} \mathrm{C}$ EEPROM Connection

### 4.7 Connecting Three-Wire EEPROMs

$\mu$ Wire EEPROMs and other compatible devices should be connected to the DIO pins SEGDIO2 and SEGDIO3, as described in 2.5.11 EEPROM Interface on page 65.

### 4.8 UARTO (TX/RX)

The UARTO RX pin should be pulled down by a $10 \mathrm{k} \Omega$ resistor and additionally protected by a 100 pF ceramic capacitor, as shown in Figure 34.


Figure 34: Connections for UARTO

### 4.9 Optical Interface (UART1)

The OPT_TX and OPT_RX pins can be used for a regular serial interface (by connecting a RS_232 transceiver for example), or they can be used to directly operate optical components (for example, an infrared diode and phototransistor implementing a FLAG interface). Figure 35 shows the basic connections for UART1. The OPT_TX pin becomes active when the control field OPT_TXE (I/O RAM 0x2456[3:2]) is set to 01 .

The polarity of the OPT_TX and OPT_RX pins can be inverted with the configuration bits, OPT_TXINV (I/O RAM 0x2456[0]) and OPT_RXINV (I/O RAM 0x2457[1]), respectively.
The OPT_TX output may be modulated at 38 kHz when system power is present. Modulation is not available in BRN mode. The OPT_TXMOD bit (I/O RAM 0x2456[1]) enables modulation. The duty cycle is controlled by OPT_FDC[1:0] (I/O RAM 0x2457[5:4]), which can select $50 \%, 25 \%, 12.5 \%$, and $6.25 \%$ duty cycle. A $6.25 \%$ duty cycle means OPT_TX is low for $6.25 \%$ of the period. The OPT_RX pin uses digital signal thresholds. It may need an analog filter when receiving modulated optical signals.

With modulation, an optical emitter can be operated at higher current than nominal, enabling it to increase the distance along the optical path.

If operation in BRN mode is desired, the external components should be connected to V3P3D. However, it is recommended to limit the current to a few mA.


Figure 35: Connection for Optical Components

### 4.10 Connecting the Reset Pin

Even though a functional meter does not necessarily need a reset switch, it is useful to have a reset pushbutton for prototyping as shown in Figure 36, left side. The RESET signal may be sourced from V3P3SYS (functional in MSN mode only), V3P3D (MSN and BRN modes), or VBAT (all modes, if a battery is present), or from a combination of these sources, depending on the application.

For a production meter, the RESET pin should be protected by the by the external components shown in Figure 36, right side. R1 should be in the range of $100 \Omega$ and mounted as closely as possible to the IC.

Since the 71 M 6543 generates its own power-on reset, a reset button or circuitry, as shown in Figure 36, is only required for test units and prototypes.


Figure 36: External Components for the RESET Pin: Push-Button (Left), Production Circuit (Right)

### 4.11 Connecting the Emulator Port Pins

Even when the emulator is not used, small shunt capacitors to ground ( 22 pF ) should be used for protection from EMI as illustrated in Figure 37. Production boards should have the ICE_E pin connected to ground.


Figure 37: External Components for the Emulator Interface

### 4.12 Flash Programming

### 4.12.1 Flash Programming via the ICE Port

Operational or test code can be programmed into the flash memory using either an in-circuit emulator or the Flash Programmer Module (TFP-2) available from Maxim. The flash programming procedure uses the E_RST, E_RXTX, and E_TCLK pins.

### 4.12.2 Flash Programming via the SPI Port

It is possible to erase, read and program the flash memory of the 71 M 6543 via the SPI port. See 2.5.12 for a detailed description.

### 4.13 MPU Demonstration Code

All application-specific MPU functions mentioned in 4 Application Information are featured in the demonstration C source code supplied by Maxim. The code is available as part of the Demonstration Kit for the 71M6543. The Demonstration Kits come with the 71M6543 preprogrammed with demonstration firmware and mounted on a functional sample meter Demo Board. The Demo Boards allow for quick and efficient evaluation of the IC without having to write firmware or having to supply an in-circuit emulator (ICE).

### 4.14 Crystal Oscillator

The oscillator of the 71 M 6543 drives a standard 32.768 kHz watch crystal. The oscillator has been designed specifically to handle these crystals and is compatible with their high impedance and limited power handling capability. The oscillator power dissipation is very low to maximize the lifetime of any battery backup device attached to the VBAT_RTC pin.

Board layouts with minimum capacitance from XIN to XOUT require less battery current. Good layouts have XIN and XOUT shielded from each other and also keep the XIN and XOUT traces short and away from LCD and digital signals.


Since the oscillator is self-biasing, an external resistor must not be connected across the crystal.

### 4.15 Meter Calibration

Once the 71M6543 energy meter device has been installed in a meter system, it must be calibrated. A complete calibration includes the following:

- Establishment of the reference temperature for factory calibration (e.g., typically $22^{\circ} \mathrm{C}$ ).
- Calibration of the metrology section, i.e., calibration for errors of the current sensors, voltage dividers and signal conditioning components as well as of the internal reference voltage (VREF) at the reference temperature (e.g., typically $22^{\circ} \mathrm{C}$ ).
- Calibration of the oscillator frequency using the RTCA_ADJ register (I/O RAM 0x2504).

The metrology section can be calibrated using the gain and phase adjustment factors accessible to the CE. The gain adjustment is used to compensate for tolerances of components used for signal conditioning, especially the resistive components. Phase adjustment is provided to compensate for phase shifts introduced by the current sensors or by the effects of reactive power supplies.
Due to the flexibility of the MPU firmware, any calibration method, such as calibration based on energy, or current and voltage can be implemented. It is also possible to implement segment-wise calibration (depending on current range).
The 71M6543 supports common industry standard calibration techniques, such as single-point (energy-only), multi-point (energy, Vrms, Irms), and auto-calibration.

Maxim provides a calibration spreadsheet file to facilitate the calibration process. Contact your Maxim representative to obtain a copy of the latest calibration spreadsheet file for the 71M6543.

## 5 Firmware Interface

### 5.1 I/O RAM Map -Functional Order

In Table 68 and Table 69, unimplemented (U) and reserved (R) bits are shaded in light gray. Unimplemented bits are ident Unimplemented bits have no memory storage, writing them has no effect, and reading them always returns zero. Reservec an ' $R$ ', and must always be written with a zero. Writing values other than zero to reserved bits may have undesirable side $\epsilon$ avoided. Non-volatile bits are shaded in dark gray. Non-volatile bits are backed-up during power failures if the system inclu to the VBAT pin.

The I/O RAM locations listed in Table 68 have sequential addresses to facilitate reading by the MPU (e.g., in order to verif) I/O RAM locations are usually modified only at boot-up. The addresses shown in Table 68 are an alternative sequential ad from Table 69 which are used throughout this document. For instance, EQU[2:0] can be accessed at I/O RAM 0x2000[7:5] 0x2106[7:5].

Table 68: I/O RAM Map - Functional Order, Basic Configuration

| Name | Addr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | B |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CE6 | 2000 | EQU[2:0] |  |  | $U$ | CHOP_E[1:0] |  | RT |
| CE5 | 2001 | $U$ |  |  | SUM_SAMPS[12:8] |  |  |  |
| CE4 | 2002 | SUM_SAMPS[7:0] |  |  |  |  |  |  |
| CE3 | 2003 | $U$ | CE_LCTN[6/5:0] |  |  |  |  |  |
| CE2 | 2004 | PLS_MAXWIDTH[7:0] |  |  |  |  |  |  |
| CE1 | 2005 | PLS_INTERVAL[7:0] |  |  |  |  |  |  |
| CE0 | 2006 | DIFF6_E | DIFF4_E | DIFF2_E | DIFF0_E | RFLY_DIS |  |  |
| RCE0 | 2007 | CHOPR[1:0] |  | RMT6_E | RMT4_E | RMT2_E |  | $M U$ |
| RTMUX | 2008 | $U$ | TMUXR4[2:0] |  |  | $U$ |  | MU |
| FOVRD | 2009 | $U$ | $U$ | $R$ | $U$ | $U$ | $U$ |  |
| MUX5 | 200A | MUX_DIV[3:0] |  |  |  | MUX10_SEL |  |  |
| MUX4 | 200B | MUX9_SEL |  |  |  | MUX8_SEL |  |  |
| MUX3 | 200C | MUX7_SEL |  |  |  | MUX6_SEL |  |  |
| MUX2 | 200D | MUX5_SEL |  |  |  | MUX4_SEL |  |  |
| MUX1 | 200E | MUX3_SEL |  |  |  | $M U X 2$ _SEL |  |  |
| MUX0 | 200F | MUX1_SEL |  |  |  | MUX0_SEL |  |  |
| TEMP | 2010 | TEMP_BSEL | TEMP_PWR | OSC_COMP | TEMP_BAT | TBYTE_BUSY | TEMP |  |
| LCD0 | 2011 | $L C D \_E$ | LCD_MODE[2:0] |  |  | LCD_ALLCOM | LCD_Y |  |
| LCD1 | 2012 | LCD_VMODE[1:0] |  |  | LCD_BLNKMAP23[5:0] |  |  |  |


| Name | Addr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | B |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LCD2 | 2013 | LCD_BAT | $R$ | LCD_BLNKMAP22[5:0] |  |  |  |  |
| LCD_MAP6 | 2014 | LCD_MAP[55:48] |  |  |  |  |  |  |
| LCD_MAP5 | 2015 | LCD_MAP[47:40] |  |  |  |  |  |  |
| LCD_MAP4 | 2016 | LCD_MAP[39:32] |  |  |  |  |  |  |
| LCD_MAP3 | 2017 | $L C D$ _MAP[31:24] |  |  |  |  |  |  |
| LCD_MAP2 | 2018 | $L C D \_M A P[23: 16]$ |  |  |  |  |  |  |
| LCD_MAP1 | 2019 | LCD_MAP[15:8] |  |  |  |  |  |  |
| LCD_MAP0 | 201A | LCD_MAP[7:0] |  |  |  |  |  |  |
| DIO_R5 | 201B | $U$ | $U$ | $U$ | $U$ | $U$ |  | DIO_ |
| DIO_R4 | 201C | $U$ | DIO_R11[2:0] |  |  | $U$ |  | DIO |
| DIO_R3 | 201D | $U$ | DIO_R9[2:0] |  |  | $U$ |  | DIO |
| DIO_R2 | 201E | $U$ | DIO_R7[2:0] |  |  | $U$ |  | DIO |
| DIO_R1 | 201F | $U$ | DIO_R5[2:0] |  |  | $U$ |  | DIO |
| DIO_R0 | 2020 | $U$ | DIO_R3[2:0] |  |  | $U$ |  | DIO |
| DIO0 | 2021 | DIO_EEX[1:0] |  | $U$ | $U$ | OPT_TXE[1:0] |  | OPT |
| DIO1 | 2022 | DIO_PW | DIO_PV | $O P T_{-} F D C[1: 0]$ |  | $U$ | OPT_RXDIS | $O P T$ |
| DIO2 | 2023 | DIO_PX | DIO_PY | $U$ | $U$ | $U$ | $U$ |  |
| INT1_E | 2024 | $E X_{-} E E X$ | EX_XPULSE | $E X_{-} Y P U L S E$ | $E X_{-} R T C T$ | $U$ | EX_RTC1M | $E X$ |
| INT2_E | 2025 | $E X$ _SPI | EX_WPULSE | $E X_{-}$VPULSE |  |  |  |  |
| WAKE_E | 2026 |  |  |  | $E W \_R X$ | $E W$ _PB | EW_DIO4 | $E W$ |
| SFMM | 2080 | SFMM[7:0]* |  |  |  |  |  |  |
| SFMS | 2081 | SFMS[7:0]* |  |  |  |  |  |  |

## Notes:

*SFMM and SFMS are accessible only through the SPI slave port. See 2.5.1.1 Flash Memory for details.

## 71M6543F/71M6543G Data Sheet

Table 69 lists bits and registers that may have to be accessed on a frequent basis. Reserved bits have lighter gray backgr bits have a darker gray background.

Table 69: I/O RAM Map - Functional Order


| Name | Addr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | E |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LCD_MAP2 | 2409 |  | LCD_MAP[23:16] |  |  |  |  |  |
| LCD_MAP1 | 240A |  | LCD_MAP[15:8] |  |  |  |  |  |
| LCD_MAP0 | 240B |  | LCD_MAP[7:0] |  |  |  |  |  |
| LCD4 | 240C | U | U | U | U | U | LCD_RST | $L C D$ |
| LCD_DAC | 240D | U | $U$ | U | LCD_DAC[4:0] |  |  |  |
| SEGDIO0 | 2410 | $U$ | $U$ |  | LCD_SEG0[5:0] |  |  |  |
| $\ldots$ | $\ldots$ | $U$ | $U$ |  | ... |  |  |  |
| SEGDIO15 | 241F | $U$ | $U$ |  | LCD_SEG15[5:0] |  |  |  |
| SEGDIO16 | 2420 | $U$ | $U$ |  | LCD_SEGDIO16[5:0] |  |  |  |
| ... | ... | $U$ | $U$ |  | ... |  |  |  |
| SEGDIO45 | 243D | $U$ | U |  | LCD_SEGDIO45[5:0] |  |  |  |
| SEGDIO46 | 243E | $U$ | U |  | LCD_SEG46[5:0] |  |  |  |
| ... | $\ldots$ | $U$ | $U$ |  | ... |  |  |  |
| SEGDIO50 | 2442 | $U$ | $U$ |  | LCD_SEG50[5:0] |  |  |  |
| SEGDIO51 | 2443 | $U$ | $U$ |  | LCD_SEGDIO51[5:0] |  |  |  |
| ... | ... | $U$ | $U$ |  | ... |  |  |  |
| SEGDIO55 | 2447 | $U$ | $U$ |  | LCD_SEGDIO55[5:0] |  |  |  |


| DIO_R5 | 2450 | U | $R$ | $R$ | $R$ | $U$ |  | DIO_I |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DIO_R4 | 2451 | U | DIO_R11[2:0] |  |  | U |  | DIO_1 |
| DIO_R3 | 2452 | U | DIO_R9[2:0] |  |  | U |  | DIO |
| DIO_R2 | 2453 | $U$ | DIO_R7[2:0] |  |  | $U$ |  | DIO |
| DIO_R1 | 2454 | $U$ | DIO_R5[2:0] |  |  | U |  | DIO |
| DIO_R0 | 2455 | U | DIO_R3[2:0] |  |  | U |  | DIO |
| DIO0 | 2456 | DIO_EEX[1:0] |  | U | $U$ |  | [1:0] | OPT |
| DIO1 | 2457 | DIO_PW | DIO_PV | OPT_FDC[1:0] |  | U | OPT_RXDIS | OPT |
| DIO2 | 2458 | DIO_PX | DIO_PY | $U$ | $U$ | $U$ | $U$ |  |
| NV BITS |  |  |  |  |  |  |  |  |
| SPARENV | 2500 | $U$ | $U$ | U | $U$ | $R$ |  |  |
| FOVRD | 2501 | $U$ | $U$ | $R$ | $U$ | U | $U$ |  |
| TMUX | 2502 | $U$ | $U$ |  |  |  | 5:0] |  |
| TMUX2 | 2503 | U | U | U |  |  | TMUX2[4:0] |  |
| RTC1 | 2504 | $U$ |  |  |  | AD |  |  |

## 71M6xx3 Interface

| Name | Addr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | E |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| REMOTE2 | 2602 | RMT_RD[15:8] |  |  |  |  |  |  |
| REMOTE1 | 2603 | RMT_RD[7:0] |  |  |  |  |  |  |
| RBITS |  |  |  |  |  |  |  |  |
| INT1_E | 2700 | $E X \_E E X$ | EX_XPULSE | EX_YPULSE | EX_RTCT | $U$ | EX_RTC1M | $E X$ |
| INT2_E | 2701 | $E X$ _SPI | EX_WPULSE | EX_VPULSE | $U$ | $U$ | $U$ |  |
| SECURE | 2702 | FLSH_UNLOCK[3:0] |  |  |  | $R$ | FLSH_RDE | $F L S$ |
| Analog0 | 2704 | VREF_CAL | VREF_DIS | PRE_E | $A D C$ _ $E$ | BCURR |  | SPAI |
| VERSION | 2706 | VERSION[7:0] |  |  |  |  |  |  |
| INTBITS | 2707 | $U$ | INT6 | INT5 | INT4 | INT3 | INT2 | $I$ |
| FLAG0 | SFR E8 | $I E \_E E X$ | IE_XPULSE | IE_YPULSE | IE_RTCT | $U$ | IE_RTC1M | $I E$ |
| FLAG1 | SFR F8 | IE_SPI | IE_WPULSE | IE_VPULSE | $U$ | $U$ | $U$ |  |
| STAT | SFR F9 | $U$ | $U$ | $U$ | PLL_OK | $U$ |  | VST |
| REMOTE0 | SFR FC | $U$ | $P E R R$ _RD | PERR_WR | RCMD[4:0] |  |  |  |
| SPI1 | SFR FD | SPI_CMD[7:0] |  |  |  |  |  |  |
| SPIO | 2708 | SPI_STAT[7:0] |  |  |  |  |  |  |
| RCE0 | 2709 | CHOPR[1:0] |  | RMT6_E | RMT4_E | $R M T 2 \_E$ |  | TMUX |
| RTMUX | 270A | $U$ | TMUXR4[2:0] |  |  | $U$ |  | TMUX |
| DIO3 | 270C | $U$ | $U$ | PORT_E | SPI_E | SPI_SAFE | $U$ |  |

NV RAM and RTC

| NVRAMxx | $\begin{aligned} & \hline 2800- \\ & 287 \mathrm{~F} \end{aligned}$ |  | NVRAM[0] - NVRAM[7F] - Direct Access |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| WAKE | 2880 |  | WAKE_TMR[7:0] |  |  |  |  |  |
| STEMP1 | 2881 |  | STEMP[10:3] |  |  |  |  |  |
| STEMP0 | 2882 |  | STEMP[2:0] |  | U | $U$ | $U$ |  |
| BSENSE | 2885 |  | BSENSE[7:0] |  |  |  |  |  |
| LKPADDR | 2887 | LKPAUTOI | LKPADDR[6:0] |  |  |  |  |  |
| LKPDATA | 2888 |  | LKPDAT[7:0] |  |  |  |  |  |
| LKPCTRL | 2889 | $U$ | $U$ | $U$ | U | $U$ | $U$ | $L K$ |
| RTC0 | 2890 | RTC_WR | RTC_RD | $U$ | RTC_FAIL | $U$ | $U$ |  |
| RTC2 | 2892 | RTC_SBSC[7:0] |  |  |  |  |  |  |
| RTC3 | 2893 | $U$ | $U$ | RTC_SEC[5:0] |  |  |  |  |
| RTC4 | 2894 | $U$ | U | RTC_MIN[5:0] |  |  |  |  |
| RTC5 | 2895 | $U$ | U | $U$ | RTC_HR[4:0] |  |  |  |


| Name | Addr | Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | E |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| RTC6 | 2896 | U | U | U | U | U |  | RTC_L |
| RTC7 | 2897 | $U$ | U | U | RTC_DATE[4:0] |  |  |  |
| RTC8 | 2898 | $U$ | $U$ | $U$ | $U$ | RTC_MO[3:0] |  |  |
| RTC9 | 2899 | RTC_YR[7:0] |  |  |  |  |  |  |
| RTC10 | 289B | $U$ | $U$ | $U$ | U | $U$ |  | RTC_1 |
| RTC11 | 289C | RTC_P[13:6] |  |  |  |  |  |  |
| RTC12 | 289D | RTC_P[5:0] |  |  |  |  |  |  |
| RTC13 | 289E | $U$ | $U$ | RTC_TMIN[5:0] |  |  |  |  |
| RTC14 | 289F | $U$ | $U$ | $U$ | RTC_THR[4:0] |  |  |  |
| TEMP | 28A0 | TEMP_BSEL | TEMP_PWR | OSC_COMP | TEMP_BAT | TBYTE_BUSY | TEMP |  |
| WF1 | 28B0 | WF_CSTART | WF_RST | WF_RSTBIT | WF_OVF | WF_ERST | WF_BADVDD |  |
| WF2 | 28B1 | $U$ | $U$ | WF_TMR | $W F_{-} R X$ | $W F_{-} P B$ | WF_DIO4 | WF |
| MISC | 28B2 | SLEEP | LCD_ONLY | WAKE_ARM | $U$ | $U$ | $U$ |  |
| WAKE_E | 28B3 | $U$ | $U$ | $U$ | $E W \_R X$ | $E W \_P B$ | EW_DIO4 | EW |
| WDRST | 28B4 | WD_RST | TEMP_START | $U$ | $U$ | $U$ | $U$ |  |
| MPU PORTS |  |  |  |  |  |  |  |  |
| PORT3 | SFR B0 | DIO_DIR[15:12] |  |  |  | DIO[15:12] |  |  |
| PORT2 | SFR A0 | DIO_DIR[11:8] |  |  |  | DIO[11:8] |  |  |
| PORT1 | SFR 90 | DIO_DIR[7:4] |  |  |  | DIO[7:4] |  |  |
| PORT0 | SFR 80 | DIO_DIR[3:0] |  |  |  | DIO[3:0] |  |  |
| FLASH |  |  |  |  |  |  |  |  |
| ERASE | SFR 94 | FLSH_ERASE[7:0] |  |  |  |  |  |  |
| FLSHCTL | SFR B2 | PREBOOT | SECURE | $U$ | $U$ | FLSH_PEND | FLSH_PSTWR | $F L S H$ |
| FL_BANK | SFR B6 | $U$ | $U$ | $U$ | $U$ | $U$ | $U$ |  |
| PGADR | SFR B7 | FLSH_PGADR[5:0] |  |  |  |  |  |  |
| $I^{2} \mathrm{C}$ |  |  |  |  |  |  |  |  |
| EEDATA | SFR 9E | EEDATA[7:0] |  |  |  |  |  |  |
| EECTRL | SFR 9F | EECTRL[7:0] |  |  |  |  |  |  |

### 5.2 I/O RAM Map - Alphabetical Order

Table 70 lists I/O RAM bits and registers in alphabetical order.
Bits with a write direction (W in column Dir) are written by the MPU into configuration RAM. Typically, they are initially stor copied to the configuration RAM by the MPU. Some of the more frequently programmed bits are mapped to the MPU SFR remaining bits are mapped to the address space $0 \times 2 \mathrm{XXX}$. Bits with R (read) direction can be read by the MPU. Columr describe the bit values upon reset and wake, respectively. No entry in one of these columns means the bit is either read-c NV supply and is not initialized. Write-only bits return zero when they are read.
Locations that are shaded in grey are non-volatile (i.e., battery-backed).
Table 70: I/O RAM Map - Alphabetical Order

| Name | Location | Rst Wk |  | Dir | Description |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $A D C=E$ | 2704[4] | 0 | 0 | R/W | Enables ADC and VREF. When disabled, reduces bias current. |  |  |  |
| ADC_DIV | 2200[5] | 0 | 0 | R/W | $A D C \_D I V$ controls the rate of the ADC and FIR clocks. <br> The ADC_DIV setting determines whether MCK is divided by 4 or 8 $\begin{aligned} & 0=\mathrm{MCK} / 4 \\ & 1=\mathrm{MCK} / 8 \end{aligned}$ <br> The resulting ADC and FIR clock is as shown below. |  |  |  |
|  |  |  |  |  |  |  | PLL_FAST $=0$ | PLL_FAST |
|  |  |  |  |  |  | MCK | 6.291456 MHz | 19.660800 N |
|  |  |  |  |  |  | ADC_DIV $=0$ | 1.572864 MHz | 4.9152 MF |
|  |  |  |  |  |  | ADC_DIV $=1$ | 0.786432 MHz | 2.4576 MF |
| BCURR | 2704[3] | 0 | 0 | R/W | Connects a $100 \mu \mathrm{~A}$ load to the battery selected by TEMP_BSEL. |  |  |  |
| BSENSE[7:0] | 2885[7:0] | - | - | R | The result of the battery measurement. See 2.5.7 71M6543 Battery Monitor on page 56. |  |  |  |
| CE_E | 2106[0] | 0 | 0 | R/W | CE enable. |  |  |  |
| CE_LCTN[6:0] | 2109[6:0] | 31 | 31 | R/W | CE program location. The starting address for the CE program is (CE_LCTN[6:0], 2109[6:0] for 71M6543G) <br> (CE_LCTN[5:0], 2109[5:0] for 71M6543F) |  |  |  |
| $\begin{aligned} & \text { CHIP_ID[15:8] } \\ & \text { CHIP_ID[7:0] } \end{aligned}$ | $\begin{aligned} & 2300[7: 0] \\ & 2301[7: 0] \end{aligned}$ | 0 | 00 | RR | These bytes contain the chip identification as shown below. |  |  |  |
|  |  |  |  |  |  | CHIP_ID[15:8] | CHIP_ID[7:0] |  |
|  |  |  |  |  | 71M6543F | $0 \times 04$ |  |  |
|  |  |  |  |  | 71M6543G | $0 \times 05$ | $0 \times 10$ |  |
| CHOP_E[1:0] | 2106[3:2] | 0 | 0 | R/W | Chop enable for the reference bandgap circuit. The value of CHO rising edge of the internal MUXSYNC signal according to the value $00=$ toggle $^{1} \quad 01=$ positive $\quad 10=$ reversed $\quad 11=$ toggle ${ }^{1}$ except at the mux sync edge at the end of an accumulation interva |  |  |  |


| Name | Location |  |  | Dir | Description |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| CHOPR [1:0] | 2709[7:6] | 00 | 00 | R/W | The CHOP settings for the remote sensor. $00=$ Auto chop. Change every MUX frame. <br> 01 = Positive <br> $10=$ Negative <br> 11 = Auto chop (same as 00) |  |  |
| DIFFO_E | 210C[4] | 0 | 0 | R/W | Enables IADC0-IADC1 differential configuration. |  |  |
| DIFF2_E | 210C[5] | 0 | 0 | R/W | Enables IADC2-IADC3 differential configuration. |  |  |
| DIFF4_E | 210C[6] | 0 | 0 | R/W | Enables IADC4-IADC5 differential configuration. |  |  |
| DIFF6_E | 210C[7] | 0 | 0 | R/W | Enables IADC6-IADC7 differential configuration. |  |  |
| $\begin{aligned} & \hline \text { DIO_R2[2:0] } \\ & \text { DIO_R3[2:0] } \\ & \text { DIO_R4[2:0] } \end{aligned}$ | $\begin{aligned} & 2455[2: 0] \\ & 2455[6: 4] \\ & 2454[2: 0] \end{aligned}$ | 0  <br> 0  <br> 0  <br> 0  <br> 0 - <br> 0 - <br> 0  <br> 0  <br> 0  <br> 0  <br> 0  | - | R/W | Connects PB and dedicated I/O pins DIO2 through DIO11 to intern than one input is connected to the same resource, the MULTIPLE co how they are combined. |  |  |
| DIO_R5[2:0] | 2454[6:4] |  |  |  | DIO_Rx | Resource | MULTIPLE |
| DIO_R6[2:0] | 2453[2:0] |  |  |  | - | NONE | - |
| DIO_R7[2:0] | 2453[6:4] |  |  |  | 1 | Reserved | OR |
| DIO_R8[2:0] | 2452[2:0] |  |  |  | 2 | T0 (Timer0 clock or gate) | OR |
| DIO R10[2:0] | 2451[2:0] |  |  |  | 3 | T1 (Timer1 clock or gate) | OR |
| DIO_R11[2:0] | 2451[6:4] |  |  |  | 4 | 10 interrupt (int0) | OR |
| DIO_RPB[2:0] | 2450[2:0] |  |  |  | 5 | 10 interrupt (int1) | OR |
| DIO_DIR[15:12] <br> DIO_DIR[11:8] <br> DIO_DIR[7:4] <br> DIO_DIR[3:0] | SFR B0[7:4] SFR A0[7:4] SFR 90[7:4] SFR 80[7:4] | F | F | R/W | Programs the direction of the first 16 DIO pins. 1 indicates output not configured as I/O. See DIO_PV and DIO_PW for special optio outputs. See DIO_EEX[1:0] for special option for SEGDIO2 and S the direction of DIO pins above 15 is set by SEGDIOx[I]. See POI up spikes. |  |  |
| $\begin{aligned} & \hline D I O[15: 12] \\ & \text { DIO[11:8] } \\ & \text { DIO[7:4] } \\ & \text { DIO[3:0] } \\ & \hline \end{aligned}$ | SFR B0[3:0] <br> SFR A0[3:0] <br> SFR 90[3:0] <br> SFR 80[3:0] | F | F | R/W | The value on the first 16 DIO pins. Pins configured as LCD read $z$ changes data on pins configured as outputs. Pins configured as writes. Note that the data for DIO pins above 15 is set by $S E G D$ |  |  |


|  | Location | Rst $\mathbf{W k}$ |  |  | Description |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $D I O \_E E X[1: 0]$ | 2456[7:6] | 0 | - | R/W | When set, converts SEGDIO3 and SEGDIO2 to interface with exte SEGDIO2 becomes SDCK and SEGDIO3 becomes bi-directional $L C D$ _MAP [2] and LCD_MAP[3] are cleared. |  |  |  |  |  |  |
|  |  |  |  |  | DIO_EEX[1:0] $)$ Function |  |  |  |  |  |  |
|  |  |  |  |  | 00 |  | Disable EEPROM interface |  |  |  |  |
|  |  |  |  |  | 01 2 |  | 2-Wire EEPROM interface |  |  |  |  |
|  |  |  |  |  | 10 |  | 3-Wire EEPROM interface |  |  |  |  |
|  |  |  |  |  | 11 |  | 3-Wire EEPROM interface with separate DO (SE (SEGDIO8) pins. |  |  |  |  |
| DIO_PV | 2457[6] | 0 | - | R/W | Causes VPULSE to be output on SEGDIO1, if $L C D$ _MAP[1]=0. |  |  |  |  |  |  |
| DIO_PW | 2457[7] | 0 | - | R/W | Causes WPULSE to be output on SEGDIO0, if $L C D_{-} M A P[0]=0$. |  |  |  |  |  |  |
| DIO_PX | 2458[7] | 0 | - | R/W | Causes XPULSE to be output on SEGDIO6, if $L C D_{-} M A P[6]=0$. |  |  |  |  |  |  |
| DIO_PY | 2458[6] | 0 | - | R/W | Causes YPULSE to be output on SEGDIO7, if $L C D$ _ $M A P[7]=0$. |  |  |  |  |  |  |
| EEDATA[7:0] | SFR 9E | 0 | 0 | R/W | Serial EEPROM interface data. |  |  |  |  |  |  |
| EECTRL[7:0] | SFR 9F | 0 | 0 | R/W | Serial EEPROM interface control. |  |  |  |  |  |  |
|  |  |  |  |  | Status <br> Bit Name <br> 7 $E R R O R$ |  | Read/ Write | Reset State | Polarity | Description |  |
|  |  |  |  |  | 7 E ERROR |  | R | 0 | Positive | 1 when an illegal cc |  |
|  |  |  |  |  | 6 BUSY |  | R | 0 | Positive | 1 when serial data |  |
|  |  |  |  |  | 5 | $R X \_A C K$ | R | 1 | Positive | 1 indicates that the |  |
| EQU[2:0] | 2106[7:5] | 0 | 0 | R/W | Specifies the power equation. |  |  |  |  |  |  |
|  |  |  |  |  | EQU[2:0] | Description |  | $\begin{gathered} \text { Element } \\ 0 \end{gathered}$ |  | $\begin{gathered} \text { Element } \\ 1 \end{gathered}$ | $\begin{gathered} \text { Elemen } \\ 2 \end{gathered}$ |
|  |  |  |  |  | 3 | 2 element, 4W, $3 \phi$ Delta |  | $\mathrm{VA}(\mathrm{IA}-\mathrm{IB}) / 2$ |  | 0 | VC IC |
|  |  |  |  |  | 4 | 2 element, 4W,$\qquad$ 3 $\phi$ Wye |  | $\mathrm{VA}(\mathrm{IA}-\mathrm{IB}) / 2$ |  | VB(IC-IB)/2 | 0 |
|  |  |  |  |  | 5* | 3 element, 4W, $3 \phi$ Wye |  | VA IA |  | VB IB | VC IC |
|  |  |  |  |  | Note: <br> *The available CE codes implements only equation 5 . Contact your local Maxim CE code for equation 3 and 4 . |  |  |  |  |  |  |


| Name | Location | Rst | Wk | Dir | Description |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| EX_XFER | 2700[0] | 0 | 0 | R/W | Interrupt enable bits. These bits enable the XFER_BUSY, the RTC bits are set by hardware and cannot be set by writing a 1 . The bits 0 . Note that if one of these interrupts is to enabled, its correspondi bit must also be set. See 2.4.8 Interrupts, for details. |  |
| EX_RTC1S | 2700[1] |  |  |  |  |  |
| EX_RTC1M | 2700[2] |  |  |  |  |  |
| EX_RTCT | 2700[3] |  |  |  |  |  |
| EX_SPI | 2701[7] |  |  |  |  |  |
| $E X \_E E X$ | 2700[7] |  |  |  |  |  |
| EX_XPULSE | 2700[6] |  |  |  |  |  |
| EX_YPULSE | 2700[5] |  |  |  |  |  |
| EX_WPULSE | 2701[6] |  |  |  |  |  |
| EX_VPULSE | 2701[5] |  |  |  |  |  |
| $E W \_D I O 4$ | 28B3[2] | 0 | - | R/W | Connects SEGDIO4 to the WAKE logic and permits SEGDIO4 risir This bit has no effect unless DIO4 is configured as a digital input. |  |
| $E W$ DIO52 | 28B3[1] | 0 | - | R/W | Connects SEGDIO52 to the WAKE logic and permits SEGDIO52 r This bit has no effect unless SEGDIO52 is configured as a digital i |  |
| $E W_{-}$DIO55 | 28B3[0] | 0 | - | R/W | Connects SEGDIO55 to the WAKE logic and permits the SEGDIO awaken the part. This bit has no effect unless SEGDIO55 is confic input. |  |
| $E W \_P B$ | 28B3[3] | 0 | - | R/W | Connects PB to the WAKE logic and permits a high level on PB to is always configured as an input. |  |
| $E W_{-} R X$ | 28B3[4] | 0 | - | R/W | Connects RX to the WAKE logic and permits the RX rising edge to See the WAKE description in 3.4 Wake on Timer for de-bounce iss |  |
| FIR_LEN[1:0] | 210C[2:1] | 0 | 0 | R/W | Determines the number of ADC cycles in the ADC decimation FIR $P L L_{-} F A S T=1$ : |  |
|  |  |  |  |  |  | ADC Cycles |
|  |  |  |  |  |  | 141 |
|  |  |  |  |  |  | 288 |
|  |  |  |  |  |  | 384 |
|  |  |  |  |  |  |  |
|  |  |  |  |  | FIR_LEN[1:0] | ADC Cycles |
|  |  |  |  |  | 00 | 135 |
|  |  |  |  |  | 01 | 276 |
|  |  |  |  |  | 10 | Not Allowed |
|  |  |  |  |  | The ADC LSB size and full-scale values depend on the FIR_LEN[ Table 81 on page 122 and Table 103 on page 141 for details. |  |



| Name | Location | Rst Wk |  | Dir | Description |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| FLSH_PWE | SFR B2[0] | 0 | 0 | R/W | Program Write Enable <br> $0=$ MOVX commands refer to External RAM Space, normal operatio 1 = MOVX @DPTR,A moves A to External Program Space (Flash) This bit is automatically reset after each byte written to flash. Write inhibited when interrupts are enabled. |  |  |
| FLSH_RDE | 2702[2] | - | - | R | Indicates that the flash may be read by ICE or SPI slave. FLSH_RDE |  |  |
| FLSH_UNLOCK[3:0] | 2702[7:4] | 0 | 0 | R/W | Must be a 2 to enable any flash modification. See the description more details. |  |  |
| FLSH_WRE | 2702[1] | - | - | R | Indicates that the flash may be written through ICE or SPI slave po |  |  |
| IE XFER <br> IE_RTCIS <br> IE_RTCIM <br> IE_RTCT <br> IE SPI <br> IE-EEX <br> IE_XPULSE <br> IE YPULSE <br> IE_WPULSE <br> IE VPULSE | SFR E8[0] <br> SFR E8[1] <br> SFR E8[2] <br> SFR E8[3] <br> SFR F8[7] <br> SFR E8[7] <br> SFR E8[6] <br> SFR E8[5] <br> SFR F8[6] <br> SFR F8[5] | 0 | 0 | R/W | Interrupt flags for external interrupts 2 and 6. These flags monitor and int2 interrupts (external interrupts to the MPU core). These fla hardware and must be cleared by the software interrupt handler. T $0 x C 0[1]$ ) and IEX6 (SFR 0xC0[5]) interrupt flags are automatically c core when it vectors to the interrupt handler. IEX2 and IEX6 must b zero to their corresponding bit positions in SFR 0xC0, while writing positions that are not being cleared. |  |  |
| INTBITS | 2707[6:0] | - | - | R | Interrupt inputs. The MPU may read these bits to see the input to INT0, INT1, up to INT6. These bits do not have any memory and for debug use. |  |  |
| LCD_ALLCOM | 2400[3] | 0 | - | R/W | Configures SEG/COM bits as COM. Has no effect on pins whose |  |  |
| LCD_BAT | 2402[7] | 0 | - | R/W | Connects the LCD power supply to VBAT in all modes. |  |  |
| LCD_BLNKMAP23[5:0] LCD_BLNKMAP22[5:0] | $\begin{aligned} & \hline 2401[5: 0] \\ & 2402[5: 0] \\ & \hline \end{aligned}$ | 0 | - | R/W | Identifies which segments connected to SEG23 and SEG22 shoulc blink. The most significant bit corresponds to COM5, the least signific |  |  |
| LCD_CLK[1:0] | 2400[1:0] | 0 | - | R/W | Sets the LCD clock frequency. Note: $\mathrm{f}_{\text {xtaL }}=32768 \mathrm{~Hz}$ |  |  |
|  |  |  |  |  |  | LCD_CLK[1:0] | LCD Clock Frequency |
|  |  |  |  |  |  | 00 | $\mathrm{fxtaL} / 2{ }^{\text {g }}$ |
|  |  |  |  |  |  | 01 | $\mathrm{f}_{\text {xtaL }} / 2{ }^{8}$ |
|  |  |  |  |  |  | 10 | $\mathrm{f}_{\text {xTAL }} / 2{ }^{\prime}$ |
|  |  |  |  |  |  | 11 | $\mathrm{f}_{\text {xtaL }} / 2{ }^{6}$ |



71M6543F


| Name | Location | Rst | Wk | Dir | Description |
| :--- | :---: | :---: | :--- | :--- | :--- | :--- |
| $M U X 8_{-} S E L[3: 0]$ | $2101[3: 0]$ | 0 | 0 | R/W | Selects which ADC input is to be converted during time slot 8. |


| Name | Location | Rst |  | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| PLL_OK | SFR F9[4] | 0 | 0 | R | Indicates that the clock generation PLL is settled. |
| PLL_FAST | 2200[4] | 0 | 0 | R/W | Controls the speed of the PLL and MCK. $\begin{aligned} & 1=19.66 \mathrm{MHz}(X T A L * 600) \\ & 0=6.29 \mathrm{MHz}(\text { XTAL * 192) } \end{aligned}$ |
| PLS_MAXWIDTH[7:0] | 210A[7:0] | FF | FF | R/W | PLS_MAXWIDTH[7:0] determines the maximum width of the pulse $P L S_{-} I N V=0$ or high-going pulse if $P L S_{-} I N V=1$ ). The maximum puls $\left(2^{*} P L S_{-} M A X W I D T H[7: 0]+1\right)^{*} \mathrm{~T}_{1}$. Where $\mathrm{T}_{1}$ is PLS_INTERVAL[7:0] clock cycles. If PLS_INTERVAL[7:0] $=0$ or PLS_MAXWIDTH[7:0] width checking is performed and the output pulses have $50 \%$ duty VPULSE and WPULSE. |
| PLS_INTERVAL[7:0] | 210B[7:0] | 0 | 0 | R/W | PLS_INTERVAL[7:0] determines the interval time between pulses. output pulses is PLS_INTERVAL[7:0]*4 in units of CK_FIR clock cycl PLS_INTERVAL[7:0] = 0 , the FIFO is not used and pulses are output issues them. PLS_INTERVAL[7:0] is calculated as follows: <br> PLS_INTERVAL[7:0] = Floor ( Mux frame duration in CK_FIR cycles / CE frame / 4 ) <br> For example, since the 71M6543 CE code is written to generate 6 pu interval, when the FIFO is enabled (i.e., PLS_INTERVAL[7:0] $\neq 0$ ) an duration is 1950 CK_FIR clock cycles, PLS_INTERVAL[7:0] should b Floor $(1950 / 6 / 4)=81$ so that the five pulses are evenly spaced integration interval and the last pulse is issued just prior to the end 2.3.6.2 VPULSE and WPULSE. |
| PLS_INV | 210C[0] | 0 | 0 | R/W | Inverts the polarity of WPULSE, VARPULSE, XPULSE, and YPUL pulses are active low. When inverted, they become active high. |
| PORT_E | 270C[5] | 0 | 0 | R/W | Enables outputs from the SEGDIO0-SEGDIO15 pins. PORT_E $=0$ output pulse that occurs when SEGDIO0-SEGDIO15 are reset on |
| PRE_E | 2704[5] | 0 | 0 | R/W | Enables the 8x pre-amplifier. |
| PREBOOT | SFRB2[7] | - | - | R | Indicates that pre-boot sequence is active. |
| RCMD[4:0] | SFR FC[4:0] | 0 | 0 | R/W | When the MPU writes a non-zero value to $R C M D$, the 71 M 6543 iss the appropriate remote sensor. When the command is complete, RCMD. |
| RESET | 2200[3] | 0 | 0 | W | When set, writes a one to $W F_{-}$RSTBIT and then causes a reset. |
| $R F L Y_{-} D I S$ | 210C[3] | 0 | 0 | R/W | Controls how the 71M6543 drives the power pulse for the 71M6xx) power pulse is driven high and low. When cleared, it is driven high circuit fly-back interval. |


| Name | Location | Rst | Wk | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\begin{aligned} & R M T 2_{-} E \\ & R M T 4_{-} E \\ & R M T 6_{-} \end{aligned}$ | $\begin{aligned} & \hline 2709[3] \\ & 2709[4] \\ & 2709[5] \end{aligned}$ | 0 | 0 | R/W | Enables the remote interface. |
| RMT_RD[15:8] RMT_RD[7:0] | $\begin{aligned} & \text { 2602[7:0] } \\ & 2603[7: 0] \end{aligned}$ | 0 | 0 | R | Response from remote read request. |
| RTCA_ADJ[6:0] | 2504[6:0] | 40 | - | R/W | Register for analog RTC frequency adjustment. |
| RTC_FAIL | 2890[4] | 0 | 0 | R | Indicates that a count error has occurred in the RTC and that the ti This bit can be cleared by writing a 0 . |
| $\begin{aligned} & R T C_{-} P[16: 14] \\ & R T C_{-} P[13: 6] \\ & R T C_{-} P[5: 0] \end{aligned}$ | $\begin{aligned} & \text { 289B[2:0] } \\ & \text { 289C[7:0] } \\ & \text { 289D[7:2] } \end{aligned}$ | $\begin{aligned} & 4 \\ & 0 \\ & 0 \end{aligned}$ | $\begin{aligned} & \hline 4 \\ & 0 \\ & 0 \end{aligned}$ | R/W | RTC adjust. See 2.5.4 Real-Time Clock (RTC). $0 \times 0 F F B F \leq R T C \_P \leq 0 \times 10040$ <br> Note: $R T C_{-} P[16: 0]$ and $R T C \_Q[1: 0]$ form a single 19-bit RTC adjus |
| RTC_Q[1:0] | 289D[1:0] | 0 | 0 | R/W | RTC adjust. See 2.5.4 Real-Time Clock (RTC). <br> Note: $R T C_{-} P[16: 0]$ and $R T C \_Q[1: 0]$ form a single 19-bit RTC adjus |
| $R T C \_R D$ | 2890[6] | 0 | 0 | R/W | Freezes the RTC shadow register so it is suitable for MPU reads. read, it returns the status of the shadow register: $0=$ up to date, $1=$ frozen. |
| RTC_SBSC[7:0] | 2892[7:0] | - | - | R | Time remaining since the last 1 second boundary. LSB=1/128 sec |
| RTC_TMIN[5:0] | 289E[5:0] | 0 | - | R/W | The target minutes register. See RTC_THR below. |
| RTC_THR[4:0] | 289F[4:0] | 0 | - | R/W | The target hours register. The RTC_T interrupt occurs when $R T C_{-} M$ equal to RTC_TMIN[5:0] and RTC_HR[4:0] becomes equal to RTC_TI |
| RTC_WR | 2890[7] | 0 | 0 | R/W | Freezes the RTC shadow register so it is suitable for MPU writes. cleared, the contents of the shadow register are written to the RTC RTC clock ( $\sim 1 \mathrm{kHz}$ ). When $R T C \_W R$ is read, it returns 1 as long as continues to return one until the RTC counter actually updates. |
| RTC_SEC[5:0] <br> RTC_MIN[5:0] <br> RTC_HR[4:0] <br> RTC_DAY[2:0] <br> RTC_DATE[4:0] <br> RTC_MO[3:0] <br> RTC_YR[7:0] | 2893[5:0] $2894[5: 0]$ $2895[4: 0]$ $2896[2: 0]$ $2897[4: 0]$ $2898[3: 0]$ $2899[7: 0]$ | $\begin{aligned} & - \\ & - \\ & - \\ & - \\ & - \\ & - \\ & - \end{aligned}$ | - - - - - - - | R/W | The RTC interface. These are the year, month, day, hour, minute an for the RTC. The RTC is set by writing to these registers. Year 00 a by 4 are defined as a leap year. <br> Each write operation to one of these registers must be preceded $b$ |
| RTM_E | 2106[1] | 0 | 0 | R/W | Real Time Monitor enable. When 0, the RTM output is low. |


| Name | Location | Rst $\mathbf{W k}$ |  | Dir | Description |
| :---: | :---: | :---: | :---: | :---: | :---: |
| RTM0[9:8] | 210D[1:0] | 0 | 0 |  |  |
| RTM0[7:0] | 210E[7:0] | 0 | 0 |  | Four RTM probes. Before each CE code pass, the values of these |
| RTM1[7:0] | 210F[7:0] | 0 | 0 | R/W | output on the RTM pin. The RTM registers are ignored when $R T M$ |
| RTM2[7:0] | 2110[7:0] | 0 | 0 |  | RTM0 is 10 bits wide. The others assume the upper two bits are 0 |
| RTM3[7:0] | 2111[7:0] | 0 | 0 |  |  |
| SECURE | SFR B2[6] | 0 | 0 | R/W | Inhibits erasure of page 0 and flash memory addresses above the $b$ as defined by CE LCTN[6/5:0]. Also inhibits the reading of flash men devices (SPI or ICE port). |
| SLEEP | 28B2[7] | 0 | 0 | W | Puts the 71 M 6543 to sleep. Ignored if system power is present. T when the Wake timer times out, when push button is pushed, or w returns. |
| SPI_CMD | SFR FD[7:0] | - | - | R | SPI command. 8-bit command from the bus master. |
| $S P I_{-} E$ | 270C[4] | 1 | 1 | R/W | SPI port enable. Enables the SPI interface on pins SEGDIO36 - S that $L C D$ _MAP [36-39] $=0$. |
| SPI_SAFE | 270C[3] | 0 | 0 | R/W | Limits SPI writes to SPI_CMD and a 16 byte region in DRAM. No permitted. |
| SPI_STAT | 2708[7:0] | 0 | 0 | R | SPI_STAT contains the status results from the previous SPI transac <br> Bit 7-71M6543 ready error: the 71M6543 was not ready to read the previous command. <br> Bit 6 - Read data parity: This bit is the parity of all bytes read from previous command. Does not include the SPI_STAT byte. <br> Bit 5 - Write data parity: This bit is the overall parity of the bytes w in the previous command. It includes CMD and ADDR bytes. <br> Bit 4:2 - Bottom 3 bits of the byte count. Does not include ADDF One, two, and three byte instructions return 111. <br> Bit 1 - SPI FLASH mode: This bit is zero when the TEST pin is zer <br> Bit 0 - SPI FLASH mode ready: Used in SPI FLASH mode. Indicates tha receive another write instruction. |
| $\begin{aligned} & \text { STEMP[10:3] } \\ & \text { STEMP[2:0] } \end{aligned}$ | $\begin{aligned} & 2881[7: 0] \\ & 2882[7: 5] \end{aligned}$ | $\begin{aligned} & - \\ & - \end{aligned}$ | - | $\begin{aligned} & \mathrm{R} \\ & \mathrm{R} \end{aligned}$ | The result of the temperature measurement. |
| SUM_SAMPS[12:8] <br> SUM_SAMPS[7:0] | $\begin{aligned} & 2107[4: 0] \\ & 2108[7: 0] \end{aligned}$ | 0 | 0 | R/W | The number of multiplexer cycles (frames) per XFER_BUSY interruf 8191 cycles. |
| TBYTE_BUSY | 28A0[3] | 0 | 0 | R | Indicates that hardware is still writing the 0x28A0 byte. Additional locked out while it is one. Write duration could be as long as 6 ms |
| $\begin{aligned} & \text { TEMP_22[10:8] } \\ & \text { TEMP_22[7:0] } \\ & \hline \end{aligned}$ | $\begin{aligned} & \text { 230A[2:0] } \\ & \text { 230B[7:0] } \end{aligned}$ | 0 | - | R | Storage location for STEMP[10:0] at 22C. STEMP[10:0] is an 11 bi |



| Name | Location | Rst | Wk | Dir | Description |  |
| :--- | :---: | :---: | :---: | :---: | :--- | :--- |
|  |  |  |  |  |  |  |

### 5.3 CE Interface Description

### 5.3.1 CE Program

The CE performs the precision computations necessary to accurately measure power. These computations include offset cancellation, phase compensation, product smoothing, product summation, frequency detection, VAR calculation, sag detection and voltage phase measurement. All data computed by the CE is dependent on the selected meter equation as given by EQU[2:0] (I/O RAM 0x2106[7:5]).

The standard CE program is supplied by Maxim as a data image that can be merged with the MPU operational code for meter applications. Typically, this CE program covers most applications and does not need to be modified. Other variations of CE code may be available from Maxim. The description in this section applies to CE code revision CE43A01A.

### 5.3.2 CE Data Format

All CE words are 4 bytes. Unless specified otherwise, they are in 32-bit two's complement format ( $-1=0 \times F F F F F F F F$ ). Calibration parameters are defined in flash memory (or external EEPROM) and must be copied to CE data memory by the MPU before enabling the CE. Internal variables are used in internal CE calculations. Input variables allow the MPU to control the behavior of the CE code. Output variables are outputs of the CE calculations. The corresponding MPU address for the most significant byte is given by $0 \times 0000+4 \times$ CE_address and by $0 \times 0003+4 \times$ CE_address for the least significant byte.

### 5.3.3 Constants

Constants used in the CE Data Memory tables are:

- Sampling Frequency: $F_{S}=32768 \mathrm{~Hz} / 15=2184.53 \mathrm{~Hz}$.
- $F_{0}$ is the fundamental frequency of the mains phases.
- IMAX is the external rms current corresponding to 250 mV pk at each IADC input.
- VMAX is the external rms voltage corresponding to 250 mV pk at each VADC input.
- NACC, the accumulation count for energy measurements is SUM_SAMPS[12:0] (I/O RAM 0x2107[4:0], $0 \times 2108$ [7:0]). This value also resides in SUM PRE (CE RAM 0x2 $\overline{3}$ ) where it is used for phase angle measurement.
- The duration of the accumulation interval for energy measurements is $S U M_{-} S A M P S[12: 0] / F_{s}$.
- X is a gain constant of the pulse generators. Its value is determined by PULSE_FAST and PULSE_SLOW (see Table 76).
- Voltage LSB $=$ VMAX * $7.879810^{-9} \mathrm{~V}$.
- $\mathrm{VMAX}=600 \mathrm{~V}, \mathrm{IMAX}=208 \mathrm{~A}$, and $\mathrm{kH}=3.2 \mathrm{~Wh} /$ pulse are assumed as default settings.

The system constants IMAX and VMAX are used by the MPU to convert internal digital quantities (as used by the CE) to external, i.e. metering quantities. Their values are determined by the scaling of the voltage and current sensors used in an actual meter. The LSB values used in this document relate digital quantities at the CE or MPU interface to external meter input quantities. For example, if a SAG threshold of 80 V peak is desired at the meter input, the digital value that should be programmed into $\operatorname{SAG}$ THR (CE $R A M 0 \times 24$ ) would be $80 \mathrm{~V} / S A G_{-} T H R_{\text {LSB }}$, where $S A G_{-} T H R_{\text {LSB }}$ is the LSB value in the description of SAG_THR (Table 77).
The parameters $E Q U[2: 0], C E \_E$, and $S U M_{-} S A M P S[12: 0]$, essential to the function of the CE are stored in I/O RAM (see 5.2 for details).

### 5.3.4 Environment

Before starting the CE using the CE_E bit (I/O RAM 0x2106[0]), the MPU has to establish the proper environment for the CE by implementing the following steps:

- Locate the CE code in Flash memory using CE_LCTN[5:0] (I/O RAM 0x2109[5:0]) in the 71M6543F and CE_LCTN[6:0] (I/O RAM 0x2109[6:0]) in the 71M6543G.
- Load the CE data into RAM.
- Establish the equation to be applied in EQU[2:0] (I/O RAM 0x2106[7:5]).
- Establish the accumulation period and number of samples in SUM_SAMPS[12:0] (I/O RAM 0x2107[4:0], 0x2108[7:07).
- Establish the number of cycles per ADC multiplexer frame (MUX_DIV[3:0] (I/O RAM 0x2100[7:4])).
- Apply proper values to MUXn_SEL, as well as proper selections for DIFFn_E (I/O RAM 0x210C[ ]) and RMTn_E (I/O RAM 0x2709[] in order to configure the analog inputs.
- Initialize any MPU interrupts, such as CE_BUSY, XFER_BUSY, or the power-failure detection interrupt.

When different CE codes are used, a different set of environment parameters need to be established. The exact values for these parameters are listed in the Application Notes and other documentation which accompanies the CE code.

Operating CE codes with environment parameters deviating from the values specified by Maxim leads to unpredictable results.

Typically, there are fifteen 32768 Hz cycles per ADC multiplexer frame (see 2.2.2). This means that the product of the number of cycles per frame and the number of conversions per frame must be 14 (allowing for one settling cycle). The default configuration is FIR_LEN $=01, I / O$ RAM 0x210C[1] (two cycles per conversion) and $M U X$ _DIV [3:0] $=7$ ( 7 conversions per multiplexer cycle).

Sample configurations can be copied from Demo Code provided by Maxim with the Demo Kits.

### 5.3.5 CE Calculations

Referring to Table 71, The MPU selects the desired equation by writing the EQU[2:0] (I/O RAM 0x2106[7:5]).

Table 71: CE EQU[2:0] Equations and Element Input Mapping

| $\begin{gathered} \text { EQU } \\ {[2: 0] *} \end{gathered}$ | Watt \& VAR Formula (WSUM/VARSUM) | $\begin{gathered} \text { WOSUM/ } \\ \text { VAROSUM } \end{gathered}$ | $\begin{gathered} \text { WISUM/ } \\ \text { VARISUM } \end{gathered}$ | $\begin{gathered} \text { W2SUM/ } \\ \text { VAR2SUM } \end{gathered}$ | $\begin{aligned} & \text { IOSQ } \\ & \text { SUM } \end{aligned}$ | $\begin{aligned} & \text { IISQ } \\ & \text { SUM } \end{aligned}$ | $\begin{aligned} & \text { I2SQ } \\ & \text { SUM } \end{aligned}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 2 | VA*IA + VB*IB <br> (2-element, 3-W, 3申 Delta) | VA * IA | VB * IB | N/A | IA | IB | - |
| 3 | $\begin{array}{\|l} \hline \text { VA*(IA-IB)/2 + VC*IC } \\ (2 \text { element, } 4 \mathrm{~W} 3 \phi \text { Delta) } \\ \hline \end{array}$ | VA*(IA-IB)/2 | - | VC*IC | IA-IB | IB | IC |
| 4 | VA*(IA-IB)/2 + VB*(IC-IB)/2 (2 element, 4W 3 ${ }^{2}$ Wye) | VA*(IA-IB)/2 | VB*(IC-IB)/2 | - | IA-IB | IC-IB | IC |
| 5 | VA*IA + VB*IB + VC*IC (3 element, 4W 3 ${ }^{\mathrm{W}} \mathrm{Wye}$ ) | VA*IA | VB*IB | VC*IC | IA | IB | IC |

Note:

* Only $E Q U[2: 0]=5$ is supported by the currently available CE code versions for the 71M6543. Contact your local Maxim representative for CE codes that support equations 2, 3 and 4.


### 5.3.6 CE Front-End Data (Raw Data)

Access to the raw data provided by the AFE is possible by reading CE RAM addresses 0 through A, as shown in Table 72. In the expression MUXn_SEL[3:0] = x, ' $n$ ' refers to the multiplexer frame time slot number and ' $x$ ' refers to the desired ADC input number or ADC handle (i.e., IADC0 to VADC10, or simply 0 to 10 decimal).
The 71 M 6543 can support up to eleven sensor inputs, when all the current sensors are configured as single-ended inputs. If all the current sensor inputs are configured as differential (recommended for best performance), the number of input sensor channels is reduced to seven (i.e., IADC0-1, IADC2-3, IADC4-5, IADC6-7, VADC8, VADC9 and VADC10). The MUXn_SEL[3:0] column in Table 72 shows the $M U X n \_S E L$ handles for the various sensor input pins. For example, if differential mode is enabled via control bit DIFF0_E = 1 (I/O RAM 0x210C[4]), then the IADC0-IADC1 input pins are combined together to form a single differential input and the corresponding $M U X n \_S E L$ handle is 0 (i.e., handle 1 is then unused). Similarly, the CE RAM location column provides the CE RAM address where the corresponding sample data is stored. Continuing with the same example, if $D I F F 0_{-} E=1$, the corresponding $C E R A M$ location where the samples for the IADC0-IADC1 differential input are stored is CE RAM 0.
The IADC2-3, IADC4-5 and IADC6-7 inputs can be configured as direct-connected sensors (i.e., directly connected to the 71 M 6543 ) or as remote sensors (i.e., using a 71 M 6 xx 3 Isolated Sensor). For example, if the IADC2-3 remote sensor is disabled by RMT2_E $=0$ (I/O RAM 0x2007[3]) and differential mode is enabled by $D I F F 2$ _ $E=1$ (I/O RAM $0 \times 210 C[4]$ ), then IADC2-IADC3 form a differential input with a MUXn_SEL handle of 2 (i.e., handle 3 is then unused), and the corresponding samples are stored in CE RAM location 2 . If the remote sensor enable bit $R M T 2_{-} E=1, D I F F 2_{-} E=\mathrm{x}$ (don't care), then the $M U X n_{-} S E L$ handle is not required (i.e., the sensor is not connectē to the 71 M 6543 multiplexer, so MUXn $S E L$ does not apply), and the samples corresponding to this remote differential IADC2-IADC3 input are stored in CE RAM location 2 directly by the digital isolation interface (see Figure 2).
The voltage sensor inputs (VADC8, VADC9 and VADC10) are always single-ended inputs and cannot be configured as remotes, so they do not have any associated configuration bits. VADC8 (VA) has a $M U X n \_S E L$ handle value of 8 , and its samples are stored in CE RAM location 8 . VADC9 (VB) has a $M U X n_{1} S E L$ handle value of 9 and its samples are stored in CE RAM location 9. VADC10 (VC) has a $M U X n^{\prime} S E L$ handle value of 10 and its samples are stored in CE RAM location 10.

Table 72: CE Raw Data Access Locations

| Pin | MUXn_SEL Handle |  |  |  | CE RAM Location |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | DIFF0_E |  |  |  | DIFF0_E |  |  |  |
|  | 0 | 1 |  |  | 0 | 1 |  |  |
| IADC0 | 0 | 0 |  |  | 0 | 0 |  |  |
| IADC1 | 1 |  |  |  | 1 |  |  |  |
|  | RMT2_E, DIFF2_E |  |  |  | RMT2_E, DIFF2_E |  |  |  |
|  | 0,0 | 0,1 | 1,0 | 1,1 | 0,0 | 0,1 | 1,0 | 1,1 |
| IADC2 | 2 | 2 | - | - | 2 | 2 | 2* | 2* |
| IADC3 | 3 |  |  |  | 3 |  |  |  |
|  | RMT4_E, DIFF4_E |  |  |  | RMT4_E, DIFF4_E |  |  |  |
|  | 0,0 | 0,1 | 1,0 | 1,1 | 0,0 | 0,1 | 1,0 | 1,1 |
| IADC4 | 4 | 4 | - | - | 4 | 4 | 4* | 4* |
| IADC5 | 5 |  |  |  | 5 |  |  |  |
|  | RMT6_E, DIFF6_E |  |  |  | RMT6_E, DIFF6_E |  |  |  |
|  | 0,0 | 0,1 | 1,0 | 1,1 | 0,0 | 0,1 | 1,0 | 1,1 |
| IADC6 | 6 | 6 | - | - | 6 | 6 | 6* | 6* |
| IADC7 | 7 |  |  |  | 7 |  |  |  |
|  | There are no configuration bits for VADC8, 9, 10 |  |  |  |  |  |  |  |
| VADC8 (VA) | 8 |  |  |  | 8 |  |  |  |
| VADC9 (VB) | 9 |  |  |  | 9 |  |  |  |  |  |
| VADC10 (VC) | 10 |  |  |  | 10 |  |  |  |  |  |

[^0]
### 5.3.7 CE Status and Control

The CE Status Word is useful for generating early warnings to the MPU (Table 73). It contains sag warnings for phase $A, B$, and $C$, as well as $F 0$, the derived clock operating at the fundamental input frequency. The MPU can read the CE status word at every CE_BUSY interrupt. Since the CE_BUSY interrupt occurs at the sample rate (i.e., 2520.6 Hz for $M U X_{-} D I V[3: 0]=6$ or 2184.5 Hz for $M U X_{-} D I V[3: 0]=7$ ), it is desirable to minimize the computation required in the interrupt handler of the MPU.

Table 73: CESTATUS Register

| CE Address | Name | Description |
| :---: | :---: | :--- |
| $0 \times 80$ | CESTATUS | See description of CESTATUS bits in Table 74. |

CESTATUS provides information about the status of voltage and input AC signal frequency, which are useful for generating an early power fail warning to initiate necessary data storage. CESTATUS represents the status flags for the preceding CE code pass (CE_BUSY interrupt). The significance of the bits in CESTATUS is shown in Table 74.

Table 74: CESTATUS Bit Definitions

| CESTATUS <br> bit | Name | Description |
| :---: | :---: | :--- |
| $31: 4$ | Not Used | These unused bits are always zero. |
| 3 | $F 0$ | $F 0$ is a square wave at the exact fundamental input frequency. |
| 2 | $S A G_{-} C$ | Normally zero. Becomes one when VADC10 (VC) remains below $S A G_{-} T H R$ <br> $(C E R A M$ <br> $($ VC $)$ rises above for $S A G C N T$ samples. Does not return to zero until VADC10 |
| 1 | $S A G_{-} B$ | Normally zero. Becomes one when VADC9 (VB) remains below $S A G_{-} T H R$ <br> for $S A G \_C N T$ samples. Does not return to zero until VADC9 (VB) rises above <br> $S A G \_T H R$. |
| 0 | $S A G_{-} A$ | Normally zero. Becomes one when VADC8 (VA) remains below $S A G_{-} T H R$ <br> for $S A G \_C N T$ samples. Does not return to zero until VADC8 (VA) rises above <br> $S A G \_T H R$. |

The CE is initialized by the MPU using CECONFIG (Table 75). This register contains in packed form SAG_CNT, FREQSEL0, FREQSEL1, EXT_PULSE, PULSE_SLOW, and PULSE_FAST. The CECONFIG bit definitions are given in Table 76.

Table 75: CECONFIG Register

| CE Address | Name | Data | Description |
| :---: | :---: | :---: | :--- |
| $0 \times 20$ | $C E C O N F I G$ | $0 \times 0030 D A 20$ | See description of the CECONFIG bits in Table 76. |

The $E X T_{-} T E M P$ bit enables temperature compensation by the MPU, when set to 1 . When 0 , internal (CE) temperature compensation is enabled.

The CE pulse generator can be controlled by either the MPU (external) or CE (internal) variables. Control is by the MPU if $E X T_{-} P U L S E=1$. In this case, the MPU controls the pulse rate by placing values into $A P U L S E W$ and APULSER (CE RAM 0x45 and 0x49). By setting EXT_PULSE $=0$, the CE controls the pulse rate based on WSUM_X (CE RAM 0x84) and VARSUM_X (CE RAM 0x88).

The 71M6543 Demo Code creep function halts both internal and external pulse generation.

Table 76: CECONFIG Bit Definitions (CE RAM 0x20)

| $\underset{\text { bit }}{\substack{\text { CECONFIG }}}$ | Name | Default | Description |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 23 | Reserved | 0 | Reserved (can be used by the MPU to indicate that the $71 \mathrm{M} 6 \times 03$ is being used; CE does not use this). |  |  |  |
| 22 | EXT_TEMP | 0 | When 1, the MPU controls temperature compensation via the GAIN_ADJn (CE RAM 0x40-0x42), when 0 , the CE is in control. |  |  |  |
| 21 | EDGE_INT | 1 | When 1, XPULSE produces a pulse for each zero-crossing of the mains phase selected by FREQSEL[1:0] , which can be used to interrupt the MPU. |  |  |  |
| 20 | SAG_INT | 1 | When 1, activates the YPULSE/SEGDIO7 output when a sag is detected (see 2.5.10) on the phase selected with FREQSEL[1:0]. |  |  |  |
| 19:8 | SAG_CNT | $\begin{gathered} 218 \\ (0 x D A) \end{gathered}$ | The number of consecutive voltage samples below SAG_THR (CE RAM 0x24) before a sag alarm is declared. The default value is equivalent to 100 ms . |  |  |  |
| 7:6 | FREQSEL[1:0] | 0 | FREQSEL[1:0] selects the phase to be used for the frequency monitor, sag detection, the phase-to-phase lag calculation and for the zero crossing counter (MAINEDGE X, CE RAM 0x83). |  |  |  |
|  |  |  | FREQ SEL[1:0] | Phase Selected | Phases Selected |  |
|  |  |  |  |  | PH_AtoB_X | PH_AtoC_X |
|  |  |  | $0{ }^{0}$ | A | A-B | A-C |
|  |  |  | $0 \quad 1$ | B | B-C | B-A |
|  |  |  | 1 0 | C | C-A | C-B |
|  |  |  | 1 1 | Not allowed |  |  |
| 5 | EXT_PULSE | 1 | When zero, causes the pulse generators to respond to internal data. WPULSE $=$ WSUM_X $($ CE RAM 0x84), VPULSE $=V A R S U M-X$ (CE RAM 0x88.) Otherwise, the generators respond to values the MPU places in APULSEW and APULSER (CE RAM 0x45 and 0x49) |  |  |  |
| 4:2 | Reserved | 0 | Reserved. |  |  |  |
| 1 | PULSE_FAST | 0 | When PULSE_FAST = 1, the pulse generator input is increased 16x. When PULSE_SLOW $=1$, the pulse generator input is reduced by a factor of 64 . These two parameters control the pulse gain factor $X$ (see table below). Allowed values are either 1 or 0 . Default is 0 for both $(\mathrm{X}=6)$. |  |  |  |
| 0 | PULSE_SLOW | 0 | PULSE_FAST | PULSE_SLOW | $X$ |  |
|  |  |  | 0 | 0 | $1.5{ }^{*} 2^{2}=$ |  |
|  |  |  | 0 | 1 | $1.5{ }^{*} 2^{-4}=0$. | 375 |
|  |  |  | 1 | 0 | 1.5 * $2^{6}=$ |  |
|  |  |  | 1 | 1 | Do not u |  |

The FREQSEL[1:0] field in CECONFIG (CE RAM 0x20[7:6]) selects the phase that is utilized to generate a sag interrupt. Thus, a SAG_INT event occurs when the selected phase has satisfied the sag event criteria as set by the $S A G_{-} T H R(\bar{C} E R A M 0 \times 24)$ register and the SAG_CNT field in CECONFIG (CE RAM 0x20[19:8]). When the $S A G_{-}^{-} I N T$ bit (CE RAM 0x20[20]) is set to 1, a sag event generates a transition on the YPULSE output. After a sag interrupt, the MPU should change the FREQSEL[1:0] setting to select the other phase, if it is powered. Even though a sag interrupt is only generated on the selected phase, all three phases are simultaneously checked for sag. The presence of power on a given phase can be sensed by directly checking the $S A G_{-} A, S A G_{-} B$ and $S A G_{-} C$ bits in CESTATUS (CE RAM 0x80[0:1]).
The EXT_TEMP bit enables temperature compensation by the MPU, when set to 1 . When 0 , internal (CE) temperature compensation is enabled.

The CE pulse generator can be controlled by either the MPU (external) or CE (internal) variables. Control is by the MPU if the EXT_PULSE bit = 1 (CE RAM 0x20[5]). In this case, the MPU controls the pulse rate (external pulse generation) by placing values into APULSEW and APULSER (CE RAM Ox45 and 0x49). By setting $E X T_{-} P U L S E=0$, the CE controls the pulse rate based on $W S U M_{-} X(C E R A M 0 x 84)$ and $V A R S U M_{-} X(C E$ RAM 0x88).
$\sqrt{ }$ The 71M6543 Demo Code creep function halts both internal and external pulse generation.
Table 77: Sag Threshold, Phase Measurement, and Gain Adjust Control

| CE <br> Address | Name | Default | Description |
| :---: | :---: | :---: | :--- |
| $0 \times 24$ | SAG_THR | $2.39 * 10^{7}$ | The voltage threshold for sag warnings. The default value is <br> equivalent to 80VRMS if VMAX $=600 \mathrm{~V}$. |
| SAG_THR $=\frac{V_{r m s} * \sqrt{2}}{V M A X * 7.8798 * 10^{-9}}$ |  |  |  |
| $0 \times 40$ |  | GAIN_ADJ0 | 16384 |
| $0 \times 41$ | GAIN_ADJ1 | 16384 | The assignments of these gain adjustments depends on the <br> meter design. See 4.5.4 Temperature Compensation for VREF <br> and Shunt Sensors on page 89 or 4.5.5 Temperature <br> Compensation of VREF and Current Transformers on page 90. <br> The default value of 16384 corresponds to unity gain. |
| $0 \times 42$ | GAIN_ADJ2 | 16384 |  |
| $0 \times 43$ | GAIN_ADJ3 | 16384 |  |
| $0 \times 44$ | GAIN_ADJ4 | 16384 |  |

### 5.3.8 CE Transfer Variables

When the MPU receives the XFER_BUSY interrupt, it knows that fresh data is available in the transfer variables. CE transfer variables are modified during the CE code pass that ends with an XFER_BUSY interrupt. They remain constant throughout each accumulation interval. In this data sheet, the names of CE transfer variables always end with _X. The transfer variables can be categorized as:

- Fundamental energy measurement variables
- Instantaneous (RMS) values
- Other measurement parameters


## Fundamental Energy Measurement Variables

Table 78 describes each transfer variable for fundamental energy measurement. All variables are signed 32 -bit integers. Accumulated variables such as WSUM are internally scaled so they have at least $2 x$ margin before overflow when the integration time is one second. Additionally, the hardware does not permit output values to fold back upon overflow.

Table 78: CE Transfer Variables (with Shunts)

| CE <br> Address | Name | Description | Configuration |
| :---: | :---: | :---: | :---: |
| 0x84 | WSUM_X | The signed sum: W0SUM_X+W1SUM_X+W2SUM_X. | Figure 31 (page 86) |
| 0x85 | WOSUM_X | The sum of Wh samples from each wattmeter element.$\mathrm{LSB}_{W}=7.7562^{*} 10^{-13} \text { VMAX * IMAX Wh. }$ |  |
| 0x86 | WISUM_X |  |  |
| 0x87 | W2SUM_X |  |  |
| 0x88 | VARSUM_X | The signed sum: VAR0SUM $X+$ VAR1SUM $X+$ VAR2SUM $X$. |  |
| 0x89 | VAR0SUM_X | The sum of VARh samples from each wattmeter element.$\mathrm{LSB}_{w}=7.7562^{*} 10^{-13} \text { VMAX } * \text { IMAX VARh. }$ |  |
| 0x8A | VARISUM_X |  |  |
| 0x8B | VAR2SUM_X |  |  |

Table 79: CE Transfer Variables (with CTs)

| CE <br> Address | Name | Description | Configuration |
| :---: | :---: | :---: | :---: |
| 0x84 | WSUM_X | The signed sum: W0SUM_X+W1SUM_X+W2SUM_X. | Figure 32 (page 87) |
| 0x85 | W0SUM_X | The sum of Wh samples from each wattmeter element.$\mathrm{LSB}_{w}=1.0856^{*} 10^{-12} \text { VMAX IMAX Wh. }$ |  |
| 0x86 | W1SUM_X |  |  |
| 0x87 | W2SUM_X |  |  |
| 0x88 | VARSUM_X | The signed sum: <br> VAROSUM_X+VARISUM_X+VAR2SUM_X. |  |
| 0x89 | VAR0SUM_X | The sum of VARh samples from each wattmeter element.$\mathrm{LSB}_{w}=1.0856^{*} 10^{-12} \text { VMAX IMAX VARh. }$ |  |
| 0x8A | VARISUM_X |  |  |
| 0x8B | VAR2SUM_X |  |  |

WSUM_ $X$ and VARSUM_ $X$ are the signed sum of Phase-A, Phase-B and Phase-C Wh or VARh values according to the metering equation specified in the control field EQU[2:0] (I/O RAM 0x2106[7:5]).
$W n S U M_{-} X$ is the Wh value accumulated for phase n in the last accumulation interval and can be computed based on the specified LSB value.
For example, with VMAX $=600 \mathrm{~V}$ and IMAX $=208 \mathrm{~A}$, the LSB for $W n S U M_{-} X$ is $0.135 \mu \mathrm{~Wh}$.

### 5.3.8.1 Instantaneous Energy Measurement Variables

InSQSUM_X and VnSQSUM are the squared current and voltage samples acquired during the last accumulation interval. $\bar{I} N S Q S U M_{-} X$ can be used for computing the neutral current.

Table 80: CE Energy Measurement Variables (with Shunts)

| CE <br> Address | Name | Description | Configuration |
| :---: | :---: | :---: | :---: |
| 0x8C | I0SQSUM_X | $\begin{aligned} & \text { Neutral Current: } \\ & \qquad \mathrm{LSB}_{1}=9.9045^{*} 10^{-13 *} \operatorname{IMAX} \mathrm{~A}^{2} \mathrm{~h}\left(P R E_{-} E=0\right) \\ & \mathrm{LSB}_{1}=6.1903125^{*} 10^{-14 *} \mathrm{IMAX}^{2} \mathrm{~A}^{2} \mathrm{~h}(\text { PRE_E=1) }) \end{aligned}$ | Figure 31 (page 86) |
| 0x8D | I1SQSUM_X |  |  |
| 0x8E | I2SQSUM_X | $\mathrm{LSB}_{I}=6.3968 * 10^{-13} *\left(\mathrm{IMAX}^{2}\right) \mathrm{A}^{2} h$ |  |
| 0x8F | I3SQSUM_X |  |  |
| 0x90 | V0SQSUM_X | $\mathrm{LSB}_{\mathrm{V}}=9.4045^{*} 10^{-13 *} \mathrm{VMAX}^{2} \mathrm{~V}^{2} \mathrm{~h}$ |  |
| 0x91 | V1SQSUM_X |  |  |
| 0x92 | V2SQSUM_X |  |  |

Table 81: CE Energy Measurement Variables (with CTs)

| CE <br> Address | Name | Description | Configuration |
| :---: | :---: | :---: | :---: |
| 0x8C | IOSQSUM_X | $\mathrm{LSB}_{\mathrm{I}}=1.0856 * 10^{-12} *\left(\mathrm{IMAX}^{2}\right) \mathrm{A}^{2} h$ | Figure 32 (page 87) |
| 0x8D | I1SQSUM_X |  |  |
| 0x8E | I2SQSUM_X |  |  |
| 0x8F | I3SQSUM_X |  |  |
| 0x90 | V0SQSUM_X | $L S B_{V}=1.0856 * 10^{-12} * V^{\prime} M A X^{2} \mathrm{~V}^{2} h$ |  |
| $0 \times 91$ | V1SQSUM_X |  |  |
| 0x92 | V2SQSUM_X |  |  |

The RMS values can be computed by the MPU from the squared current and voltage samples as follows:

$$
I x_{R M S}=\sqrt{\frac{I x S Q S U M \cdot L S B_{I} \cdot 3600 \cdot F_{S}}{N_{A C C}}} \quad V x_{R M S}=\sqrt{\frac{V x S Q S U M \cdot L S B_{V} \cdot 3600 \cdot F_{S}}{N_{A C C}}}
$$

Other transfer variables include those available for frequency and phase measurement, and those reflecting the count of the zero-crossings of the mains voltage and the battery voltage. These transfer variables are listed in Table 82.

MAINEDGE_X reflects the number of half-cycles accounted for in the last accumulated interval for the AC signal of the phase specified in the FREQSEL[1:0] field of the CECONFIG register (CE RAM 0x20[7:6]). MAINEDGE_X is useful for implementing a real-time clock based on the input AC signal.

Table 82: Other Transfer Variables

| CE <br> Address | Name | Description |
| :---: | :---: | :---: |
| $0 \times 82$ | FREQ_X | $\begin{aligned} & \text { Fundamental frequency: } \mathrm{LSB} \equiv \frac{2184 \mathrm{~Hz}}{2^{32}} \approx 0.509 \cdot 10^{-6} \mathrm{~Hz} \text { (for CT) } \\ & \text { LSB } \equiv \frac{2520 \mathrm{~Hz}}{2^{32}} \approx 0.587 \cdot 10^{-6} \mathrm{~Hz} \text { (for Shunt) } \end{aligned}$ |
| 0x83 | MAINEDGE_X | The number of edge crossings of the selected voltage in the previous accumulation interval. Edge crossings are either direction and are debounced. |
| 0x94 | PH_AtoB_X | Voltage phase lag. The selection of the reference phase is based on FREQSEL[1:0] in the CECONFIG register: <br> If $F R E Q S E L[1: 0]$ selects phase A : Phase lag from A to B . If $F R E Q S E L[1: 0]$ selects phase B : Phase lag from B to C . If $F R E Q S E L[1: 0]$ selects phase C : Phase lag from C to A . <br> Angle in degrees is ( 0 to 360 ): $P H_{-} A t o B_{-} X^{*} 360 / \mathrm{N}_{\text {ACC }}+2.4^{*} 15 / 13$ (for CT) <br> Angle in degrees is ( 0 to 360): PH_AtoB_X* $360 / \mathrm{N}_{\mathrm{AcC}}+2.4$ (for Shunt) |
| 0x95 | PH_AtoC_X | If $F R E Q S E L[1: 0]$ selects phase A: Phase lag from A to C . <br> If $F R E Q S E L[1: 0]$ selects phase B : Phase lag from B to A . <br> If $F R E Q S E L[1: 0]$ selects phase C : Phase lag from C to B . <br> Angle in degrees is ( 0 to 360): PH_AtoC_X* $360 / \mathrm{N}_{\mathrm{ACC}}+4.8^{* 15 / 13 ~(f o r ~ C T) ~}$ <br> Angle in degrees is ( 0 to 360 ): $P H_{\_} A t o C_{\_} X^{*} 360 / \mathrm{N}_{\mathrm{ACC}}+4.8^{*} 15 / 13$ (for Shunt) |

Phase angle measurement accuracy can be increased by writing values > 1 into $V_{-} A N G_{-} C N T$ ( $V$ _ $A N G_{-} C N T$ indicates how many accumulation periods to sum PH _AtoB_X and PH _AtōC_X over. The MPU then has to divide by that number. For standard CE codes that support shunts with remotes, $V_{-} A N G_{-} C N T$ is at CE address $0 \times 53$. For standard CE codes that support shunts with CT, $V_{-} A N G_{-} C N T$ is at CE address $0 \times 55$. For other than standard CE codes, please contact Maxim for information).

### 5.3.9 Pulse Generation

Table 83 describes the CE pulse generation parameters.
The combination of the CECONFIG PULSE_SLOW (CE RAM 0x20[0]) and PULSE_FAST (CE RAM 0x20[1]) bits controls the speed of the pulse rate. The default values of 0 and 0 maintain the original pulse rate given by the Kh equation.
WRATE (CE RAM 0x21) controls the number of pulses that are generated per measured Wh and VARh quantities. The lower WRATE is the slower the pulse rate for measured energy quantity. The metering constant Kh is derived from WRATE as the amount of energy measured for each pulse. That is, if $\mathrm{Kh}=$
$1 \mathrm{~Wh} /$ pulse, a power applied to the meter of 120 V and 30 A results in one pulse per second. If the load is 240 V at 150 A , ten pulses per second are generated.

Control is transferred to the MPU for pulse generation if $E X T_{-} P U L S E=1$ (CE RAM 0x20[5]). In this case, the pulse rate is determined by $A P U L S E W$ and $A P U L S E R$ (CE RAM 0x45 and 0x49). The MPU has to load the source for pulse generation in $A P U L S E W$ and $A P U L S E R$ to generate pulses. Irrespective of the $E X T_{-} P U L S E$ status, the output pulse rate controlled by $A P U L S E W$ and $A P U L S E R$ is implemented by the CE only. By setting $E X T_{-} P U L S E=1$, the MPU is providing the source for pulse generation. If $E X T_{-} P U L S E$ is 0 , WOSUM_X and VAROSUM_X are the default pulse generation sources. In this case, creep cannot be controlled since it is an MPU function.

The maximum pulse rate is $3^{*} F_{S}=7.5 \mathrm{kHz}$.
See 2.3.6.2 VPULSE and WPULSE (page 27) for details on how to adjust the timing of the output pulses.
The maximum time jitter is $1 / 6$ of the multiplexer cycle period (nominally $67 \mu \mathrm{~s}$ ) and is independent of the number of pulses measured. Thus, if the pulse generator is monitored for one second, the peak jitter is 67 ppm . After 10 seconds, the peak jitter is 6.7 ppm . The average jitter is always zero. If it is attempted to drive either pulse generator faster than its maximum rate, it simply outputs at its maximum rate without exhibiting any rollover characteristics. The actual pulse rate, using $W S U M$ as an example, is:

$$
R A T E=\frac{W R A T E \cdot W S U M \cdot F_{S} \cdot X}{2^{46}} H z
$$

where $F_{S}=$ sampling frequency $(2184.53 \mathrm{~Hz}), \mathrm{X}=$ Pulse speed factor derived from the CE variables PULSE_SLOW (CE RAM 0x20[0]) and PULSE_FAST (CE RAM 0x20[1]).

Table 83: CE Pulse Generation Parameters

| CE <br> Address | Name | Default | Description |
| :---: | :---: | :---: | :---: |
| 0x21 | WRATE | 227 | $\mathrm{Kh}=\mathrm{VMAX} \mathrm{IMAX}^{*} \mathrm{~K} /\left(\right.$ WRATE $\left.^{*} \mathrm{~N}_{\text {Acc }}{ }^{*} \mathrm{X}\right)$ Wh/pulse where: <br> $\mathrm{K}=76.3594$ when used with local sensors (CT or shunt) <br> $\mathrm{K}=54.5793$ when used with $71 \mathrm{M} 6 \times x 3$ remote sensors |
| 0x22 | KVAR | 6444 | Scale factor for VAR measurement. |
| 0x23 | SUM_PRE | 2184 | Number of samples per accumulation interval, as specified in SUM SAMPS[12:0], I/O RAM 0x2107[4:0], 0x2108[7:0] ( $\mathrm{N}_{\text {ACC }}$ ). |
| 0x45 | APULSEW | 0 | Wh pulse (WPULSE) generator input to be updated by the MPU when using external pulse generation. The output pulse rate is: APULSEW ${ }^{*} \mathrm{~F}_{\mathrm{S}} * 2^{-32 *}$ WRATE * $X * 2^{-14}$. <br> This input is buffered and can be updated by the MPU during a conversion interval. The change takes effect at the beginning of the next interval. |
| 0x46 | WPULSE_CTR | 0 | Counter for WPULSE output. |
| 0x47 | WPULSE_FRAC | 0 | Unsigned numerator, containing a fraction of a pulse. The value in this register always counts up towards the next pulse. |
| 0x48 | WSUM_ACCUM | 0 | Roll-over accumulator for WPULSE. |
| 0x49 | APULSER | 0 | VARh (VPULSE) pulse generator input. |
| 0x4A | VPULSE_CTR | 0 | Counter for VPULSE output. |
| 0x4B | VPULSE_FRAC | 0 | Unsigned numerator, containing a fraction of a pulse. The value in this register always counts up towards the next pulse. |
| 0x4C | VSUM_ACCUM | 0 | Roll-over accumulator for VPULSE. |

## Other CE Parameters

Table 84 shows the QUANT CE parameters used for suppression of noise due to scaling and truncation effects. The equations for calculating the LSB weight of each QUANT parameter are provided at the bottom of Table 84.

Table 84: CE Parameters for Noise Suppression and Code Version

| CE <br> Address | Name | Default | Description |
| :---: | :---: | :---: | :---: |
| 0x26 | QUANT_IA | 0 | Compensation factors for truncation and noise in current, real energy and reactive energy for phase A. |
| $0 \times 27$ | QUANT_WA | 0 |  |
| 0x28 | QUANT_VARA | 0 |  |
| $0 \times 2 \mathrm{~A}$ | QUANT_IB | 0 | Compensation factors for truncation and noise in current, real energy and reactive energy for phase B. |
| $0 \times 2 \mathrm{~B}$ | QUANT_WB | 0 |  |
| 0x2C | QUANT_VARB | 0 |  |
| 0x2E | QUANT_IC | 0 | Compensation factors for truncation and noise in current, real energy and reactive energy for phase C. |
| 0x2F | QUANT_WC | 0 |  |
| 0x30 | QUANT_VARC | 0 |  |
| 0x31 | QUANT_ID | 0 | Compensation factors for truncation and noise in current for phase D. |

LSB weights for use with the 71M6xx3 isolated sensors:

$$
\begin{aligned}
& Q U A N T_{-} I x_{-} L S B=5.20864 \cdot 10^{-10} \cdot I M A X^{2}\left(\text { Amps }^{2}\right) \\
& Q U A N T_{-} W x_{-} L S B=8.59147 \cdot 10^{-10} \cdot V M A X \cdot I M A X(\text { Watts }) \\
& Q U A N T_{-} \text {VARx_LSB }=8.59147 \cdot 10^{-10} \cdot V M A X \cdot I M A X(\text { Vars })
\end{aligned}
$$

LSB weights for use with Current Transformers (CTs):

$$
\begin{aligned}
& Q U A N T_{-} I x_{-} L S B=5.08656 \cdot 10^{-13} \cdot I M A X^{2}\left(\text { Amps }^{2}\right) \\
& Q U A N T_{-} W x_{-} L S B=1.04173 \cdot 10^{-9} \cdot V M A X \cdot I M A X(\text { Watts }) \\
& Q U A N T_{\_} V A R x_{-} L S B=1.04173 \cdot 10^{-9} \cdot V M A X \cdot I M A X(\text { Vars })
\end{aligned}
$$

### 5.3.10 CE Calibration Parameters

Table 85 lists the parameters that are typically entered to effect calibration of meter accuracy.
Table 85: CE Calibration Parameters

| CE <br> Address | Name | Default | Description |  |
| :---: | :---: | :---: | :---: | :---: |
| $0 \times 10$ | CAL_IA | 16384 | These constants control the gain of their respective channels. The nominal value for each parameter is $2^{14}=16384$. The gain of each channel is directly proportional to its CAL parameter. Thus, if the gain of a channel is $1 \%$ low, CAL should be increased by $1 \%$. |  |
| $0 \times 11$ | CAL_VA | 16384 |  |  |
| $0 \times 13$ | CAL_IB | 16384 |  |  |
| 0x14 | CAL_VB | 16384 |  |  |
| 0x16 | CAL_IC | 16384 |  |  |
| $0 \times 17$ | CAL_VC | 16384 |  |  |
| $0 \times 19$ | CAL_ID | 16384 |  |  |
| 0x12 | PHADJ_A | 0 | These constants control the CT phase compensation. No compensation occurs when PHADJ_X=0. As PHADJ_X is increased, more compensation (lag) is introduced. The range is $\pm 2^{15}-1$. If it is desired to delay the current by the angle $\Phi$, the equations are:$\begin{aligned} & \text { PHADJ_ } X=2^{20} \frac{0.029615 T A N \Phi}{0.1714-0.0168 \cdot \text { TAN } \Phi} \text { at } 60 \mathrm{~Hz} \\ & \text { PHADJ_ } X=2^{20} \frac{0.0206 \cdot \text { TAN } \Phi}{0.1430-0.01226 \cdot \text { TAN } \Phi} \text { at } 50 \mathrm{~Hz} \end{aligned}$ |  |
| $0 \times 15$ | PHADJ_B | 0 |  |  |
| $0 \times 18$ | PHADJ_C | 0 |  |  |
|  |  |  | The shunt delay compensation is obtained using the equation provided below: $D L Y A D J_{-} X=\Delta_{\text {degrees }}\left(1+0.1 \Delta_{\text {degrees }}\right) 2^{14} \frac{2 \pi}{360} \frac{a^{2} \cos ^{2}\left(\frac{2 \pi f}{f_{s}}\right)+2 a b \cos \left(\frac{2 \pi f}{f_{s}}\right)+b}{c \sin \left(\frac{2 \pi f}{f_{s}}\right)}$ <br> where: |  |
| $0 \times 12$ | $D L Y A D J \_A$ | 0 |  |  |
|  |  |  |  |  |
| $0 \times 15$ | DLYADJ_B | 0 |  | $-1$ |
|  |  |  | $c=2 A^{2}+$ <br> $f$ is the | $\left(\frac{2 \pi f}{f_{s}}\right)+2$ <br> equency |
| $0 \times 18$ | DLYADJ_C | 0 | $f$ is the mains frequency $f_{s}$ is the sampling frequency <br> The table below provides the value of $A$ for each channel: |  |
|  |  |  | Channel | Value of $A$ (decimal) |
|  |  |  | $D \quad Y A D J=A$ | $13840$ |
|  |  |  | DLYADJ_B | 11693 |
|  |  |  | DLYADJ_C | 9359 |

## Note:

The current sensor inputs are not assigned to the $\mathrm{A}, \mathrm{B}$ and C phases in a fixed manner. The assignments of phases $\mathrm{A}, \mathrm{B}$ and C depends on how the IADC0-1, IADC2-3, IADC4-5, IADC6-7 current sensing inputs are connected in the meter design. The CE code must be aware of these connections. See Figure 31 and Figure 32 for typical meter configurations. VADC8, VADC9 and VADC10 are assigned to voltage phases VA, VB and VC in a fixed manner, respectively.
The CE addresses listed in this table are assigned to phases $\mathrm{A}, \mathrm{B}$ and C as indicated by their names.

### 5.3.11 CE Flow Diagrams

Figure 38 through Figure 40 show the data flow through the CE in simplified form. Functions not shown include delay compensation, sample interpolation, scaling and the processing of meter equations.


Figure 38: CE Data Flow: Multiplexer and ADC


Figure 39: CE Data Flow: Scaling, Gain Control, Intermediate Variables for one Phase


Figure 40: CE Data Flow: Squaring and Summation Stages

## 6 71M6543 Specifications

This section provides the electrical specifications for the 71M6543. Please refer to the 71M6xxx Data Sheet for the 71M6xx3 electrical specifications, pin-out and package mechanical data.

### 6.1 Absolute Maximum Ratings

Table 86 shows the absolute maximum ratings for the device. Stresses beyond Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only and functional operation at these or any other conditions beyond those indicated under recommended operating conditions (See 6.3) is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltages are with respect to GNDA.

Table 86: Absolute Maximum Ratings

| Voltage and Current |  |
| :---: | :---: |
| Supplies and Ground Pins |  |
| V3P3SYS, V3P3A | -0.5 V to +4.6 V |
| VBAT, VBAT_RTC | -0.5 V to +4.6 V |
| GNDD | -0.1 V to +0.1 V |
| Analog Output Pins |  |
| VREF | $\begin{array}{\|l\|} \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ -0.5 \mathrm{~V} \text { to } \mathrm{V} 3 \mathrm{P} 3 \mathrm{~A}+0.5 \mathrm{~V} \\ \hline \end{array}$ |
| VDD | $\begin{aligned} & -10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ & -0.5 \text { to }+3.0 \mathrm{~V} \\ & \hline \end{aligned}$ |
| V3P3D | $\begin{array}{\|l} \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ -0.5 \mathrm{~V} \text { to } 4.6 \mathrm{~V} \end{array}$ |
| VLCD | $\begin{aligned} & -10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ & -0.5 \mathrm{~V} \text { to }+6 \mathrm{~V} \end{aligned}$ |
| Analog Input Pins |  |
| IADC0, IADC1, IADC2, IADC3, IADC4, IADC5, IADC6, IADC7, VADC8, VADC9 and VADC10 | $\begin{array}{\|l\|} \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA} \\ -0.5 \mathrm{~V} \text { to } \mathrm{V} 3 \mathrm{P} 3 \mathrm{~A}+0.5 \mathrm{~V} \\ \hline \end{array}$ |
| XIN, XOUT | $\begin{aligned} & \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA} \\ & -0.5 \mathrm{~V} \text { to }+3.0 \mathrm{~V} \end{aligned}$ |
| SEG and SEGDIO Pins |  |
| Configured as SEG or COM drivers | $\begin{array}{\|l\|} \hline-1 \mathrm{~mA} \text { to }+1 \mathrm{~mA}, \\ -0.5 \mathrm{~V} \text { to } \mathrm{VLCD}+0.5 \mathrm{~V} \\ \hline \end{array}$ |
| Configured as Digital Inputs | $\begin{array}{\|l} \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ -0.5 \mathrm{~V} \text { to }+6 \mathrm{~V} \end{array}$ |
| Configured as Digital Outputs | $\begin{aligned} & \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ & -0.5 \mathrm{~V} \text { to V3P3D+0.5 } \end{aligned}$ |
| Digital Pins |  |
| Inputs (PB, RESET, RX, ICE_E, TEST) | $\begin{array}{\|l} \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ -0.5 \text { to } 6 \mathrm{~V} \end{array}$ |
| Outputs (TX) | $\begin{aligned} & \hline-10 \mathrm{~mA} \text { to }+10 \mathrm{~mA}, \\ & -0.5 \mathrm{~V} \text { to V3P3D+0.5 } \end{aligned}$ |
| Temperature |  |
| Operating junction temperature (peak, 100ms) | $140{ }^{\circ} \mathrm{C}$ |
| Operating junction temperature (continuous) | $125^{\circ} \mathrm{C}$ |
| Storage temperature | $-45^{\circ} \mathrm{C}$ to $+165^{\circ} \mathrm{C}$ |
| Soldering temperature - 10 second duration | $250{ }^{\circ} \mathrm{C}$ |

### 6.2 Recommended External Components

Table 87: Recommended External Components

| Name | From | To | Function | Value | Unit |
| :---: | :---: | :---: | :--- | :---: | :---: |
| C1 | V3P3A | GNDA | Bypass capacitor for 3.3 V supply | $\geq 0.1 \pm 20 \%$ | $\mu \mathrm{~F}$ |
| C2 | V3P3D | GNDD | Bypass capacitor for 3.3 V output | $0.1 \pm 20 \%$ | $\mu \mathrm{~F}$ |
| CSYS | V3P3SYS | GNDD | Bypass capacitor for V3P3SYS | $\geq 1.0 \pm 30 \%$ | $\mu \mathrm{~F}$ |
| CVDD | VDD | GNDD | Bypass capacitor for VDD | $0.1 \pm 20 \%$ | $\mu \mathrm{~F}$ |
| CVLCD | VLCD | GNDD | Bypass capacitor for VLCD pin | $\geq 0.1 \pm 20 \%$ | $\mu \mathrm{~F}$ |
| XTAL | XIN | XOUT | $32.768 ~ k H z ~ c r y s t a l ~-~ e l e c t r i c a l l y ~$ <br> equivalent to ECS .327-12.5-17X or <br> Vishay XT26T, load capacitance 12.5 pF | 32.768 | kHz |
| CXS | XIN | GNDA | Load capacitor values for crystal depend <br> on crystal specifications and board <br> parasitics. Nominal values are based on <br> 4 pF board capacitance and include an <br> allowance for chip capacitance. | $15 \pm 10 \%$ | pF |
| CXL | XOUT | GNDA | $10 \pm 10 \%$ | pF |  |

### 6.3 Recommended Operating Conditions

Unless otherwise specified, all parameters listed under 6.4 Performance Specifications and 6.5 Timing Specifications are valid over the Recommended Operating Conditions provided in Table 88 below.

Table 88: Recommended Operating Conditions

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| V3P3SYS and V3P3A Supply Voltage for precision metering operation (MSN mode). Voltages at VBAT and VBAT_RTC need not be present. | $\begin{aligned} & \text { VBAT=0 } \mathrm{V} \text { to } 3.8 \mathrm{~V} \\ & \text { VBAT_RTC }=0 \mathrm{~V} \text { to } \\ & 3.8 \mathrm{~V} \end{aligned}$ | 3.0 |  | 3.6 | V |
| VBAT Voltage (BRN mode). V3P3SYS is below the 2.8 V comparator threshold. Either V3P3SYS or VBAT_RTC must be high enough to power the RTC module. | $\begin{aligned} & \text { V3P3SYS < } 2.8 \mathrm{~V} \\ & \text { and } \\ & \text { Max(VBAT_RTC, } \\ & \text { V3P3SYS) > } 2.0 \mathrm{~V} \\ & \hline \end{aligned}$ | 2.5 |  | 3.8 | V |
| VBAT_RTC Voltage. VBAT_RTC is not needed to support the RTC and non-volatile memory unless V3P3SYS<2.0 V | V3P3SYS<2.0 V | 2.0 |  | 3.8 | V |
| Operating Temperature |  | -40 |  | +85 | ${ }^{\circ} \mathrm{C}$ |

## Notes

1. GNDA and GNDD must be connected together.
2. V3P3SYS and V3P3A must be connected together.

### 6.4 Performance Specifications

### 6.4.1 Input Logic Levels

Table 89: Input Logic Levels

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Digital high-level input voltage ${ }^{1}, \mathrm{~V}_{\mathrm{IH}}$ |  | 2 |  |  | V |
| Digital low-level input voltage ${ }^{1}, \mathrm{~V}_{\mathrm{IL}}$ |  |  |  | 0.8 | V |
| Input pullup current, IIL E_RXTX, E_RST, E_TCLK OPT_RX, OPT_TX SPI_CSZ (SEGDIO36) Other digital inputs | $\begin{aligned} & \mathrm{VIN}=0 \mathrm{~V}, \\ & \text { ICE_E=3.3 V } \end{aligned}$ | $\begin{aligned} & 10 \\ & 10 \\ & 10 \\ & -1 \end{aligned}$ | 0 | $\begin{gathered} 100 \\ 100 \\ 100 \\ 1 \end{gathered}$ | $\mu \mathrm{A}$ <br> $\mu \mathrm{A}$ <br> $\mu \mathrm{A}$ <br> $\mu \mathrm{A}$ |
| Input pull down current, IIH ICE_E, RESET, TEST Other digital inputs | $\mathrm{VIN}=\mathrm{V} 3 \mathrm{P} 3 \mathrm{D}$ | $\begin{aligned} & 10 \\ & -1 \end{aligned}$ | 0 | $\begin{gathered} 100 \\ 1 \end{gathered}$ | $\underset{\mu \mathrm{A}}{\mu \mathrm{~A}}$ |

Note:

1. In battery powered modes, digital inputs should be below 0.1 V or above VBAT -0.1 V to minimize battery current.

### 6.4.2 Output Logic Levels

Table 90: Output Logic Levels

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Digital high-level output voltage $\mathrm{V}_{\mathrm{OH}}$ | $\mathrm{I}_{\text {LOAD }}=1 \mathrm{~mA}$ | V3P3D-0.4 |  |  | V |
|  | $\begin{aligned} & \hline \mathrm{I}_{\text {LOAD }}=15 \mathrm{~mA} \\ & \text { (see notes } 1,2 \text { ) } \end{aligned}$ | V3P3D-0.6 |  |  | V |
| Digital low-level output voltage VoL | $\mathrm{I}_{\text {LOAD }}=1 \mathrm{~mA}$ | 0 |  | 0.4 | V |
|  | $\begin{aligned} & \mathrm{I}_{\text {LOAD }}=15 \mathrm{~mA} \\ & \text { (see note 1) } \end{aligned}$ | 0 |  | 0.8 | V |

Note:

1. Guaranteed by design; not production tested.
2. Caution: The sum of all pull up currents must be compatible with the on-resistance of the internal V3P3D switch. See 6.4.6 V3P3D Switch on page 136.

### 6.4.3 Battery Monitor

Table 91: Battery Monitor Performance Specifications (TEMP_BAT =1)

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| BV: Battery Voltage (definition) | MSN mode, $T E M P_{-} P W R=1$ <br> BRN mode, <br> TEMP_ $P W R=T E M P \_B S E L$ | $\begin{gathered} B V=3.3 V+(\text { BSENSE }-142) \cdot 0.0246 V+\text { STEMP } \cdot 297 \mu V \\ B V=3.291 V+(\text { BSENSE }-142) \cdot 0.0255 V+\text { STEMP } \cdot 328 \mu V \end{gathered}$ |  |  | V |
| Measurement Error $100 \cdot\left(\frac{B V}{V B A T}-1\right)$ | $\begin{gathered} \hline \text { VBAT }= \\ 2.0 \mathrm{~V} \\ 2.5 \mathrm{~V} \\ 3.0 \mathrm{~V} \\ 4.0 \mathrm{~V} \end{gathered}$ | $\begin{gathered} -7.5 \\ -5 \\ -3 \\ -3 \end{gathered}$ |  | $\begin{gathered} 7.5 \\ 5 \\ 3 \\ 5 \end{gathered}$ | $\begin{aligned} & \% \\ & \% \\ & \% \\ & \% \end{aligned}$ |
| Input impedance in continuous measurement, MSN mode. <br> V(VBAT_RTC)/I(VBAT_RTC) | $\begin{aligned} & \mathrm{V} 3 \mathrm{P} 3=3.3 \mathrm{~V}, \\ & T E M P \_B S E L=0, \\ & T E M P-P E R=111, \\ & \mathrm{VBAT} \text { _RTC }=3.6 \mathrm{~V}, \end{aligned}$ | 1 |  |  | $\mathrm{M} \Omega$ |
| Load applied with BCURR $\operatorname{IBAT}(B C U R R=1)-\operatorname{IBAT}(B C U R R=0)$ | $\mathrm{V} 3 \mathrm{P} 3=3.3 \mathrm{~V}$ | 50 | 100 | 140 | $\mu \mathrm{A}$ |

### 6.4.4 Temperature Monitor

Table 92: Temperature Monitor

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Temperature Measurement Equation for 71M6543F and 71M6543G (see notes 2 and 3 ) | ```In MSN, TEMP_PWR=1: Temp \(=0.325 \cdot\) STEMP +22 In BRN, TEMP_P \(^{2} P\) = TEMP_BSEL: Temp \(=0.325 \cdot\) STEMP \(+0.00218 \cdot\) BSENSE \(^{2}-0.609 \cdot\) BSENSE +64.4``` |  |  |  | ${ }^{\circ} \mathrm{C}$ |
| Temperature Error (71M6543) (see note 1) | $\mathrm{T}_{\mathrm{A}}=22^{\circ} \mathrm{C}$ | -2 |  | 2 | ${ }^{\circ} \mathrm{C}$ |
| VBAT_RTC charge per measurement | TEMP_BSEL $=0$, <br> TEMP $P W R=0$, <br> SLP Mode, <br> VBAT RTC $=3.6 \mathrm{~V}$ |  | 16 |  | $\mu \mathrm{C}$ |
| Duration of temperature measurement after setting TEMP_START (see note 1) |  |  | 15 | 60 | ms |

Notes:

1. Guaranteed by design; not production tested.
2. For the 71 M 6543 F and 71 M 6543 G , TEMP_ 85 fuses read 0 .
3. The coefficients provided in these equations are typical.

### 6.4.5 Supply Current

The supply currents provided in Table 93 below include only the current consumed by the 71 M 6543 . Refer to the 71M6xxx Data Sheet for additional current required when using a 71M6x03 remote sensor.

Table 93: Supply Current Performance Specifications


### 6.4.6 V3P3D Switch

Table 94: V3P3D Switch Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| On resistance - V3P3SYS to V3P3D | $\left\|l_{\text {V3P3D }}\right\| \leq 1 \mathrm{~mA}$ |  |  | 10 | $\Omega$ |
| On resistance - VBAT to V3P3D | $\begin{aligned} & \left\|I_{\text {V3P3D }}\right\| \leq 1 \mathrm{~mA}, \\ & \text { VBAT }>2.5 \mathrm{~V} \end{aligned}$ |  |  | 10 | $\Omega$ |
| V3P3D $\mathrm{I}_{\text {OH }}$, MSN | $\begin{aligned} & \text { V3P3SYS = 3V } \\ & \text { V3P3D }=2.9 \mathrm{~V} \end{aligned}$ | 10 |  |  | mA |
| V3P3D $\mathrm{I}_{\text {OH }}$, BRN | $\begin{aligned} & \mathrm{VBAT}=2.6 \mathrm{~V} \\ & \mathrm{~V} 3 \mathrm{P} 3 \mathrm{D}=2.5 \mathrm{~V} \end{aligned}$ | 10 |  |  | mA |

### 6.4.7 Internal Power Fault Comparators

Table 95: Internal Power Fault Comparators Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Overall response time | 100 mV overdrive, falling 100 mV overdrive, rising | 20 |  | $\begin{aligned} & 200 \\ & 200 \end{aligned}$ | $\begin{aligned} & \mu \mathrm{s} \\ & \mu \mathrm{~s} \end{aligned}$ |
| Falling Threshold <br> 3.0 V Comparator <br> 2.8 V Comparator <br> Difference 3.0 V and 2.8 V Comparators | V3P3 falling | $\begin{gathered} 2.83 \\ 2.75 \\ 50 \end{gathered}$ | $\begin{aligned} & 2.93 \\ & 2.81 \\ & 136 \end{aligned}$ | $\begin{aligned} & 3.03 \\ & 2.87 \\ & 220 \end{aligned}$ | $\begin{gathered} \mathrm{V} \\ \mathrm{~V} \\ \mathrm{mV} \end{gathered}$ |
| Falling Threshold <br> 2.25 V Comparator <br> 2.0 V Comparator <br> VDD (@VBAT=3.0V) - 2.25V Comparator <br> Difference 2.25 V and 2.0 V Comparators | VDD falling | $\begin{gathered} 2.2 \\ 1.90 \\ 0.25 \\ 0.15 \\ \hline \end{gathered}$ | $\begin{aligned} & 2.25 \\ & 2.00 \\ & 0.35 \\ & 0.25 \\ & \hline \end{aligned}$ | $\begin{gathered} 2.5 \\ 2.20 \\ 0.45 \\ 0.35 \\ \hline \end{gathered}$ | $\begin{aligned} & \mathrm{V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \hline \end{aligned}$ |
| Hysteresis, <br> (Rising Threshold - Falling Threshold) <br> 3.0 V Comparator <br> 2.8 V Comparator <br> 2.25 V Comparator <br> 2.0 V Comparator | $\mathrm{T}_{\mathrm{A}}=22^{\circ} \mathrm{C}$ | $\begin{aligned} & 22 \\ & 25 \\ & 10 \\ & 10 \\ & \hline \end{aligned}$ | $\begin{aligned} & 45 \\ & 42 \\ & 33 \\ & 28 \\ & \hline \end{aligned}$ | $\begin{aligned} & 65 \\ & 60 \\ & 60 \\ & 60 \\ & \hline \end{aligned}$ | mV <br> mV <br> mV <br> mV |

### 6.4.8 2.5 V Voltage Regulator - System Power

Table 96: 2.5 V Voltage Regulator Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :--- | :--- | :---: | :---: |
| V2P5 | V3P3 $=3.0 \mathrm{~V}-3.8 \mathrm{~V}$ <br> ILOAD $=0 \mathrm{~mA}$ | 2.55 | 2.65 | 2.75 | V |
| V2P5 load regulation | V3P3 $=3.3 \mathrm{~V}$ <br> ILOAD $=0 \mathrm{~mA}$ to 5 mA |  |  | 40 | mV |
| Voltage overhead V3P3SYS-V2P5 | ILOAD $=5 \mathrm{~mA}$, <br> Reduce V3P3D until V2P5 <br> drops 200 mV |  |  | 440 | mV |

### 6.4.9 2.5 V Voltage Regulator - Battery Power

Table 97: Low-Power Voltage Regulator Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| V2P5 | VBAT $=3.0 \mathrm{~V}-3.8 \mathrm{~V}$, <br> $\mathrm{V} 3 \mathrm{P} 3=0 \mathrm{~V}, \mathrm{ILOAD}=0 \mathrm{~mA}$ | 2.55 | 2.65 | 2.75 | V |
| V2P5 load regulation | $\mathrm{VBAT}=3.3 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, <br> $\mathrm{ILOAD}=0 \mathrm{~mA}$ to 1 mA |  |  | 40 | mV |
| Voltage Overhead 2V - VBAT-VDD | I IOAD $=0 \mathrm{ma}$, VBAT $=2.0 \mathrm{~V}$, <br> V3P3 $=0 \mathrm{~V}$. |  |  | 200 | mV |

### 6.4.10 Crystal Oscillator

Table 98: Crystal Oscillator Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| Maximum Output Power to Crystal | Crystal connected, see note 1 |  |  | 1 | $\mu \mathrm{~W}$ |
| XIN to XOUT Capacitance <br> (see note 1) |  |  |  | 3 | pF |
| Capacitance change on XOUT | $R T C A \_A D J=7 \mathrm{~F}$ to 0, <br> Bias voltage = unbiased <br> Vpp $=0.1 \mathrm{~V}$ |  | 15 | pF |  |

Note:

1. Guaranteed by design; not production tested.

### 6.4.11 Phase-Locked Loop (PLL)

Table 99: PLL Performance Specifications

| PARAMETER | CONDITION | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| PLL Power-up Settling Time | $\text { PLL_FAST = } 0 \text {, }$ <br> V3P3 $=0$ to 3.3 V step Measured from first edge of MCK (TMUX2OUT pin) |  | 3 |  | ms |
| PLL_FAST settling time PLL_FAST rise PLL FAST fall | V3P3=0, VBAT $=3.8$ to 2.0 V |  | $\begin{aligned} & 3 \\ & 3 \\ & \hline \end{aligned}$ |  | $\begin{aligned} & \mathrm{ms} \\ & \mathrm{~ms} \end{aligned}$ |
| PLL SLP to MSN Settling Time | PLL_FAST $=0$ |  | 3 |  | ms |

### 6.4.12 LCD Drivers

Table 100: LCD Drivers Performance Specifications

| PARAMETER | CONDITION | MIN | TYP | MAX | UNIT |
| :--- | :--- | :---: | :---: | :---: | :---: |
| VLCD Current | VLCD $=3.3$, all LCD map bits=0 |  |  | 2 | uA |
|  | VLCD $=5.0$, all LCD map bits $=0$ |  |  | 3 | uA |

## Note:

1. These specifications apply to all COM and SEG pins.
2. $L C D$ VMODE $=3, L C D ~ O N=1, L C D ~ B L A N K=0, L C D \_M O D E=6, L C D \_C L K=2$.
3. Output load is 74 pF per SEG and COM pin.

### 6.4.13 VLCD Generator

Table 101: VLCD Generator Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| VSYS to VLCD switch impedance | $\begin{array}{\|l\|} \hline \mathrm{V} 3 \mathrm{P} 3=3.3 \mathrm{~V}, \\ \mathrm{RVLCD}=\text { removed, } L C D \_B A T=0, \\ L C D \_V M O D E[1: 0]=0, \\ I_{\mathrm{ILCD}}=10 \mu \mathrm{~A} \\ \hline \end{array}$ |  |  | 750 | $\Omega$ |
| VBAT to VLCD switch impedance | $\begin{aligned} & \mathrm{V} 3 \mathrm{P} 3=0 \mathrm{~V}, \mathrm{VBAT}=2.5 \mathrm{~V}, \\ & \mathrm{RVLCD}=\text { removed, } L C D \_B A T=1, \\ & L C D=V M O D E[1: 0]=0, \\ & \Delta \mathrm{ILCD}=10 \mu \mathrm{~A} \\ & \hline \end{aligned}$ |  |  | 700 | $\Omega$ |
| LCD Boost Frequency | $\begin{aligned} & \hline L C D \_V M O D E[1: 0]=2, \\ & \mathrm{RVLCD}=\text { removed, } \\ & \mathrm{CVLCD}=\text { removed } \\ & P L L \_F A S T=1 \\ & P L L \_F A S T=0 \\ & \hline \end{aligned}$ |  | $\begin{array}{r} 820 \\ 786 \\ \hline \end{array}$ |  | $\begin{array}{r} \mathrm{kHz} \\ \mathrm{kHz} \\ \hline \end{array}$ |
| VLCD IOH current <br> (VLCD $(0)-\mathrm{VLCD}(\mathrm{IOH})<0.25)$ | $\begin{aligned} & \hline L C D \_V M O D E[1: 0]=2, \\ & L C D \_C L K[1: 0]=2, \\ & \mathrm{RVLCD}=\text { removed, } \\ & \mathrm{V} 3 \mathrm{P} 3=3.3 \mathrm{~V}, \\ & L C D \_D A C[4: 0]=1 \mathrm{~F} \\ & \hline \end{aligned}$ | 10 |  |  | $\mu \mathrm{A}$ |

From LCDADJO and LCDADJ12 fuses:

$$
\begin{gathered}
L C D A D J\left(L C D_{-} D A C\right)=5 m V\left[L C D A D J 0+\frac{L C D A D J 12-L C D A D J 0}{12} L C D_{-} D A C\right] \\
V L C D_{N_{\text {OM }}}\left(L C D_{-} D A C\right)=2.65+2.65 \frac{L C D_{-} D A C}{31}+L C D A D J\left(L C D_{-} D A C\right)
\end{gathered}
$$

The above equations describe the nominal value of VLCD for a specific LCD_DAC value. The specifications below list the maximum deviation between actual VLCD and VLCDnom. Note that when VCC and boost are insufficient, the LCD DAC will not reach its target value and a large negative error will occur.

| LCD DAC Error. VLCD-VLCDnom <br> Full Scale, with Boost <br> V3P3 $=3.6 \mathrm{~V}$ <br> $\mathrm{V} 3 \mathrm{P} 3=3.0 \mathrm{~V}$ <br> VBAT $=4.0 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0$, BRN Mode <br> VBAT=2.5 V, V3P3=0, BRN Mode | $\begin{aligned} & L C D \_V M O D E=10, \\ & L C D-D A C[4: 0]=1 \mathrm{~F}, \\ & L C D-C L K[1: 0]=2, \\ & L C D \_M O D E[2: 0]=6 \end{aligned}$ | $\begin{aligned} & -0.15 \\ & -0.4 \\ & -0.15 \\ & -1.3 \\ & \hline \end{aligned}$ | $\begin{aligned} & 0.15 \\ & 0.15 \\ & 0.15 \end{aligned}$ | V V |
| :---: | :---: | :---: | :---: | :---: |
| ```LCD DAC Error. VLCD-VLCDnom DAC=12, with Boost V3P3 = 3.6 V V3P3 = 3.0 V VBAT =2.5 V, V3P3 = 0 V, BRN Mode``` | $\begin{aligned} & \text { LCD_VMODE = 10, } \\ & L C D \_D A C[4: 0]=\mathrm{C}, \\ & L C D \_C L K[1: 0]=2, \\ & L C D-M O D E[2: 0]=6 \end{aligned}$ | $\begin{aligned} & -0.15 \\ & -0.15 \\ & -0.15 \end{aligned}$ | $\begin{aligned} & 0.15 \\ & 0.15 \\ & 0.15 \end{aligned}$ | V v V |
| ```LCD_DAC Error. VLCD-VLCDnom Zero Scale, with Boost V3P3 = 3.6 V V3P3 = 3.0 V VBAT =4.0 V, V3P3 = 0 V, BRN Mode VBAT =2.5 V, V3P3 = 0 V, BRN Mode``` | $\begin{aligned} & \text { LCD_VMODE }=2, \\ & \text { LCD_DAC[4:0] }=0, \\ & \text { LCD_CLK[1:0]=2, } \\ & \text { LCD_MODE[2:0]=6 } \end{aligned}$ | $\begin{aligned} & -0.15 \\ & -0.15 \\ & -0.15 \\ & -0.15 \\ & \hline \end{aligned}$ | $\begin{aligned} & 0.15 \\ & 0.15 \\ & 0.15 \\ & 0.15 \end{aligned}$ | V |
| LCD DAC Error. VLCD-VLCDnom <br> Full Scale, no Boost <br> V3P3 $=3.6 \mathrm{~V}$ (see note 1) <br> $\mathrm{V} 3 \mathrm{P} 3=3.0 \mathrm{~V}$ (see note 1) <br> VBAT $=4.0 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode <br> VBAT $=2.5 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode | $\begin{aligned} & \text { LCD_VMODE }=1, \\ & L C D-D A C[4: 0]=1 \mathrm{~F}, \\ & L C D-C L K[1: 0]=2, \\ & \text { LCD_MODE } 2: 0]=6 \end{aligned}$ | $\begin{aligned} & -2.1 \\ & -2.8 \\ & -1.8 \\ & -3.2 \end{aligned}$ |  | V |
| LCD_DAC Error. VLCD-VLCDnom <br> DAC=12, no Boost <br> V3P3 $=3.6 \mathrm{~V}$ <br> V3P3 $=3.0 \mathrm{~V}$ <br> VBAT $=4.0 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode <br> VBAT $=2.5 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode | $\begin{aligned} & \text { LCD_VMODE = } 1, \\ & \text { LCDDAC[4:0]=C, } \\ & \text { LCD_CLK[1:0]=2, } \\ & \text { LCD_MODE } 2: 0]=6 \end{aligned}$ | $\begin{aligned} & -0.5 \\ & -1.1 \\ & -0.15^{1} \\ & -1.5^{1} \end{aligned}$ | $0.15^{1}$ | V |


| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| LCD_DAC Error. VLCD-VLCDnom | $L C D \_V M O D E=01$, |  |  |  |  |
| Zero Scale, no Boost | $L C D \_D A C[4: 0]=0$, |  |  |  |  |
| $\mathrm{V} 3 \mathrm{P} 3=3.6 \mathrm{~V}$ | $L C D \_C L K[1: 0]=2$, | -0.15 |  | 0.15 | V |
| $\mathrm{V} 3 \mathrm{P} 3=3.0 \mathrm{~V}$ | $L C D \_M O D E[2: 0]=6$ | -0.15 |  | 0.15 | V |
| VBAT $=4.0 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode |  | -0.15 |  | 0.15 | V |
| VBAT $=2.5 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$, BRN Mode |  | -0.45 |  | 0.15 | V |
| $L C D \_D A C$ Error. VLCD-VLCDnom | $L C D \_V M O D E=1$, |  |  |  |  |
| Full Scale, with Boost, LCD mode | $L C D \_D A C[4: 0]=1 \mathrm{~F}$, |  |  |  |  |
| $\mathrm{VBAT}=4.0 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$ | LCD_CLK[1:0]=2, | -0.15 |  | 0.15 | V |
| $\mathrm{VBAT}=2.5 \mathrm{~V}, \mathrm{~V} 3 \mathrm{P} 3=0 \mathrm{~V}$ | $L C D \_M O D E[2: 0]=6$ | -1.3 |  |  | V |
| Note: |  |  |  |  |  |
| 1. Guaranteed by design; not production tested. |  |  |  |  |  |
| 2. The following test conditions | o apply to all paramet $\mathrm{k} \Omega$, no display, all SEG | table d as | ass | acito | $\text { LCD } \geq$ |

### 6.4.14 71M6543 VREF

Table 102 shows the performance specifications for the 71M6543 ADC reference voltage (VREF).
Table 102: 71M6543 VREF Performance Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| VREF output voltage, VREF(22) | $\mathrm{T}_{\mathrm{A}}=22^{\circ} \mathrm{C}$ | 1.193 | 1.195 | 1.197 | V |
| VREF output voltage, VREF(22) | PLL_FAST $=0$ |  | 1.195 |  | V |
| VREF chop step, trimmed | VREF(CHOP=01) - VREF(CHOP=10) | -10 |  | 10 | mV |
| VREF power supply sensitivity $\Delta$ VREF / $\Delta \mathrm{V} 3 \mathrm{P} 3 \mathrm{~A}$ | $\mathrm{V} 3 \mathrm{P} 3 \mathrm{~A}=3.0$ to 3.6 V | -1.5 |  | 1.5 | mV/V |
| VREF input impedance | VREF DIS = 1, <br> VREF $=1.3 \mathrm{~V}$ to 1.7 V | 100 |  |  | k $\Omega$ |
| VREF output impedance | $\begin{aligned} & \text { VREF_CAL }=1, \\ & \text { ILOAD }=10 \mu \mathrm{~A},-10 \mu \mathrm{~A} \\ & \hline \end{aligned}$ |  |  | 3.2 | k $\Omega$ |
| VNOM definition (see note 2) | $\operatorname{VNOM}(T)=\operatorname{VREF}(22)+(T-22) T C 1+(T-22)^{2} T C 2$ |  |  |  | V |
| If temperature characterization trim information is not available (71M6543F and 71M6543G) |  |  |  |  |  |
| VNOM temperature coefficients: $\begin{aligned} & \text { TC1 = } \\ & \text { TC2 }= \end{aligned}$ | $\begin{gathered} 275-4.95 \cdot \text { TRIMT } \\ -0.557-0.00028 \cdot \text { TRIMT } \end{gathered}$ |  |  |  | $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}^{2}$ |
| $\operatorname{VREF}(\mathrm{T})$ deviation from VNOM(T) (see note 1): <br> $\operatorname{VREF}(T)-\operatorname{VNOM}(T) 10^{6}$ |  | -40 |  | +40 | ppm/ $/{ }^{\circ} \mathrm{C}$ |
| $\operatorname{VNOM}(T) \quad 62$ |  |  |  |  |  |
| VREF aging |  |  | $\pm 25$ |  | ppm/ year |

Notes:

1. Guaranteed by design; not production tested.
2. This relationship describes the nominal behavior of VREF at different temperatures, as governed by a second order polynomial of $1^{\text {st }}$ and $2^{\text {nd }}$ order coefficients TC1 and TC2.
3. For the parameters in this table, unless otherwise specified, $V R E F_{-} D I S=0, P L L_{-} F A S T=1$

### 6.4.15 ADC Converter

Table 103: ADC Converter Performance Specifications

| Parameter |  |  |  |  | Condition | Min |  | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Recommended Input Range (Vin - V3P3A) |  |  |  |  |  | -250 |  |  | 250 | $\begin{gathered} \mathrm{mV} \\ \text { peak } \end{gathered}$ |
| Voltage to Current Crosstalk$\begin{aligned} & \frac{10^{6} * \text { Vcrosstalk }}{\operatorname{Vin}} \cos (\angle \text { Vin }-\angle V \text { crosstalk }) \\ & \text { (see note } 1 \text { ) } \end{aligned}$ |  |  |  |  | Vin $=200 \mathrm{mV}$ peak, 65 Hz , on VADC8 (VA) or VADC9 (VB) or VADC10 (VC). <br> Vcrosstalk $=$ largest measurement on IADC0-1 or IADC2-3 or IADC4-5 or IADC6-7 | -10 |  |  | 10 | $\mu \mathrm{V} / \mathrm{V}$ |
| Input Impedance, no pre-amp |  |  |  |  | Vin=65 Hz | 40 |  |  | 90 | k $\Omega$ |
| ADC Gain Error vs \%Power Supply Variation$\frac{10^{6} \Delta \text { Nout }_{P K} 357 n V / V_{I N}}{100 \Delta V 3 P 3 A / 3.3}$ |  |  |  |  | $\begin{array}{\|l} \mathrm{Vin}=200 \mathrm{mV} \text { pk, } 65 \mathrm{~Hz} \\ \mathrm{~V} 3 \mathrm{P} 3 \mathrm{~A}=3.0 \mathrm{~V}, 3.6 \mathrm{~V} \end{array}$ |  |  |  | 50 | ppm / \% |
| Input Offset IADC0=IADC1=V3P3A IADC0=V3P3A |  |  |  |  | $\begin{aligned} & \text { DIFF0_E }=1, \text { PRE_E }=0 \\ & D I F F 0 \_E=0, P R E \_E=0 \end{aligned}$ | $\begin{aligned} & -10 \\ & -10 \end{aligned}$ |  |  | $\begin{aligned} & 10 \\ & 10 \end{aligned}$ | $\begin{aligned} & \mathrm{mV} \\ & \mathrm{mV} \end{aligned}$ |
| THD <br> T Name <br> A <br> B <br> C <br> D <br> E <br> F <br> G <br> H <br> J |  | V1pk <br> ADCDl <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 1 <br> 1 <br> 1 <br> 1 <br> 1 |  |  <br> $M L X D V$ <br>  <br>  <br> 11 <br> 6 <br> 4 <br> 2 <br> 6 <br>  | $\mathrm{V}_{\mathrm{IN}}=65 \mathrm{~Hz}, 250 \mathrm{mVpk},$ <br> 64kpts FFT, Blackman Harris Window. |  | $A$ <br> $B$ <br> $C$ <br> $D$ <br> $E$ <br> F <br> $G$ <br> $H$ <br> $J$ | -82  <br>  -84 <br>  -83 <br>  -86 | A -75 <br> B -75 <br> C -75 <br> D -75 <br> E -75 <br> F -75 <br> G -75 <br> H -75 <br> J -75 | dB |
| THD <br> THame <br> Nam <br> B <br> C <br> D <br> E <br> F <br> G <br> H <br> J |  | Vpk <br> ADCDIV <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 0 <br> 1 <br> 1 <br> 1 <br> 1 <br> 1 <br> 1 | $\square$ | MUXXIV <br> 3 <br> 2 <br> 11 <br> 6 <br> 4 <br> 2 <br> 6 <br> 3 <br> 2 | $\mathrm{V}_{\mathrm{IN}}=65 \mathrm{~Hz}, 20 \mathrm{mVpk},$ <br> 64kpts FFT, Blackman Harris Window. |  | B <br> C <br> D <br> E <br> F <br> G <br> H | -85  <br> -.91  <br> -.85  <br>  -91 <br>  -95 <br>  -85 <br>  -91 <br>  -93 |  | dB |
| LSB |  |  |  |  | $\mathrm{Vin}=65 \mathrm{~Hz}, 20 \mathrm{mV} \mathrm{pk}$, 64kpts FFT, BlackmanHarris window |  | A <br> B <br> C <br> D <br> E <br> F <br> G <br> H <br> J |  3470 <br>  406 <br>  3040 <br>  357 <br>  151 <br>  3470 <br>  3040 <br>  357 <br>  151 |  | nV |
| Digit | Full-S <br> FIRLEN <br> 0 <br> 1 <br> 0 <br> 1 <br> 2 <br> 0 <br> 1 |   <br> ale:  <br> ADCDIV  <br>  0 <br>  0 <br>  0 <br>  0 <br>  1 <br>  1 <br> 1 1 |  |  <br> MUXDIV <br> 3 <br> 2 <br> 11 <br> 6 <br> 4 <br> 2 <br> 6 <br> 3 |  |  |  | 91125 778688 103823 884736 2097152 91125 103823 884736 2097152 |  | LSB |


| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :--- | :--- | :--- | :--- |
| Note: | Guaranteed by design; not production tested. |  |  |  |  |
| 1. |  |  |  |  |  |
| 2. | Unless stated otherwise, the following test conditions apply to all the parameters provided in |  |  |  |  |
| this table: $F I R \_L E N[1: 0]=1, V R E F-D I S=0, P L L \_F A S T=1, A D C_{-} D I V=0, M U X \_D I V=6$, LSB values |  |  |  |  |  |
|  | do not include the 9-bit left shift at CE input. |  |  |  |  |

### 6.4.16 Pre-Amplifier for IADC0-IADC1

Table 104: Pre-Amplifier Performance Specifications

| PARAMETER | CONDITION | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Differential Gain <br> Vin $=30 \mathrm{mV}$ differential <br> Vin=15mV differential (see note 1) | $\begin{aligned} & \hline \mathrm{T}_{\mathrm{A}}=5^{\circ} \mathrm{C}, \\ & \mathrm{~V}_{3} 3=3.3 \mathrm{~V}, \\ & \text { PRE } E=1, \\ & \text { FIR_LEN=2, } \\ & \text { DIFFO_E=1, } \end{aligned}$ $2520 \mathrm{~Hz} \text { sample rate }$ | $\begin{aligned} & 7.8 \\ & 7.8 \end{aligned}$ | $\begin{aligned} & 7.92 \\ & 7.92 \end{aligned}$ | $\begin{aligned} & 8.0 \\ & 8.0 \end{aligned}$ | $\begin{aligned} & V / V \\ & V / V \end{aligned}$ |
| Gain Variation vs V3P3 <br> Vin $=30 \mathrm{mV}$ differential (see note 1) | $\begin{aligned} & \hline \mathrm{V} 3 \mathrm{P} 3= \\ & 2.97 \mathrm{~V}, 3.63 \mathrm{~V} \\ & \hline \end{aligned}$ | -100 |  | 100 | ppm/\% |
| Gain Variation vs Temp Vin $=30 \mathrm{mV}$ differential (see note 1 ) | $\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}, 85^{\circ} \mathrm{C}$ | 10 | -25 | -80 | ppm/C |
| Phase Shift, <br> Vin=30mV differential (see note 1) | $\begin{aligned} & \hline \mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \\ & \mathrm{~V} 3 \mathrm{P} 3=3.3 \mathrm{~V} \\ & \hline \end{aligned}$ | -6 |  | 6 | $\mathrm{m}^{\circ}$ |
| Preamp input current <br> IADC0 <br> IADC1 | PRE E=1, <br> FIR_LEN=10, <br> DIFFO E=1 <br> 2520 Hz sample rate, <br> IADC0 $=$ IADC1 $=$ V3P3 | $\begin{aligned} & 4 \\ & 4 \end{aligned}$ | $\begin{aligned} & 9 \\ & 9 \end{aligned}$ | $\begin{aligned} & 16 \\ & 16 \end{aligned}$ | $\begin{aligned} & \text { uA } \\ & \text { uA } \end{aligned}$ |
| Preamp+ADC THD <br> Vin $=30 \mathrm{mV}$ differential <br> Vin $=15 \mathrm{mV}$ differential | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, <br> V3P3=3.3 V, <br> PRE_E=1, <br> FIR_LEN=2, <br> DIFFO $E=1$, <br> 2520 Hz sample rate. |  | $\begin{aligned} & -82 \\ & -86 \end{aligned}$ |  | $\begin{aligned} & \mathrm{dB} \\ & \mathrm{~dB} \end{aligned}$ |
| Preamp Offset <br> IADC0 $=1 \mathrm{ADC} 1=\mathrm{V} 3 \mathrm{P} 3+30 \mathrm{mV}$ <br> IADC $0=I A D C 1=V 3 P 3+15 \mathrm{mV}$ <br> IADC0=IADC1 $=V 3 P 3$ <br> IADC0 $=$ IADC1 $=\mathrm{V} 3 \mathrm{P} 3-15 \mathrm{mV}$ <br> IADC0=IADC1 = V3P3-30mV | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C},$ <br> V3P3=3.3 V, <br> PRE $E=1$, <br> FIR_LEN=10, <br> DIFFO_E=1, <br> 2520 Hz sample rate |  | $\begin{array}{\|l} -0.63 \\ -0.57 \\ -0.56 \\ -0.56 \\ -0.55 \\ \hline \end{array}$ |  | $\begin{aligned} & \mathrm{mV} \\ & \mathrm{mV} \\ & \mathrm{mV} \\ & \mathrm{mV} \\ & \mathrm{mV} \end{aligned}$ |

## Note:

1. Guaranteed by design; not production tested.

### 6.5 Timing Specifications

### 6.5.1 Flash Memory

Table 105: Flash Memory Timing Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| Flash write cycles | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 20,000 |  |  | Cycles |
| Flash data retention | $25^{\circ} \mathrm{C}$ | 100 |  |  | Years |
| $85^{\circ} \mathrm{C}$ |  |  |  | 2 | Cycles |
| Flash byte writes between page or <br> mass erase operations |  |  |  | 21 | $\mu \mathrm{~s}$ |
| Write Time per Byte |  |  |  | 21 | ms |
| Page Erase (1024 bytes) |  |  |  | 21 | ms |
| Mass Erase |  |  |  |  |  |

### 6.5.2 SPI Slave

Table 106. SPI Slave Timing Specifications

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| SPI Setup Time | SPI_DI to SPI_CK rise | 10 |  |  | ns |
| SPI Hold Time | SPI_CK rise to SPI_DI | 10 |  |  | ns |
| SPI Output Delay | SPI_CK fall to SPI_D0 |  |  | 40 | ns |
| SPI Recovery Time | SPI_CSZ fall to SPI_CK | 10 |  |  | ns |
| SPI Removal Time | SPI_CK to SPI_CSZ rise | 15 |  |  | ns |
| SPI Clock High |  | 40 |  |  | ns |
| SPI Clock Low |  | 40 |  |  | ns |
| SPI Clock Freq | SPI Freq/MPU Freq |  |  | 2.0 | $\mathrm{MHz} / \mathrm{MHz}$ |
| SPI Transaction Space | SPI_CSZ rise to SPI_CSZ fall | 4.5 |  |  | MPU Cycles |

### 6.5.3 EEPROM Interface

Table 107: EEPROM Interface Timing

| Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Write Clock frequency ( ${ }^{2} \mathrm{C}$ ) | CKMPU $=4.9 \mathrm{MHz}$, <br> Using interrupts |  | 310 |  | kHz |
|  | CKMPU $=4.9 \mathrm{MHz}$, bit-banging DIO2/3 PLL $F A S T=0$ |  | 100 |  | kHz |
| Write Clock frequency (3-wire) | $\begin{aligned} & \text { CKMPU }=4.9 \mathrm{MHz} \\ & \text { PLL_FAST }=0 \\ & \text { PLL_FAST }=1 \end{aligned}$ |  | $\begin{aligned} & 160 \\ & 500 \end{aligned}$ |  | kHz |

### 6.5.4 RESET Pin

Table 108: RESET Pin Timing

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| Reset pulse width |  | 5 |  |  | $\mu \mathrm{~s}$ |
| Reset pulse fall time (see note 1) |  |  |  | 1 | $\mu \mathrm{~s}$ |

Note:

1. Guaranteed by design; not production tested.

### 6.5.5 Real-Time Clock (RTC)

Table 109: RTC Range for Date

| Parameter | Condition | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| Range for date |  | 2000 | - | 2255 | year |

### 6.6 100-Pin LQFP Package Outline Drawing

Controlling dimensions are in mm .


Top View


Side View
Figure 41: 100-pin LQFP Package Outline

### 6.7 71M6543 Pinout



Figure 42: Pinout for the LQFP-100 Package

### 6.8 71M6543 Pin Descriptions

### 6.8.1 71M6543 Power and Ground Pins

Pin types: $\mathrm{P}=$ Power, $\mathrm{O}=$ Output, $\mathrm{I}=$ Input, $\mathrm{I} / \mathrm{O}=\operatorname{Input/Output.~The~circuit~number~denotes~the~equivalent~}$ circuit, as specified under Section 6.8.4 I/O Equivalent Circuits.

Table 110: 71M6543 Power and Ground Pins

| Pin | Name | Type | Circuit | Function |
| :---: | :---: | :---: | :---: | :--- |
| 72,80 | GNDA | P | - | Analog Ground. This pin should be connected directly to the <br> ground plane. |
| 62 | GNDD | P | - | Digital Ground. This pin should be connected directly to the <br> ground plane. |
| 85 | V3P3A | P | - | Analog Power Supply. A 3.3 V power supply should be <br> connected to this pin. V3P3A must be the same voltage as <br> V3P3SYS. |
| 69 | V3P3SYS | P | - | System 3.3 V Supply. This pin should be connected to a 3.3 V <br> power supply. |
| 61 | V3P3D | O | 13 | Auxiliary Voltage Output of the Chip. In mission mode, this <br> pin is connected to V3P3SYS by the internal selection switch. <br> In BRN mode, it is internally connected to VBAT. V3P3D is <br> floating in LCD and sleep mode. A bypass capacitor to ground <br> should not exceed 0.1 $\mu \mathrm{F}$. |
| 60 | VDD | O | - | Output of the 2.5 V Regulator. This pin is powered in MSN and <br> BRN modes. A 0.1 $\mu \mathrm{FF}$ bypass capacitor to ground should be <br> connected to this pin. |
| 89 | VLCD | O | - | Output of the LCD DAC. A 0.1 $\mu$ F bypass capacitor to ground <br> should be connected to this pin. |
| 70 | VBAT | P | 12 | Battery Backup Pin to Support the Battery Modes (BRN, LCD). <br> A battery or super capacitor is to be connected between VBAT <br> and GNDD. If no battery is used, connect VBAT to V3P3SYS. |
| 71 | VBAT_RTC | P | 12 | RTC and Oscillator Power Supply. A battery or super-capacitor <br> is to be connected between VBAT and GNDD. If no battery is <br> used, connect VBAT_RTC to V3P3SYS. |

### 6.8.2 71M6543 Analog Pins

Pin types: $\mathrm{P}=$ Power, $\mathrm{O}=$ Output, $\mathrm{I}=$ Input, $\mathrm{I} / \mathrm{O}=$ Input/Output. The circuit number denotes the equivalent circuit, as specified in Section 6.8.4.

Table 111: 71M6543 Analog Pins


### 6.8.3 71M6543 Digital Pins

Pin types: $\mathrm{P}=$ Power, $\mathrm{O}=$ Output, $\mathrm{I}=$ Input, $\mathrm{I} / \mathrm{O}=$ Input/Output, $\mathrm{N} / \mathrm{C}=$ no connect. The circuit number denotes the equivalent circuit, as specified in Section 6.8.4.

Table 112: 71M6543 Digital Pins

| Pin | Name | Type | Circuit | Function |
| :---: | :---: | :---: | :---: | :---: |
| 12-15 | COM0-COM3 | 0 | 5 | LCD Common Outputs. These four pins provide the select signals for the LCD display. |
| 45 | SEGDIOOMWPULSE | I/O | 3, 4, 5 | Multiple-Use Pins. Configurable as either LCD segment driver or DIO. Alternative functions with proper selection of associated I/O RAM registers are: <br> SEGDIOO = WPULSE (45) <br> SEGDIO1 = VPULSE (44) <br> SEGDIO2 = SDCK (43) <br> SEGDIO3 = SDATA (42) <br> SEGDIO6 = XPULSE (38) <br> SEGDIO7 = YPULSE (37) <br> SEGDIO8 = DI (36) <br> Unused pins must be configured as outputs or terminated to V3P3/GNDD. |
| 44 | SEGDIO1/VPULSE |  |  |  |
| 43 | SEGDIO2/SDCK |  |  |  |
| 42 | SEGDIO3/SDATA |  |  |  |
| 41 | SEGDIO4 |  |  |  |
| 39 | SEGDIO5 |  |  |  |
| 38 | SEGDIO6/XPULSE |  |  |  |
| 37 | SEGDIO7/YPULSE |  |  |  |
| 36 | SEGDIO8/DI |  |  |  |
| 35-27 | SEGDIO[9:17] |  |  |  |
| 25-18 | SEGDIO[18:25] |  |  |  |
| 11-4 | SEGDIO[28:35] |  |  |  |
| 99-94 | SEGDIO[40:45] |  |  |  |
| 52 | SEGDIO52 |  |  |  |
| 51 | SEGDIO53 |  |  |  |
| 47 | SEGDIO54 |  |  |  |
| 17 | SEGDIO26/COM5 |  |  | Multiple-Use Pins. Configurable as either LCD segment |
| 16 | SEGDIO27/COM4 |  |  | drivers). |
| 3 | SPI_CSZ/SEGDIO36 | I/O | 3, 4, 5 | Multiple-Use Pins. Configurable as either LCD segment driver or DIO with alternative function (SPI interface). |
| 2 | SPI_DO/SEGDIO37 |  |  |  |
| 1 | SPI_DI/SEGDIO38 |  |  |  |
| 100 | SPI_CKI/SEGDIO39 |  |  |  |
| 53 | OPT_TX/SEGDIO51 | I/O | 3, 4, 5 | Multiple-Use Pins, configurable as either LCD segment driver or DIO with alternative function (optical port/UART1) |
| 46 | OPT_RX/SEGDIO55 |  |  |  |
| 58 | E_RXTX/SEG48 | I/O | 1,4,5 | Multiuse Pins. Configurable as either emulator port pins (when ICE_E pulled high) or LCD segment drivers (when ICE_E tied to GND). |
| 56 | E_RST/SEG50 |  |  |  |
| 57 | E_TCLK/SEG49 | 0 | 4,5 |  |
| 59 | ICE_E | 1 | 2 | ICE Enable. When zero, E_RST, E_TCLK, and E_RXTX become SEG50, SEG49, and SEG48 respectively. For production units, this pin should be pulled to GND to disable the emulator port. |
| 92 | TMUXOUT/SEG47 | 0 | 4, 5 | Multiple-Use Pins. Configurable as either multiplexer/clock output or LCD segment driver using the I/O RAM registers. |
| 93 | TMUX2OUT/SEG46 |  |  |  |


| Pin | Name | Type | Circuit | Function |
| :---: | :---: | :---: | :---: | :---: |
| 91 | RESET | 1 | 2 | Chip Reset. This input pin is used to reset the chip into a known state. For normal operation, this pin is pulled low. To reset the chip, this pin should be pulled high. This pin has an internal $30 \mu \mathrm{~A}$ (nominal) current source pulldown. No external reset circuitry is necessary. |
| 55 | RX | 1 | 3 | UARTO Input. If this pin is unused it must be terminated to V3P3D or GNDD. |
| 54 | TX | 0 | 4 | UARTO Output |
| 81 | TEST | 1 | 7 | Enables Production Test. This pin must be grounded in normal operation. |
| 90 | PB | 1 | 3 | Pushbutton Input. This pin must be at GNDD when not active or unused. A rising edge sets the $W F_{-} P B$ flag. It also causes the part to wake up if it is in SLP or LCD mode. PB does not have an internal pullup or pulldown resistor. |
| $\begin{aligned} & 26,40, \\ & 48,49, \\ & 50,73, \\ & 74,77, \\ & 78,79 \end{aligned}$ | NC | N/C | - | No Connection. Do not connect this pin. |

### 6.8.4 I/O Equivalent Circuits



Figure 43: I/O Equivalent Circuits

## 7 Ordering Information

### 7.1 71M6543 Ordering Guide

Refer to the 71M6xxx data sheet for the 71M6xx3 ordering guide information.
Table 113.71M6543 Ordering Guide

| Part | Part Description <br> (Package, TYP Accuracy) | Flash <br> Size <br> (KB) | Packaging | Order Number | Package Marking |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 71M6543F | l00-pin LQFP <br> Lead(Pb)-Free, 0.1\% | 64 | bulk | 71M6543F-IGT/F | 71M6543F-IGT |
| 71M6543F | 100-pin LQFP <br> Lead(Pb)-Free, 0.1\% | 64 | tape and reel | 71M6543F-IGTR/F | 71M6543F-IGT |
| 71M6543G | 100-pin LQFP <br> Lead(Pb)-Free, 0.1\% | 128 | bulk | 71M6543G-IGT/F | 71M6543G-IGT |
| 71M6543G | 100-pin LQFP <br> Lead(Pb)-Free, 0.1\% | 128 | tape and reel | 71M6543G-IGTR/F | 71M6543G-IGT |

## 8 Related Information

The following documents related to the 71M6543 and 71M6xx3 are available:

- 71M6543F/71M6543G Data Sheet (this document)
- 71M6xxx Data Sheet
- 71M654x Software User's Guide (SUG)
- 71M6543 Demo Board User's Manual (DBUM)


## 9 Contact Information

For technical support or more information about Maxim products, contact technical support at www.maximintegrated.com/support.

## Appendix A: Acronyms

| AFE | Analog Front-End |
| :--- | :--- |
| AMR | Automatic Meter Reading |
| ANSI | American National Standards Institute |
| CE | Compute Engine |
| DIO | Digital I /O |
| DSP | Digital Signal Processor |
| FIR | Finite Impulse Response |
| I $^{2}$ C | Inter-IC Bus |
| ICE | In-Circuit Emulator |
| IEC | International Electrotechnical Commission |
| MPU | Microprocessor Unit (CPU) |
| PLL | Phase-Locked Loop |
| RMS | Root Mean Square |
| SFR | Special Function Register |
| SoC | System-on-Chip |
| SPI | Serial Peripheral Interface |
| TOU | Time of Use |
| UART | Universal Asynchronous Receiver/Transmitter |

## Appendix B: Revision History

| REVISION <br> NUMBER | REVISION <br> DATE | DESCRIPTION | PAGES <br> CHANGED |
| :---: | :---: | :--- | :---: |
| 1.0 | $1 / 11$ | Initial release | - |
| 1.1 | $3 / 11$ | Added the 71M6543G, 71M6543GH | All |
| 1.2 | $4 / 11$ | Removed the 17mW typ consumption at 3.3V for sleep <br> mode from the Features section | 1 |
| 2 | $10 / 13$ | Removed the 71M6543H, 71M6543GH; updated PLS_INV <br> description on Table 70, added warning note on SPI Flash <br> Mode section, updated IEN0 Bit Function and External <br> MPU Interrupts table, removed INFO_PG from the register <br> map, changed CECONFIG bit 23 to reserved, corrected <br> SPP Slave port diagram (Figure 23), updated the text <br> description of the Signal Input Pins section, combined <br> columns 3 and 4 of Table 33, updated the Interrupt <br> Structure diagram, corrected the OPT_TXE active <br> definition, updated the required CE code and settings notes <br> about MUX_DV[3:0], added a note about V_ANG_CNT <br> under Table 82 | All |

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[^0]:    *Remote interface data

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